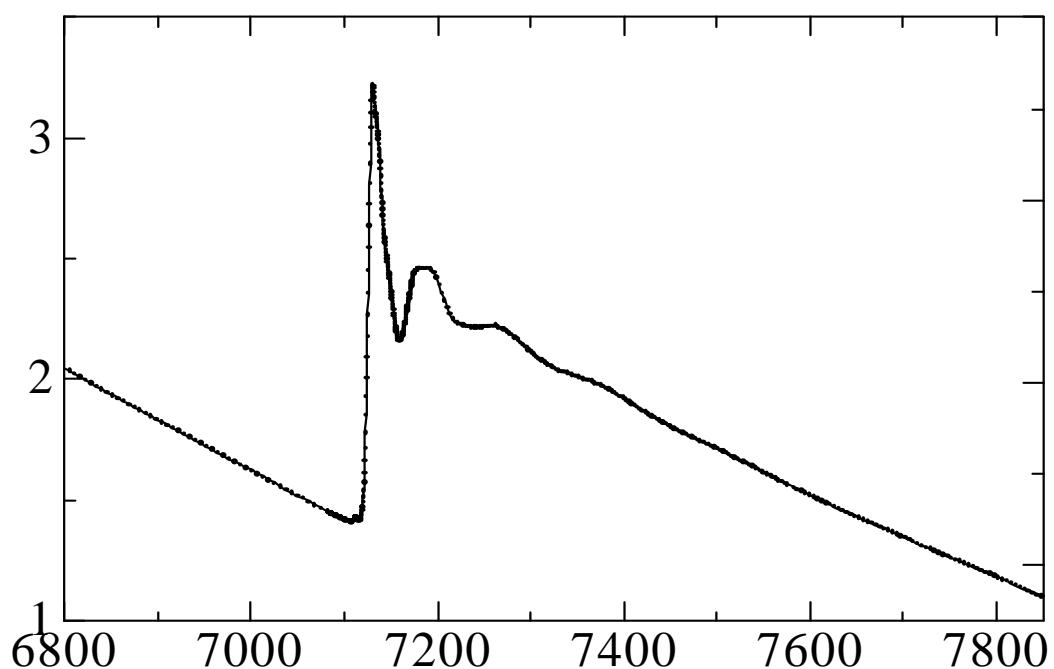


# XAFS

## *X-ray Absorption Fine Structure*



*Iwao Watanabe*  
*Ritsumeikan University*

# XAFS

## Theory

Quantum Mechanics  
Models  
Approximations

## Experiment

Light Source  
Monochromator  
Higher Harmonics Rejection  
Sample Preparation  
Detection Methods  
Polarization XAFS

## Data Analysis

Limited Usable Range in Experimental Data

Estimation of Background Curves

Fourier Transform

Multi-Scattering

Curve Fitting Procedure

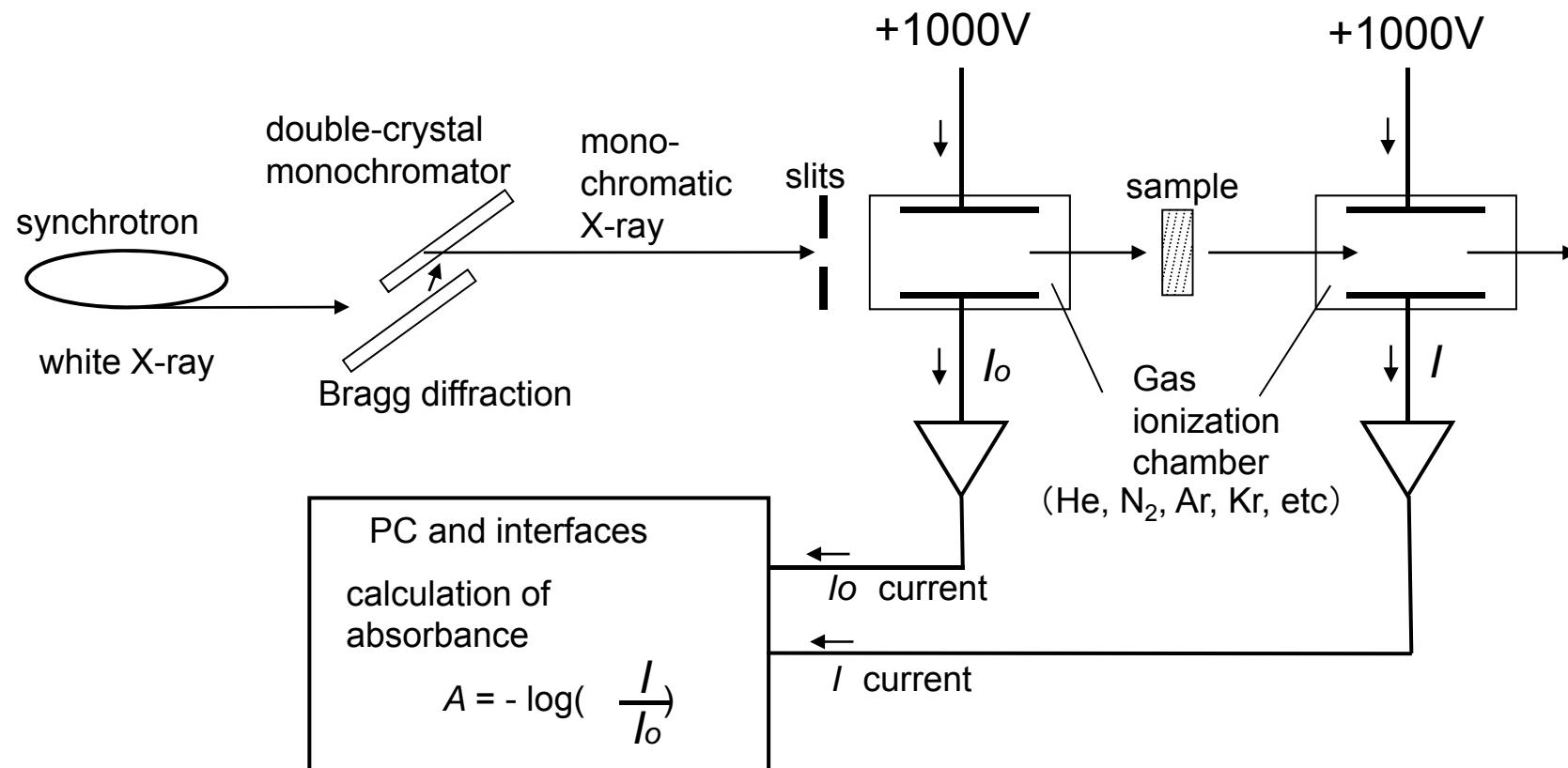
Phase Problems

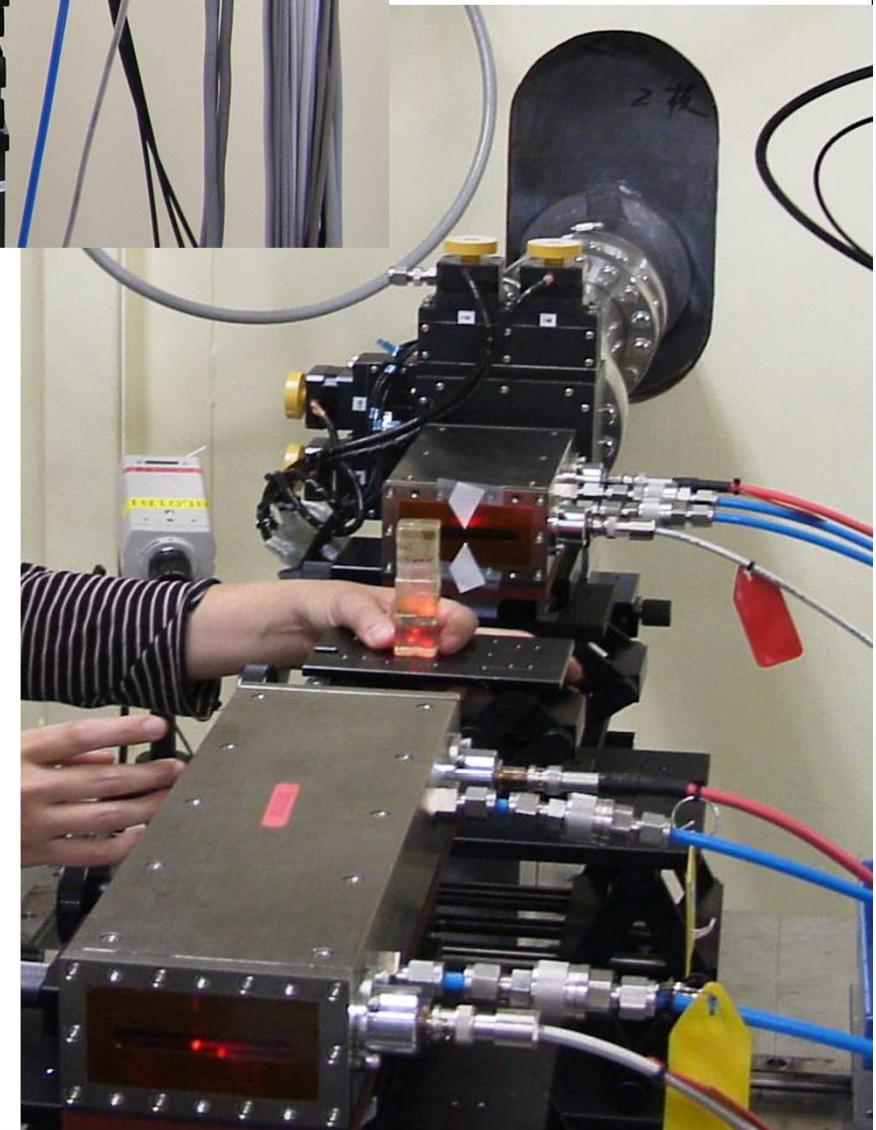
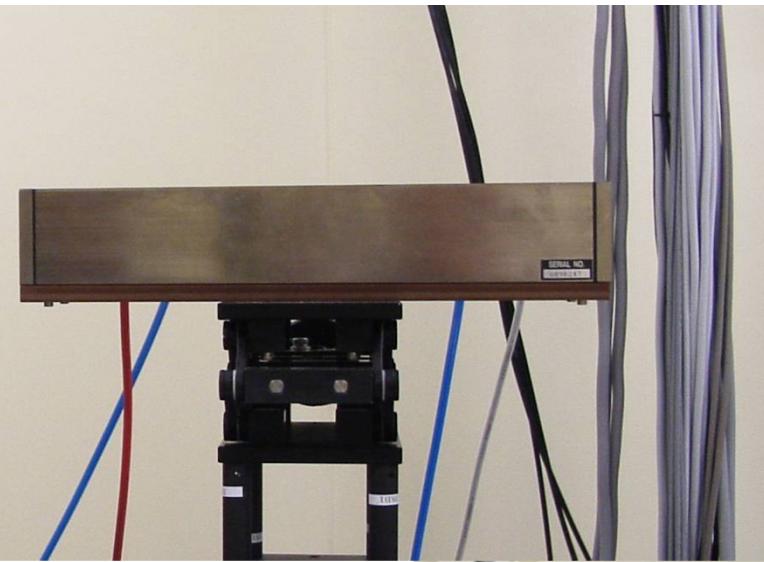
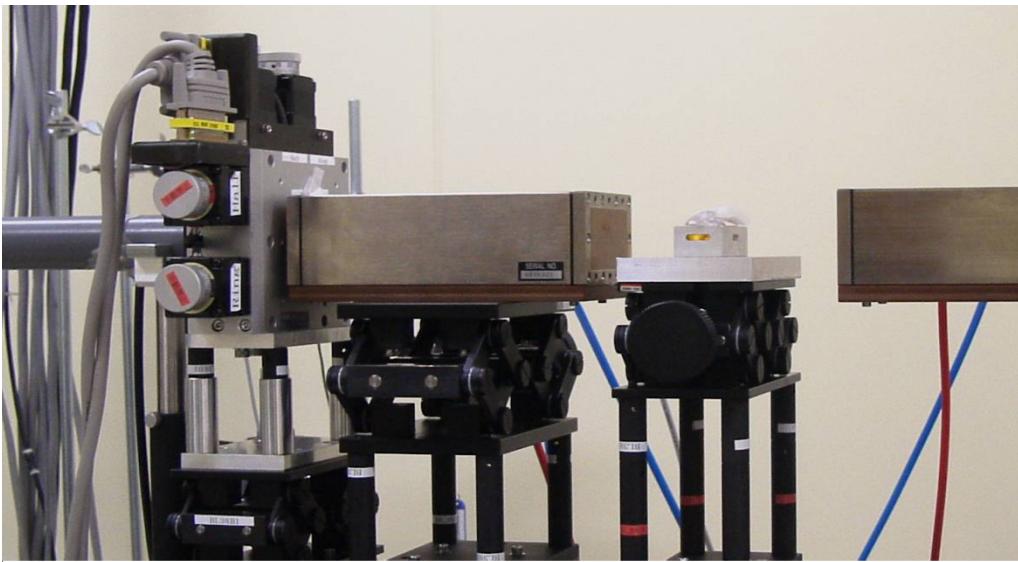
Debye-Waller-Like Parameter

Anharmonicity in Potential

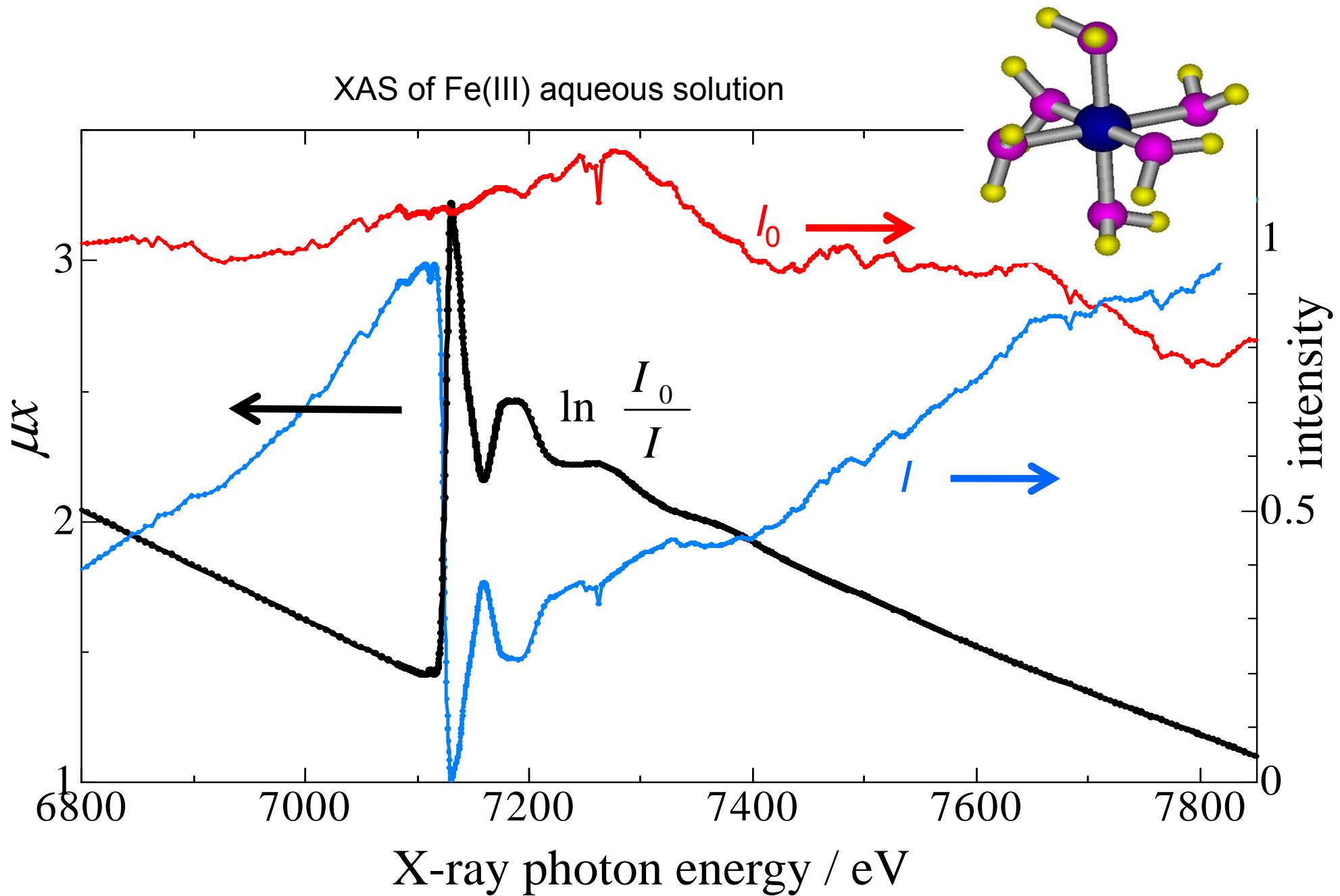
# X-ray absorption measurement by transmission method

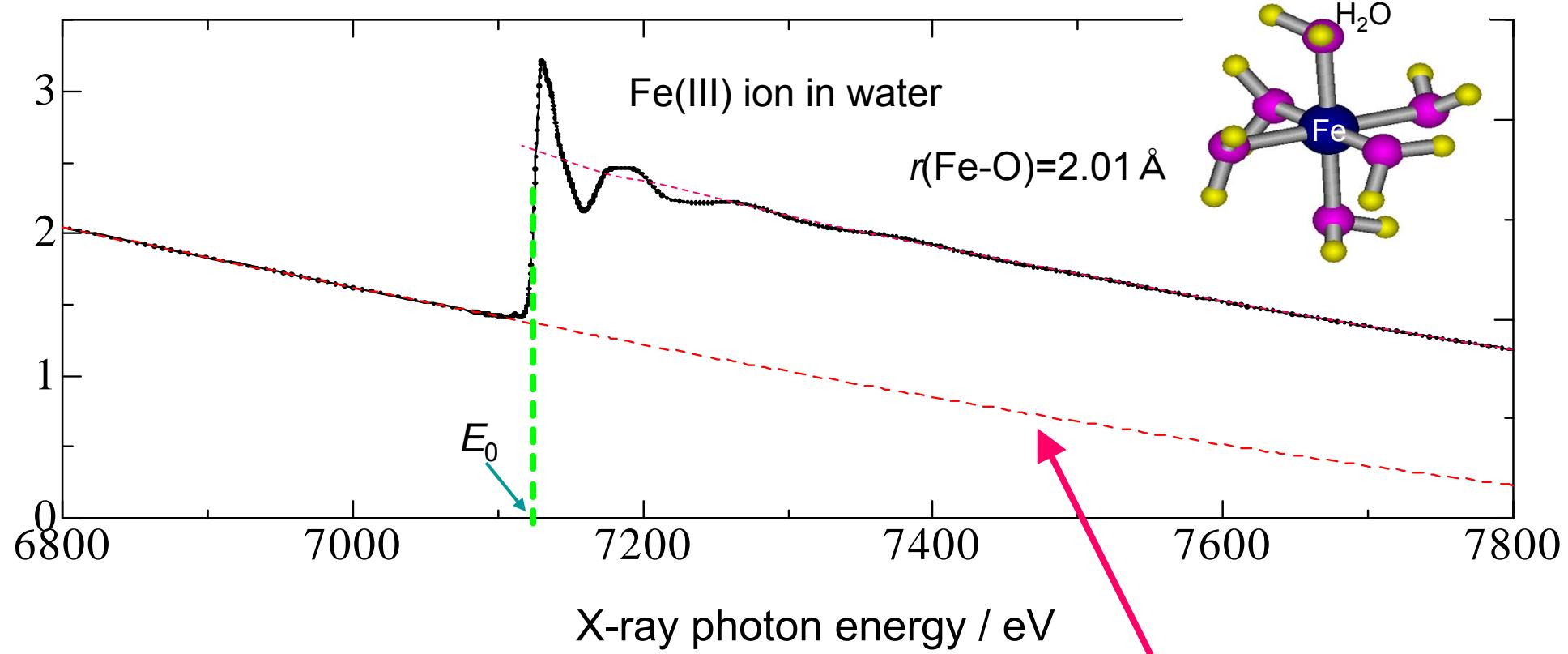
## The most reliable and basic method





### XAS of Fe(III) aqueous solution





Focusing on K shell (1s electron) excitation

Background absorption due to other atoms and other shell electrons

### Fermi's Golden Rule

In XAS we measure the dipole mediated transition of an electron in a deep core state  $|i\rangle$  into an unoccupied state  $|f\rangle$ :

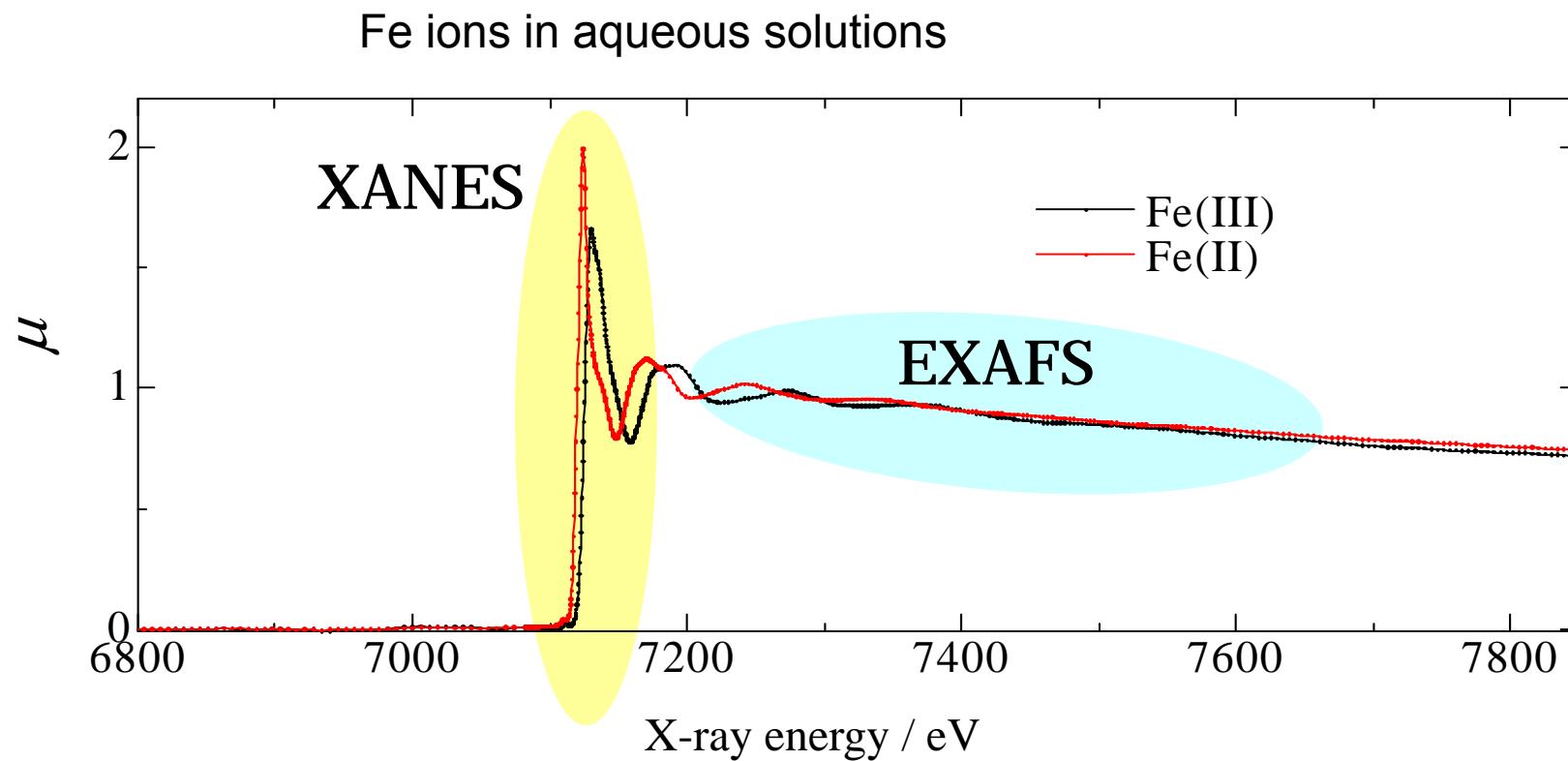
$$\mu(E) \propto \sum_f | \langle f | \hat{\epsilon} \cdot \mathbf{r} | i \rangle |^2 \delta(E_f - E_f)$$

There are two ways to solve this equation:

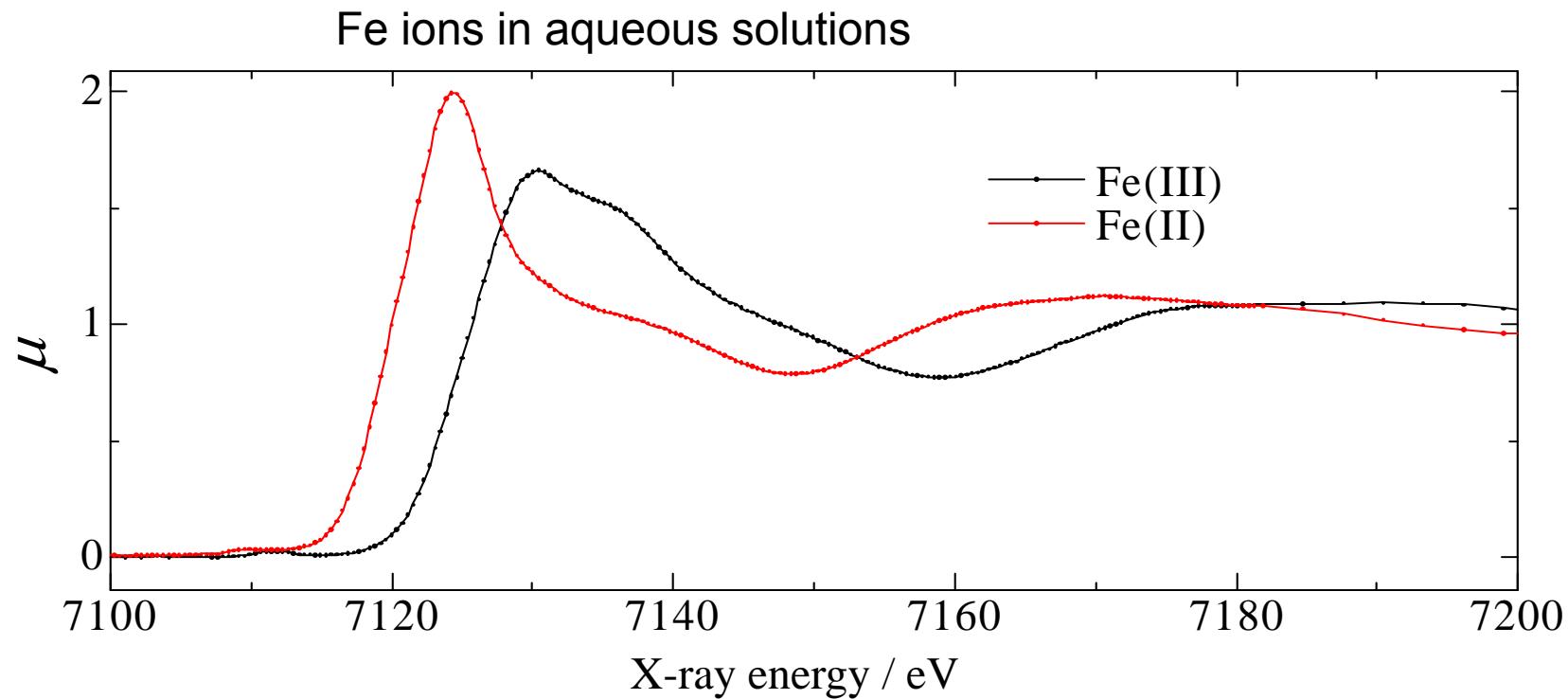
1. Accurately represent  $|i\rangle$  and  $|f\rangle$ , then evaluate the integral directly. This is the approach taken, for example, by molecular orbital theory.
2. Use **multiple scattering theory**:

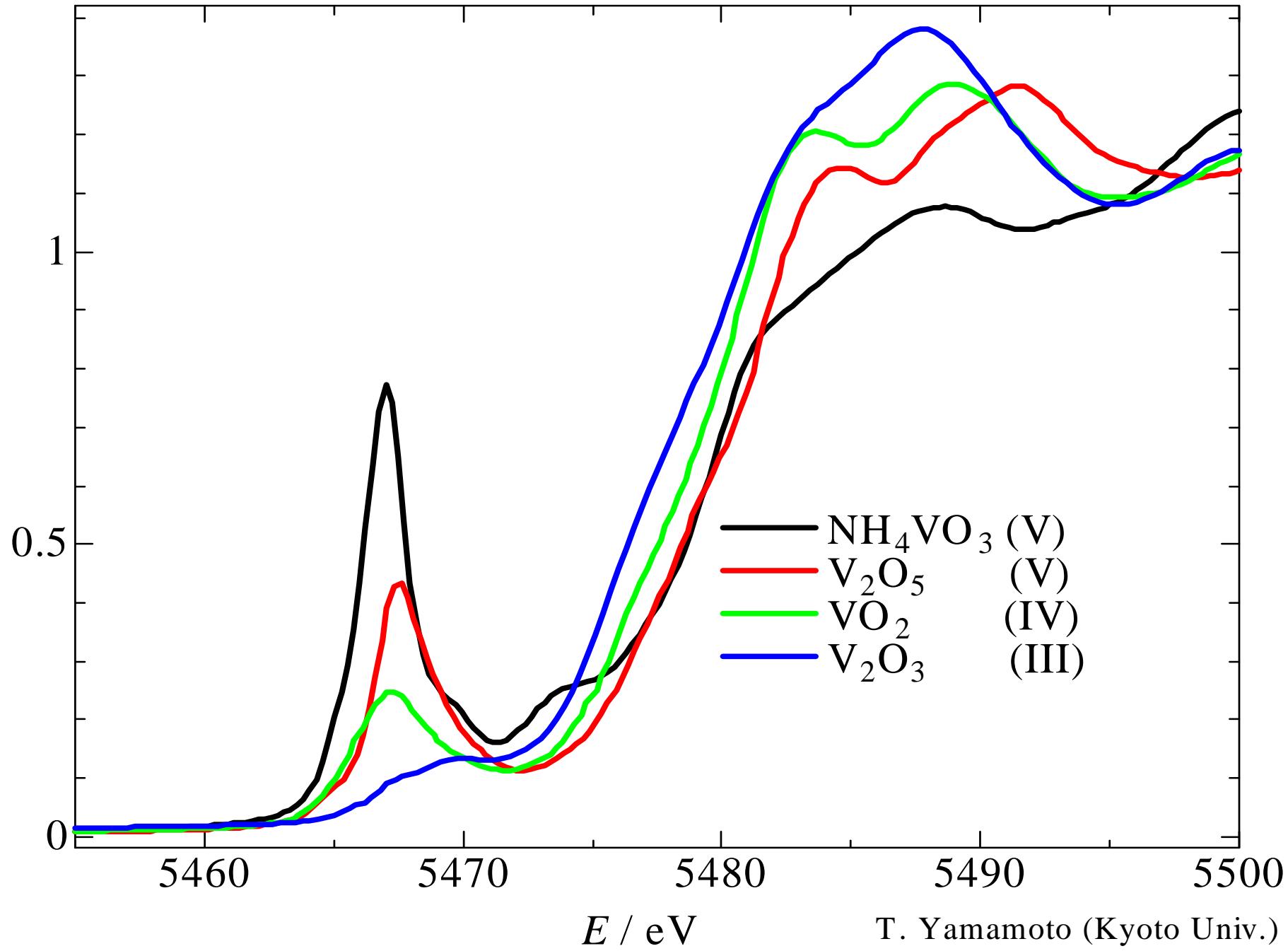
This is the approach taken by **FEFF** and, by extension, by analysis programs which use **FEFF**.

# XAFS: X-ray Absorption Fine Structure



# XANES: X-ray Absorption Near Edge Structure





$E / \text{eV}$

T. Yamamoto (Kyoto Univ.)

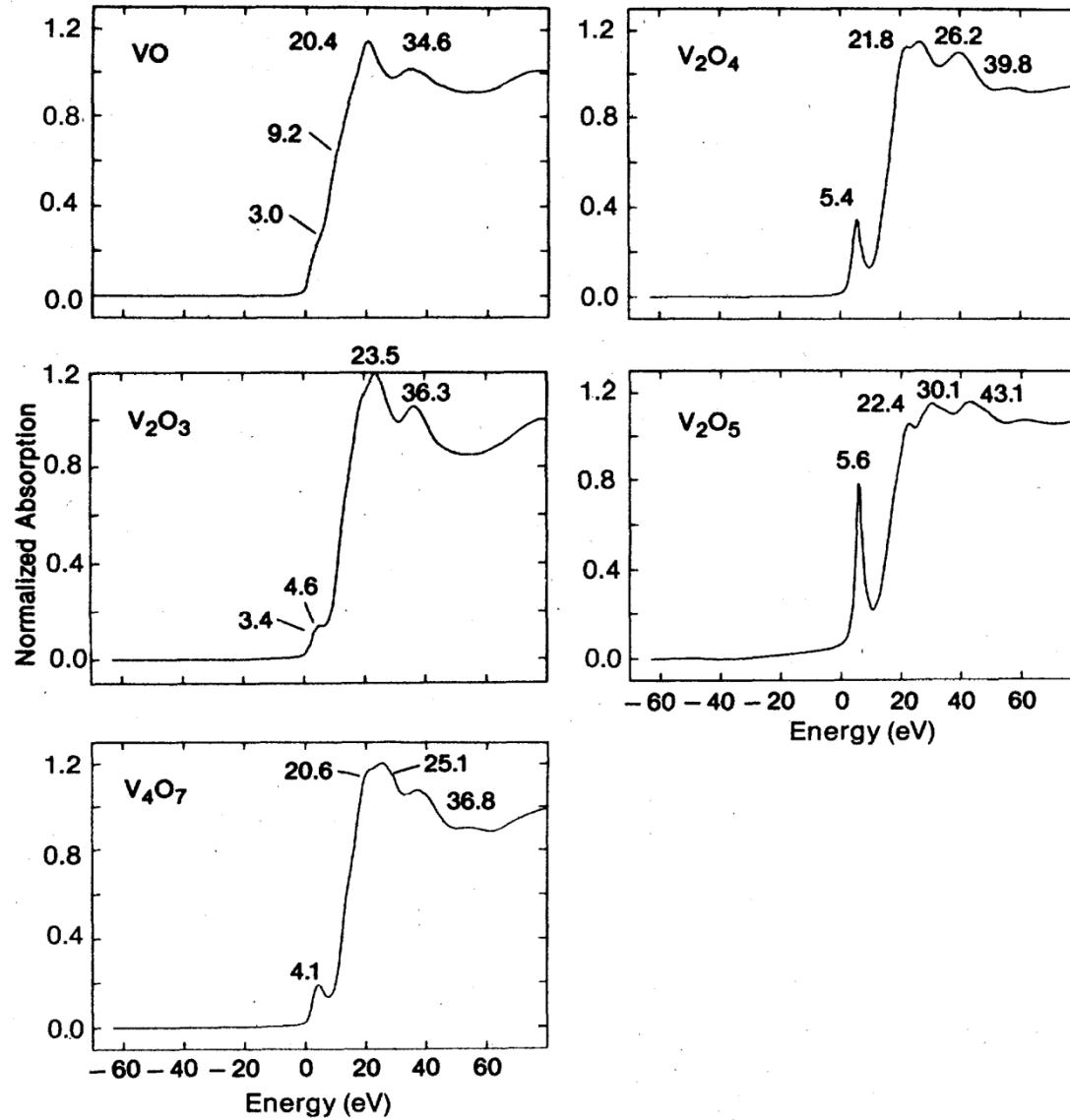
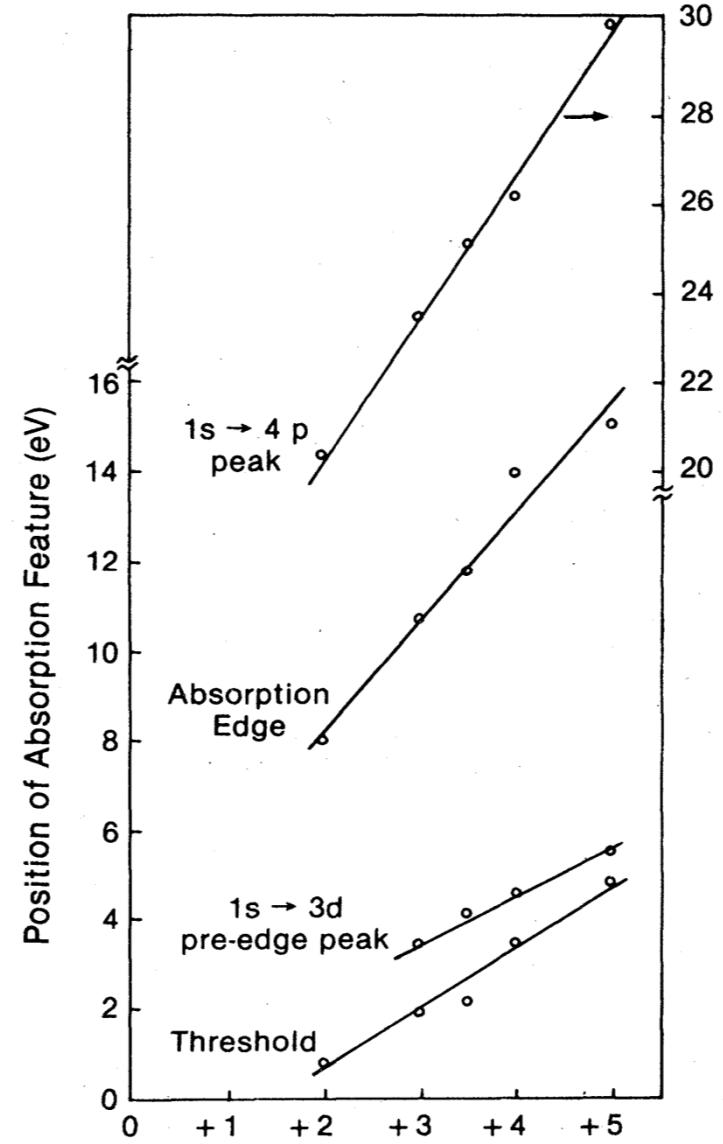
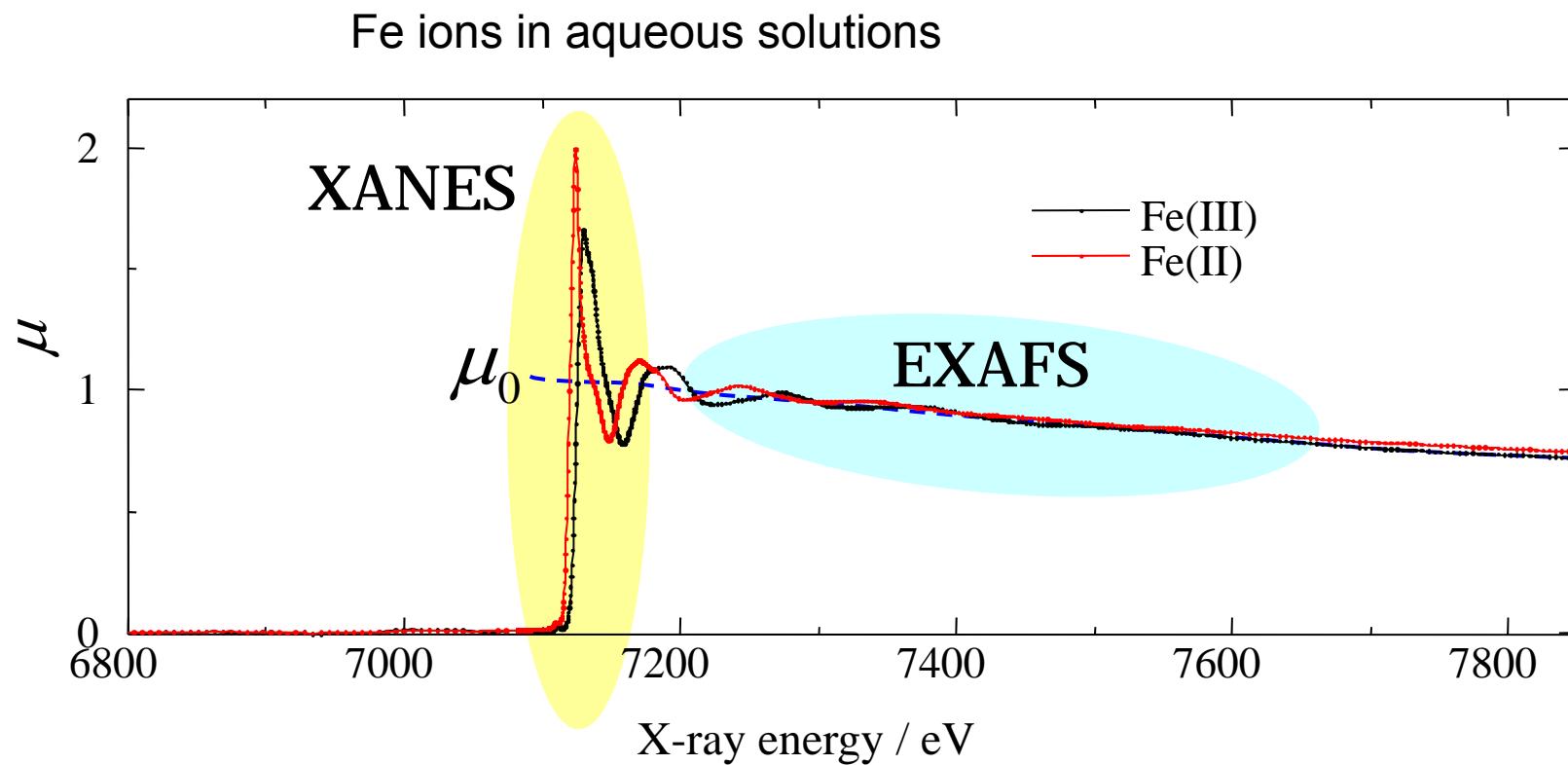


FIG. 3. Normalized  $K$ -edge XANES spectra of vanadium oxides, the zero of energy taken at 5465 eV.



Wong et al. Phys.Rev.B 30  
(1984) 5596

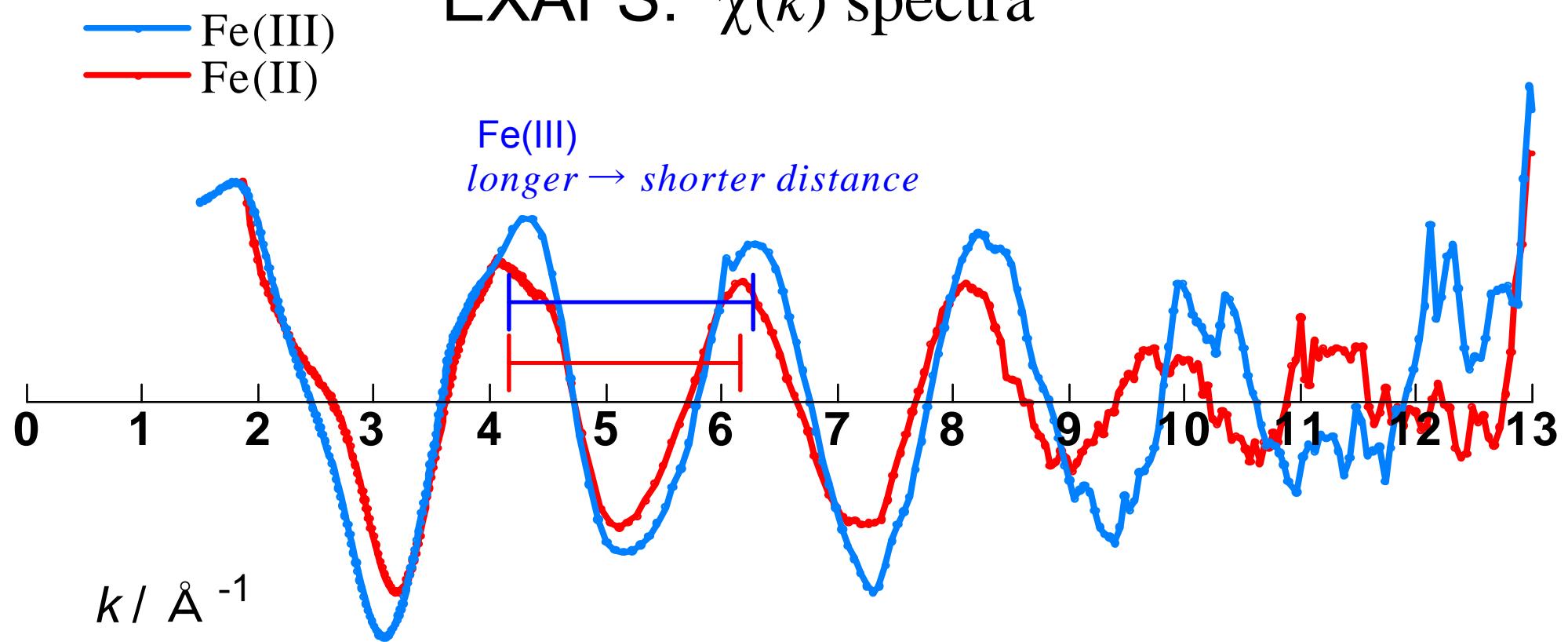
# EXAFS: Extended X-ray Absorption Fine Structure



$$\chi(k) = \frac{\mu(k) - \mu_0(k)}{\mu_0(k)}$$

$$k = \sqrt{\frac{2m_e(E - E_0)}{\hbar^2}}$$

# EXAFS: $\chi(k)$ spectra



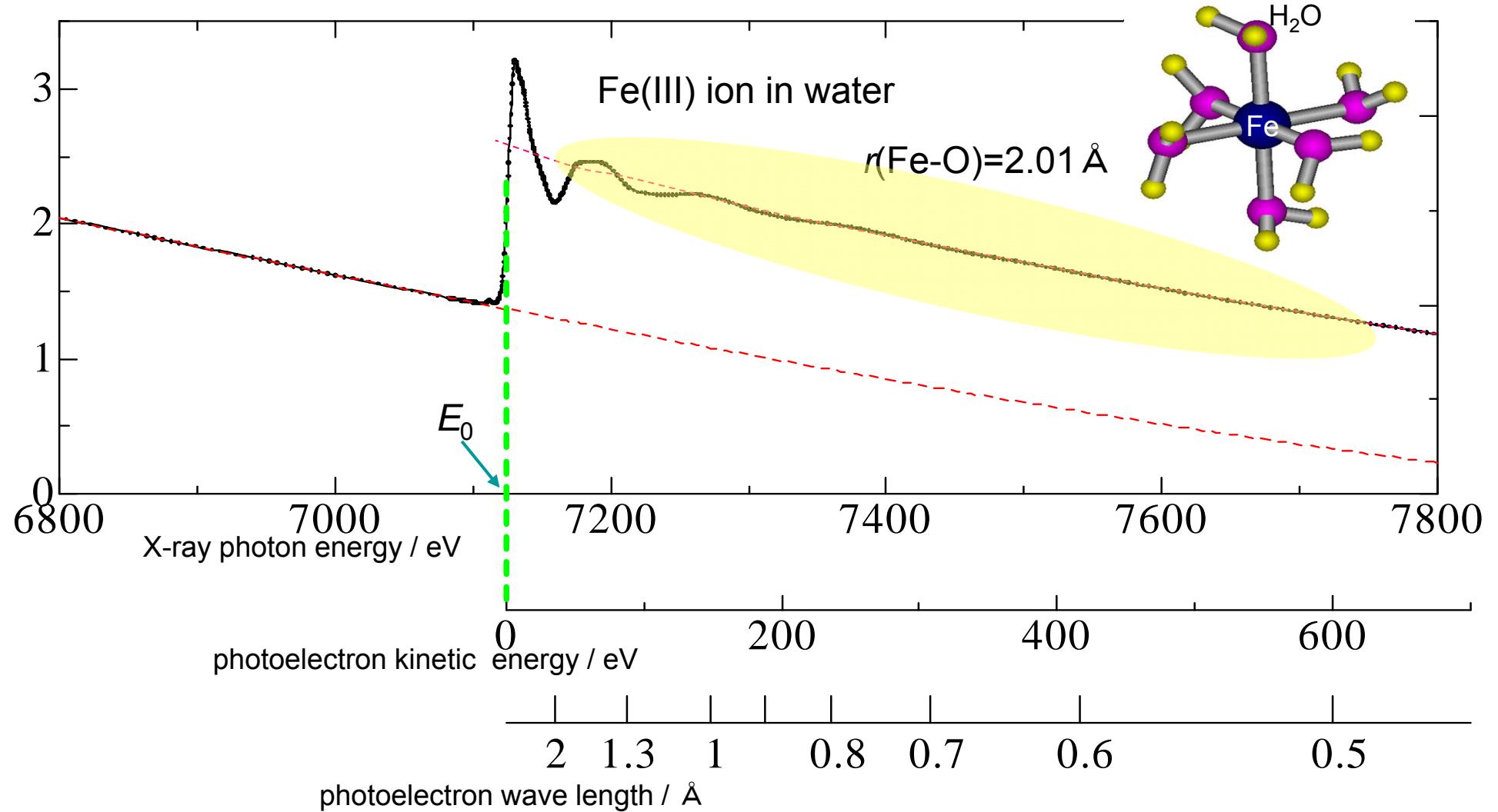
$k$  : wave number, wave vector

$$k = \frac{2\pi}{\lambda}$$

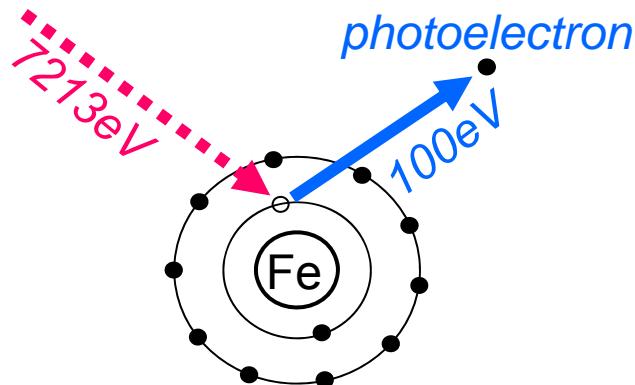
$$k = \sqrt{\frac{2m_e(E - E_0)}{\hbar^2}}$$

$(E - E_0)$   
kinetic energy of  
photoelectron

*Simplest model to explain how the EXAFS oscillation occurs*



*X-ray photon*



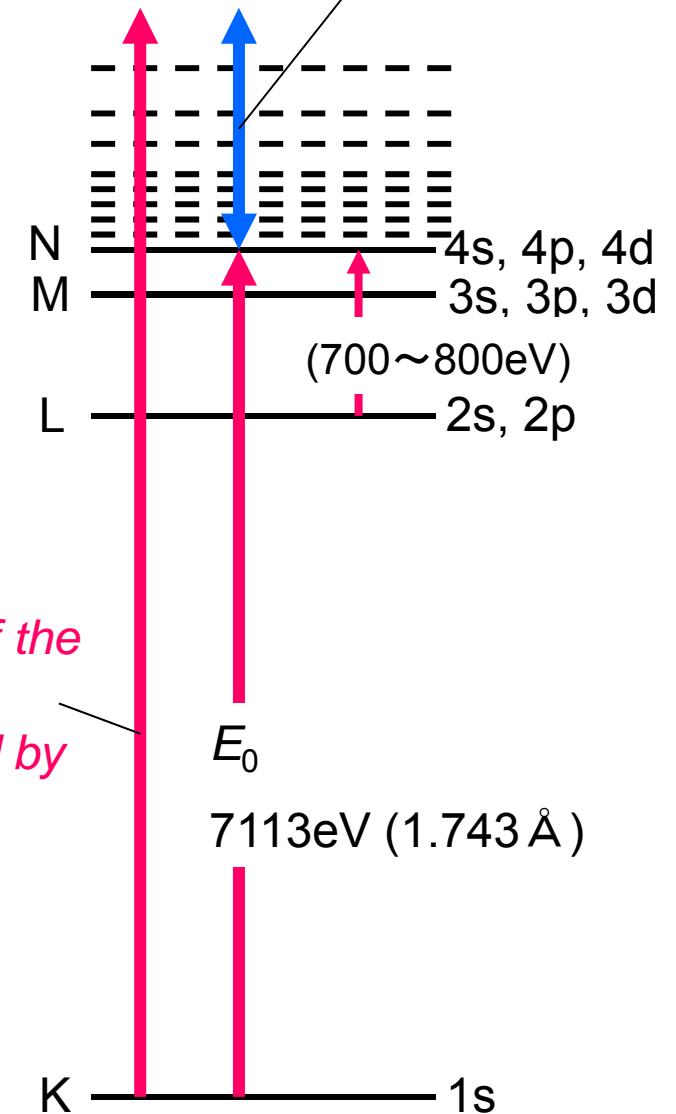
an electron with  $E_k = 100\text{eV}$  behaves as a wave with  $\lambda = 1.2\text{\AA}$

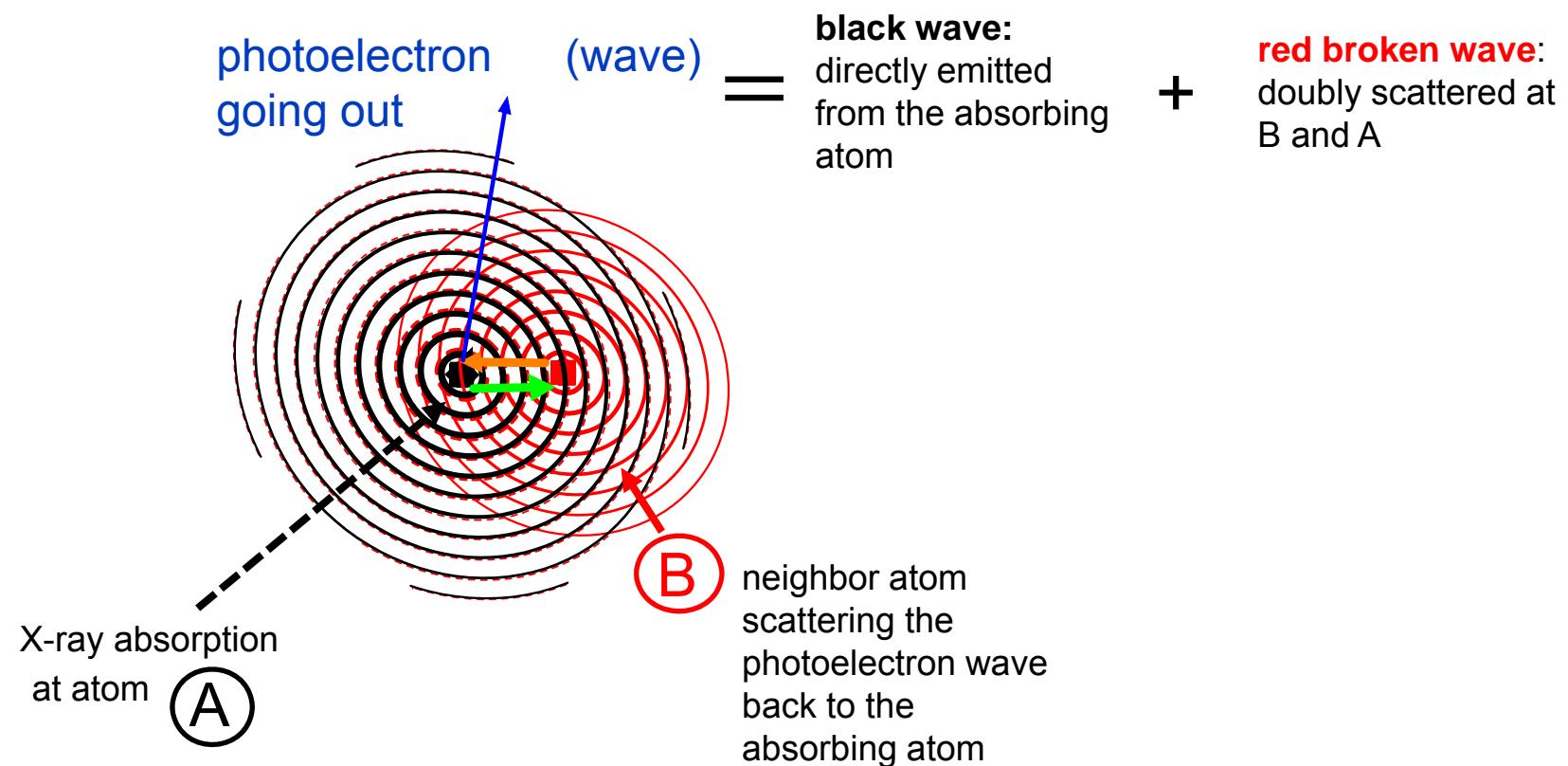
$$\lambda = \frac{h}{p} : \text{de Broglie}$$

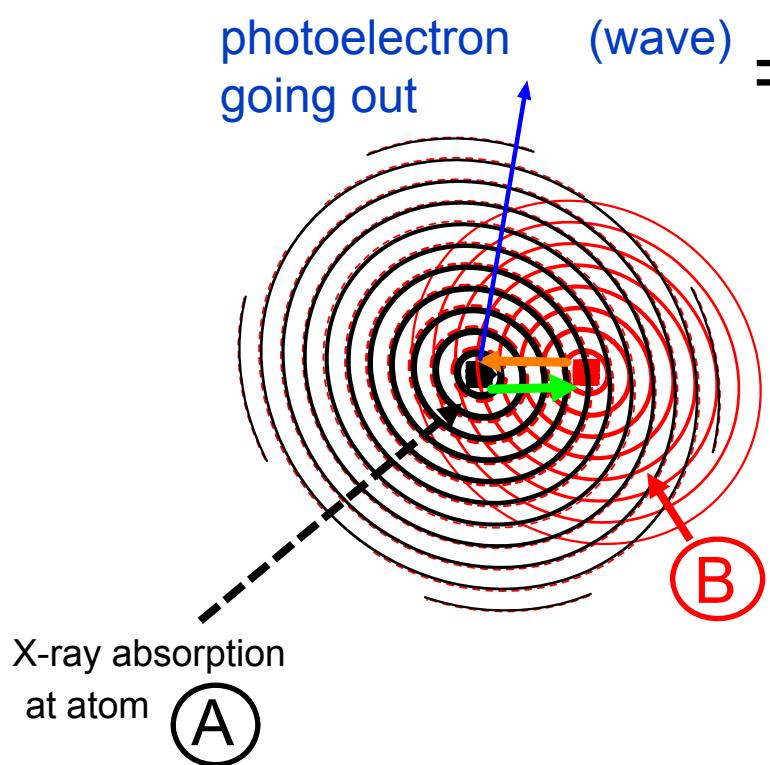
*This wave length is just the order of normal atom-atom bond distance !!!*

*The cause for EXAFS appearance !!!*

*kinetic energy of the photoelectron*







= **black wave:**  
directly emitted  
from the absorbing  
atom + **red broken wave:**  
doubly scattered at B  
and A

If they are ***in phase***,  $(2r)k=2n\pi$  ( $k=2\pi/\lambda$ ) or  $2r=n\lambda$ ,

→ larger photoelectron wave

→ larger probability of finding photoelectrons

(amplitude squared).

If they are ***out of phase***,  $(2r)k=(2n+1)\pi$ , and equal amplitudes,

→ photoelectron waves disappear

→ no photoelectrons found outside.

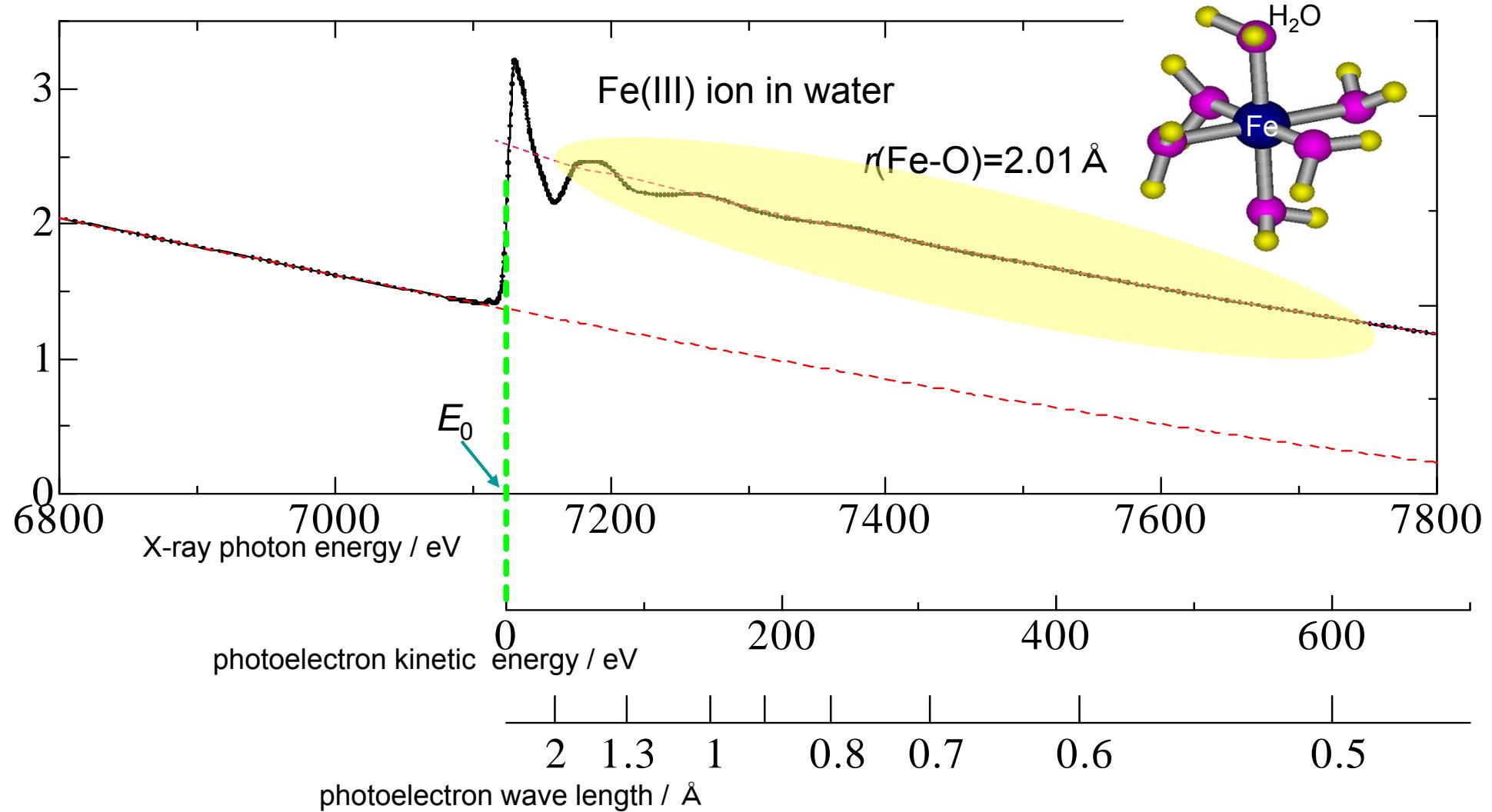
The law of conservation of energy tells that

when no photoelectrons are emitted, no photons should be absorbed !!!

if the X-ray photons are absorbed, the photoelectrons must be emitted !!!

**Larger probability of finding photoelectrons → STRONG X-ray absorption**

**Smaller probability of finding photoelectrons → WEAK X-ray absorption**

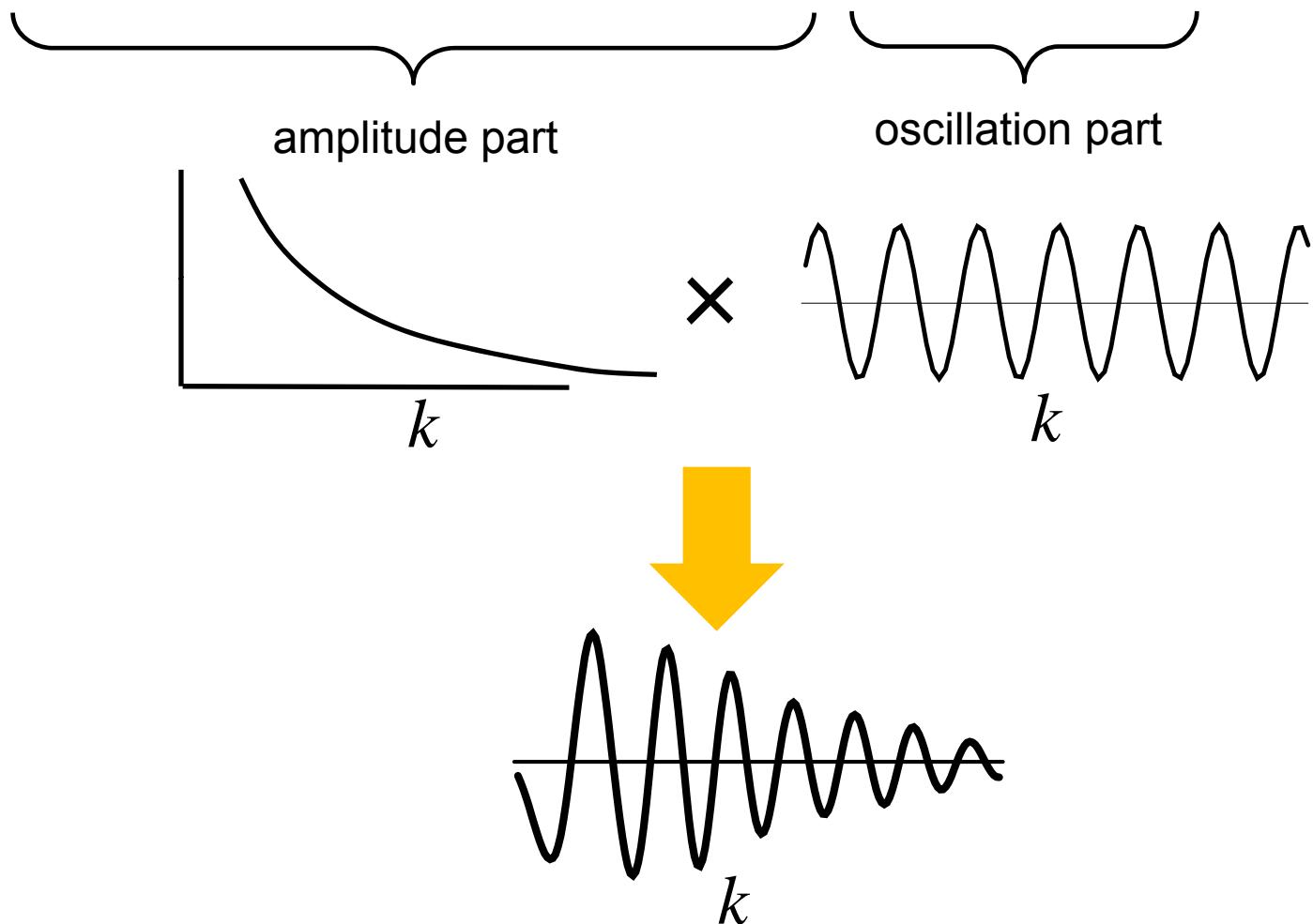


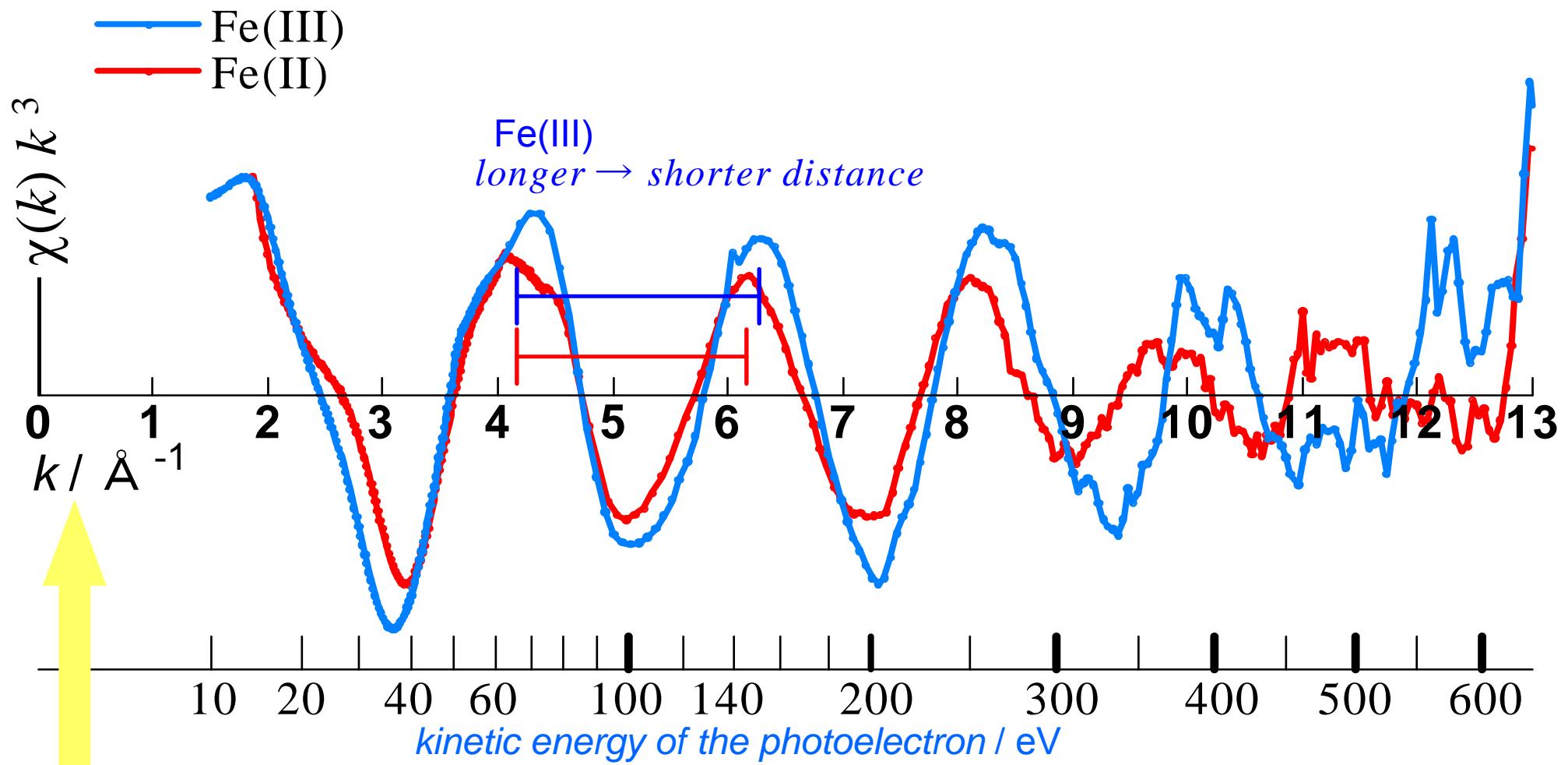
BASIC EXAFS equation

$$\chi(k) = \sum_i \frac{N_i}{k r_i^2} f_i(k) \exp(-2\sigma_i^2 k^2 - 2r_i/\lambda) S_0^2(k) \sin(2kr_i + \phi_i(k))$$

## BASIC EXAFS equation

$$\chi(k) = \sum_i \frac{N_i}{k r_i^2} f_i(k) \exp(-2\sigma_i^2 k^2 - 2r_i/\lambda) S_0^2(k) \sin(2kr_i + \phi_i(k))$$



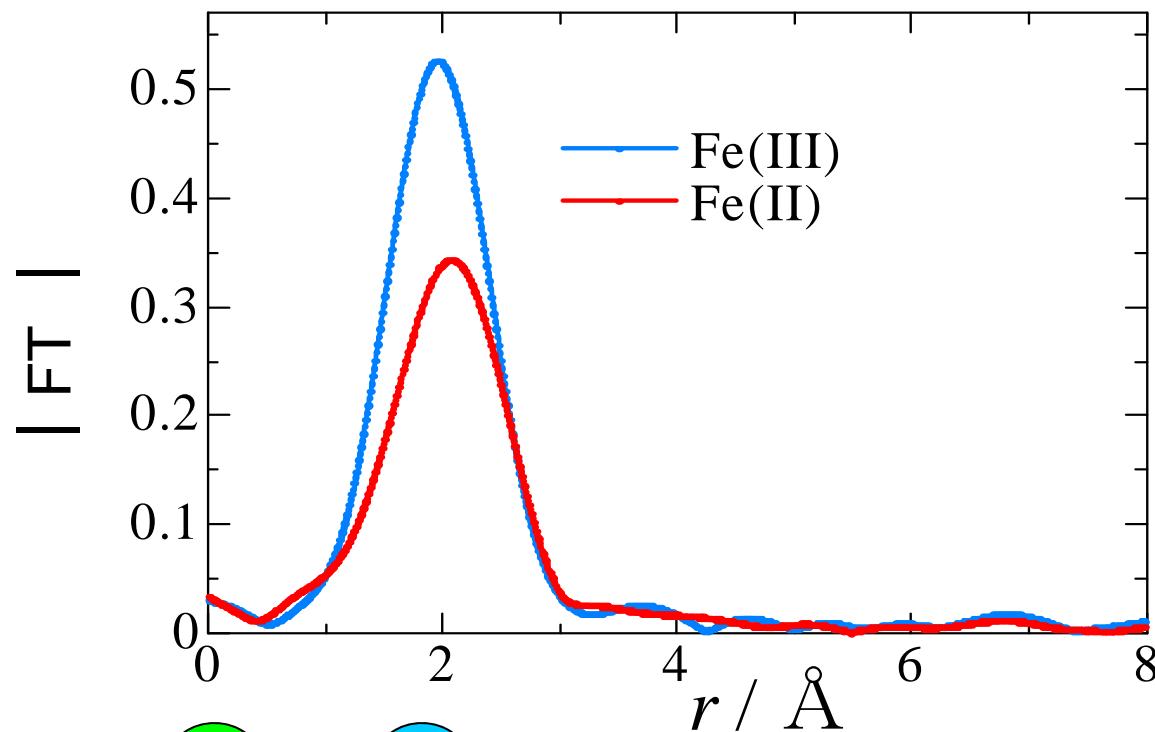


photoelectron wave number (vector)

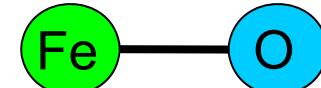
$$k = \frac{2\pi}{\lambda}$$

*Fourier Transform:  
Simplest way to analyze the EXAFS  
oscillation*

*The simplest way of knowing the wave number (corresponding to the distance) is Fourier Transformation of wave on  $k$*

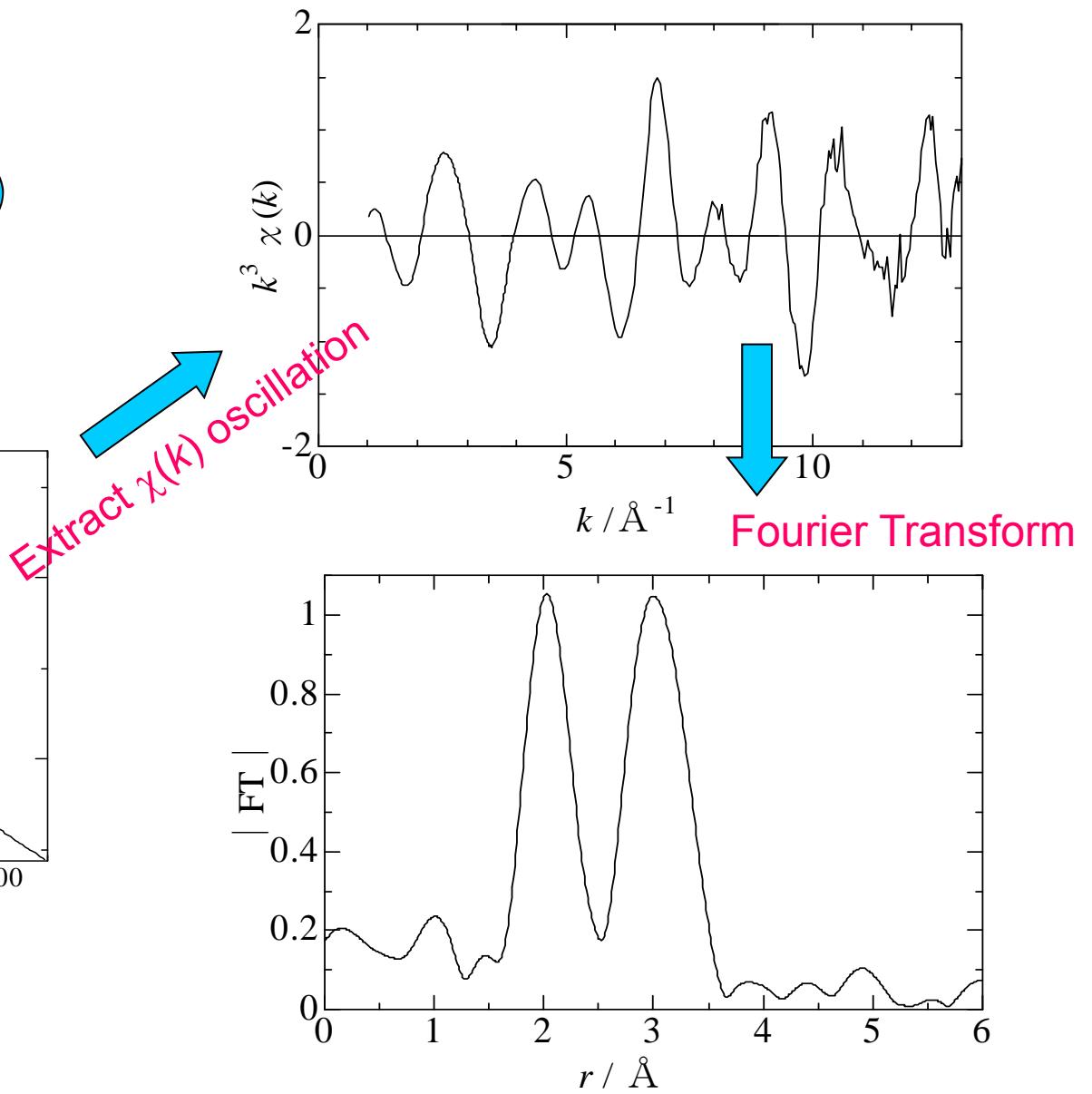
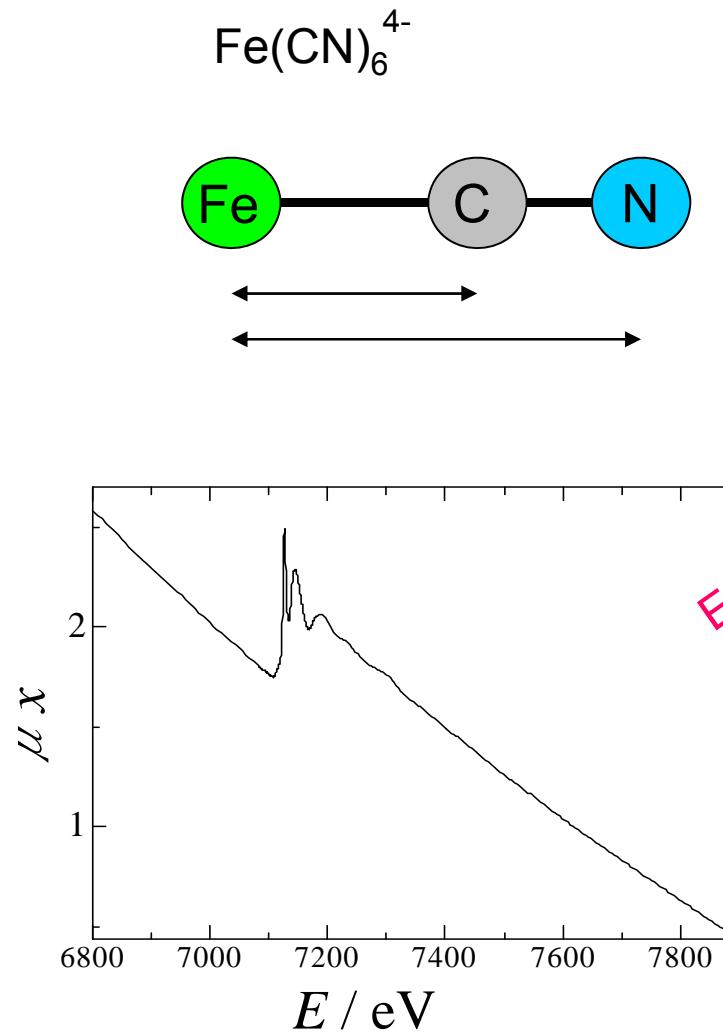


Fe(III) shorter

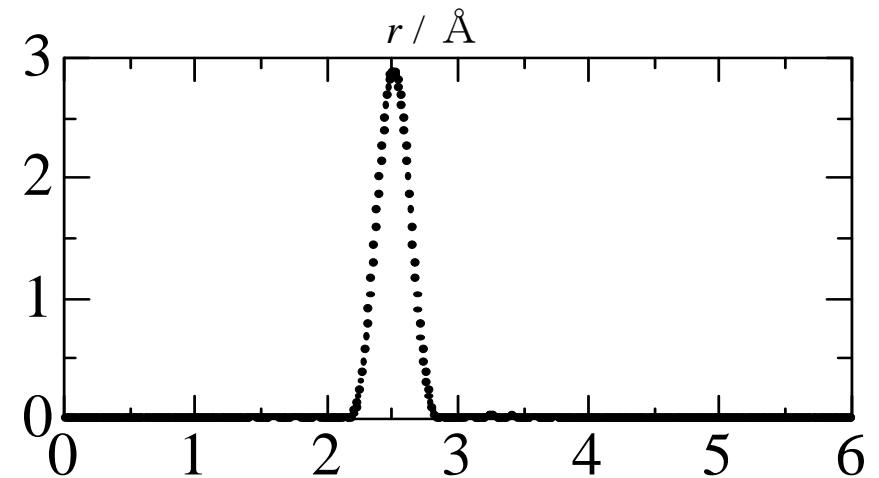
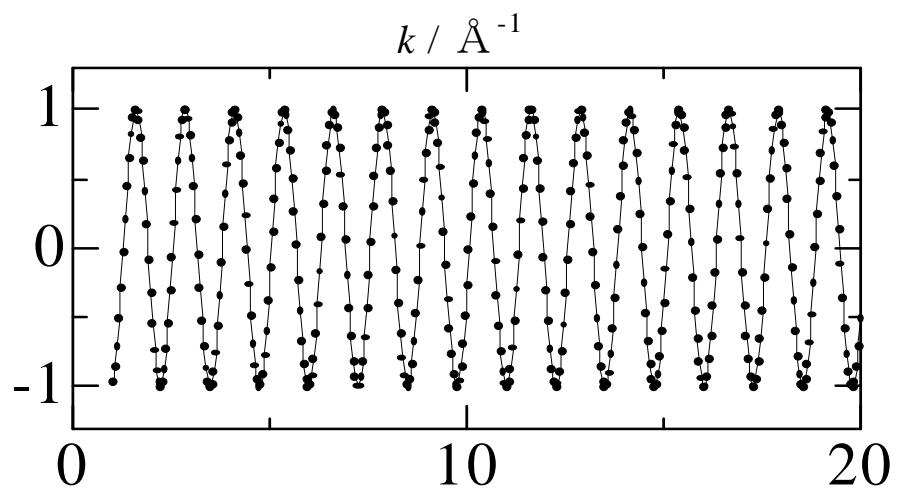


Fe(II) longer

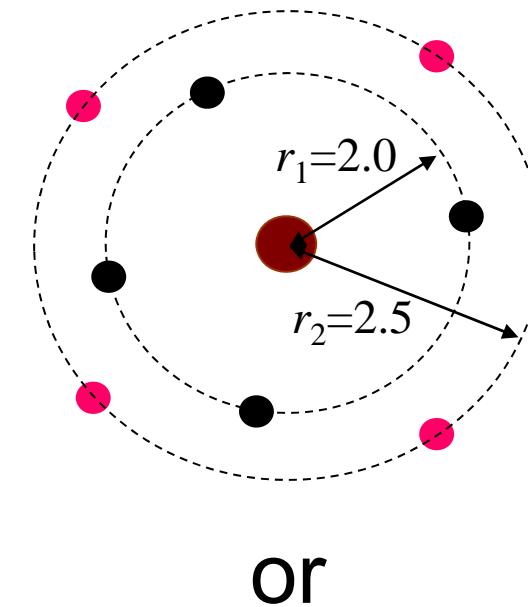
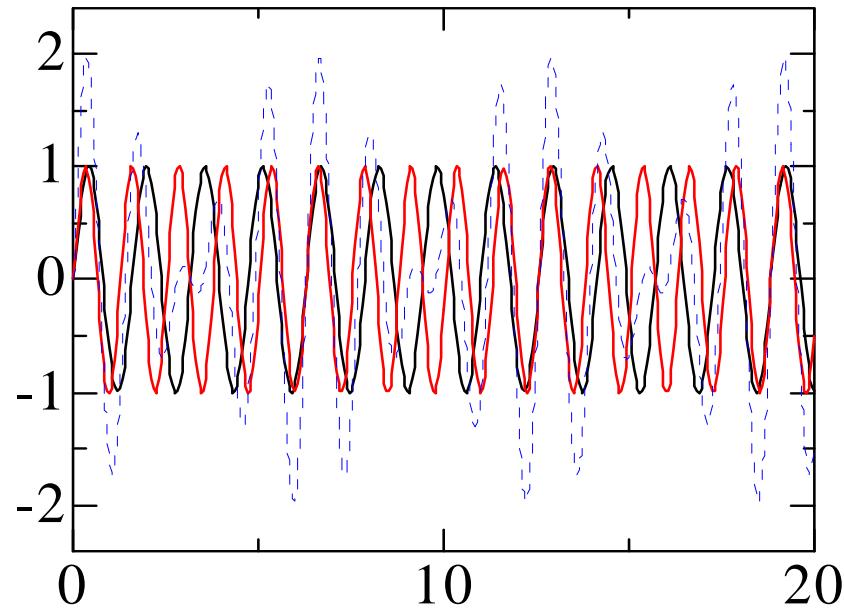




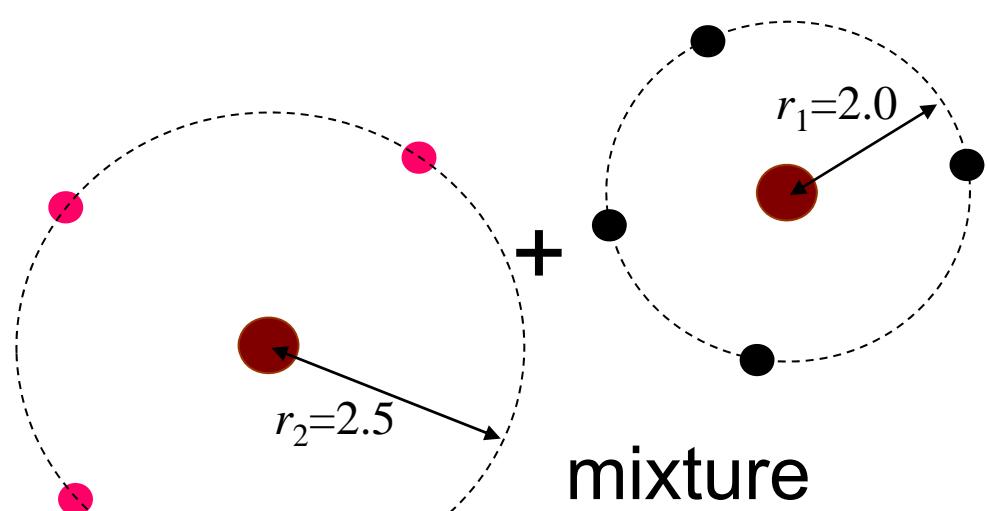
*Fourier Transform (Frequency Filter)*  
*will let you know the frequencies  
of the waves*



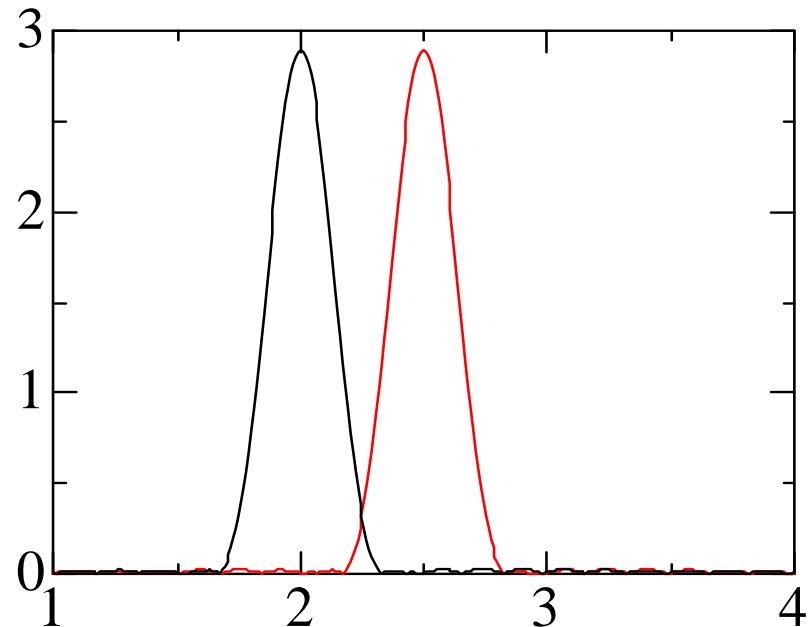
$$\sin(kr)$$



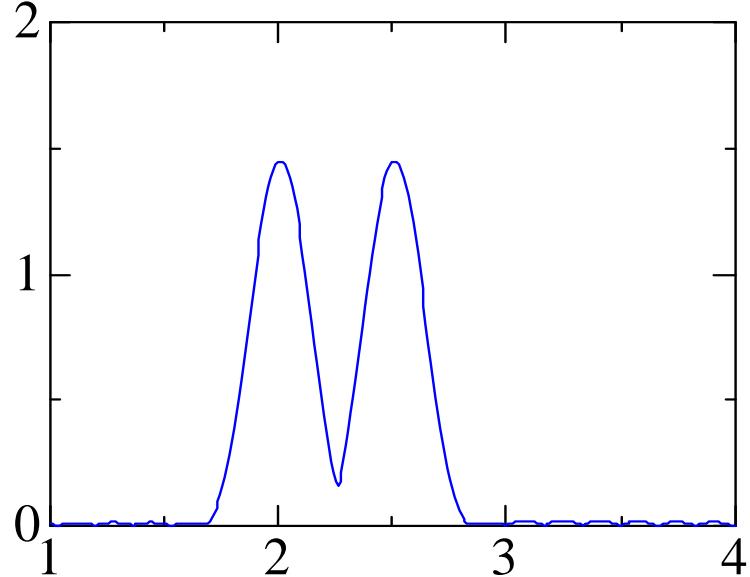
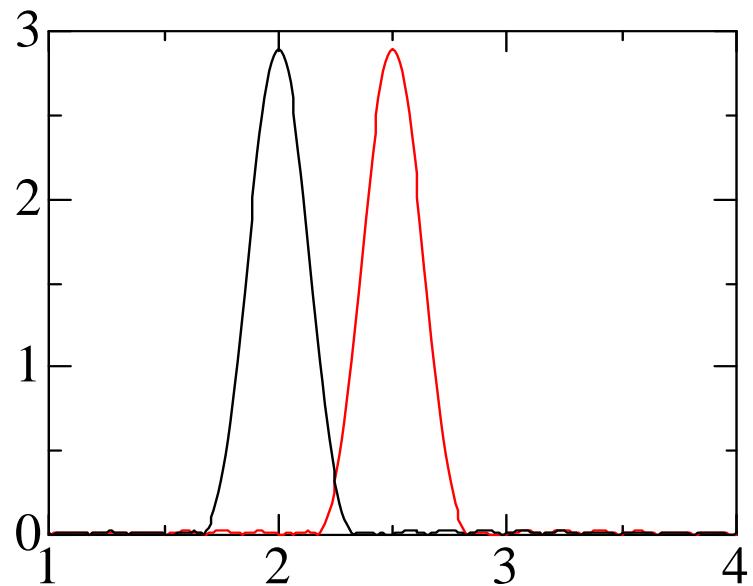
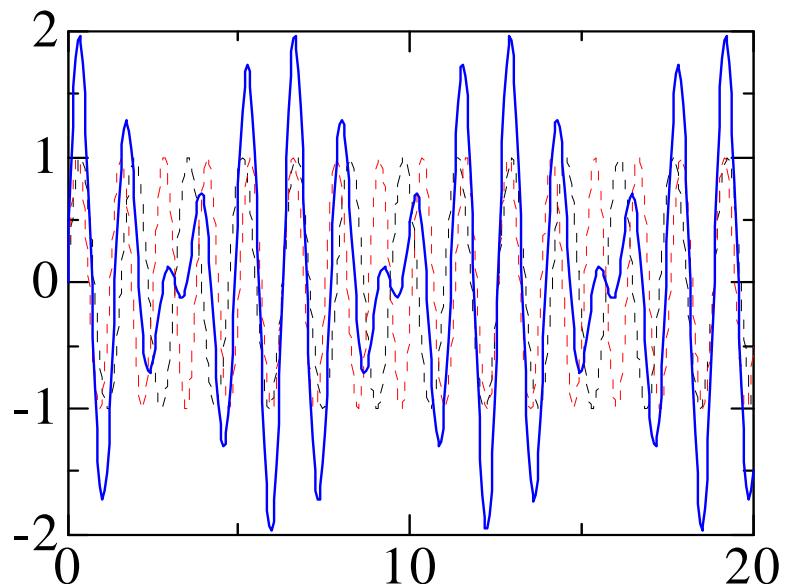
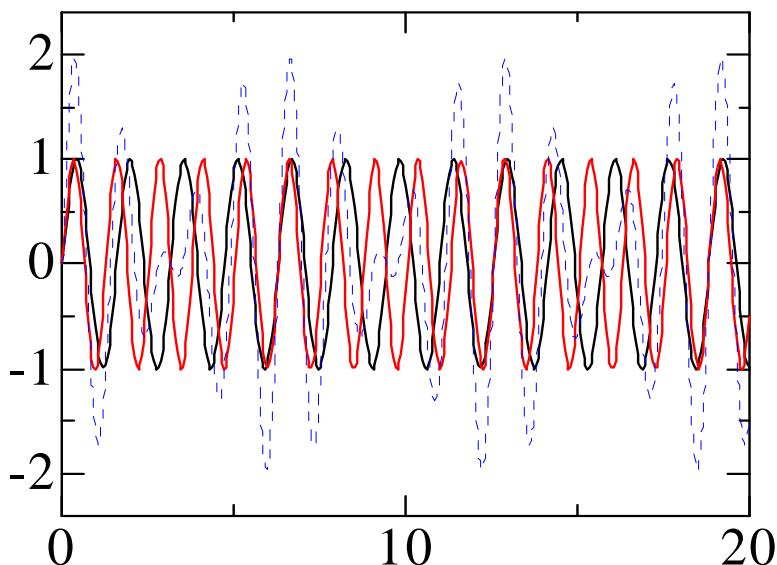
or

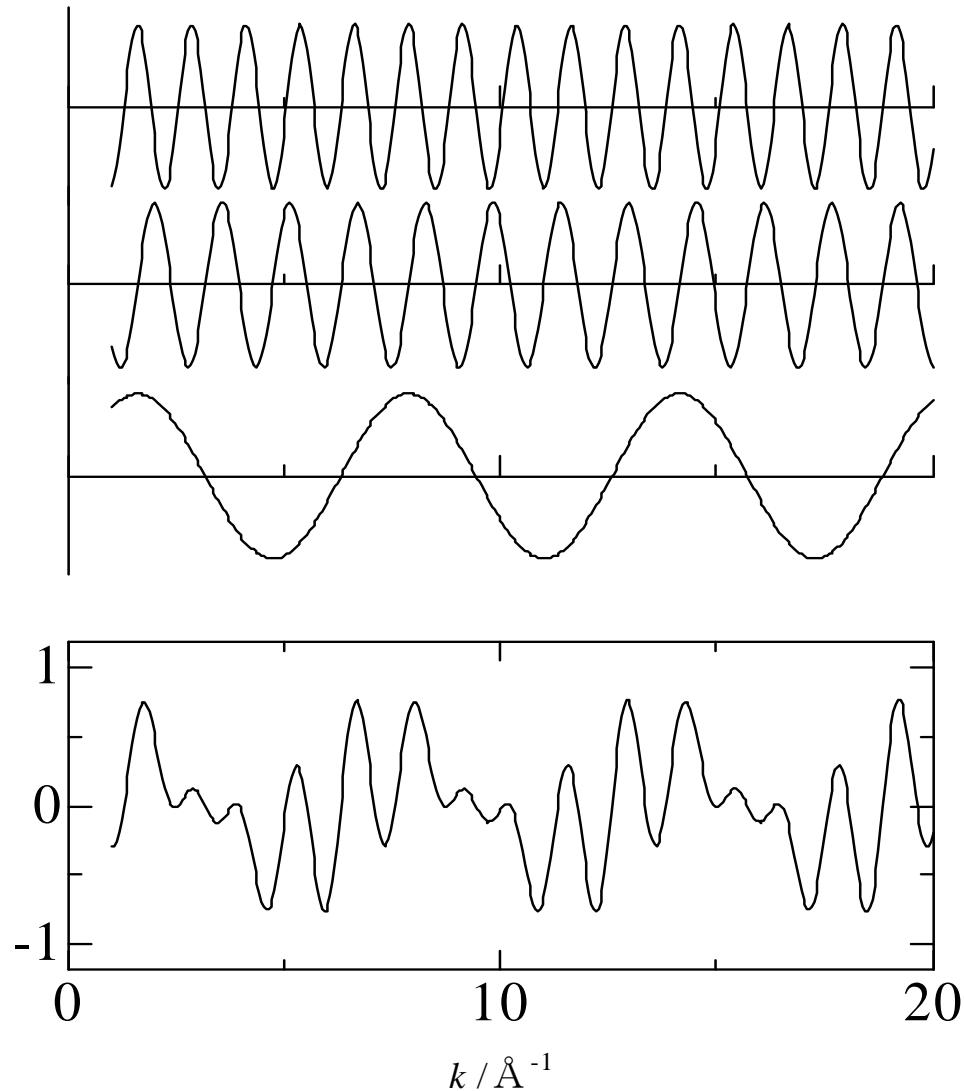


mixture

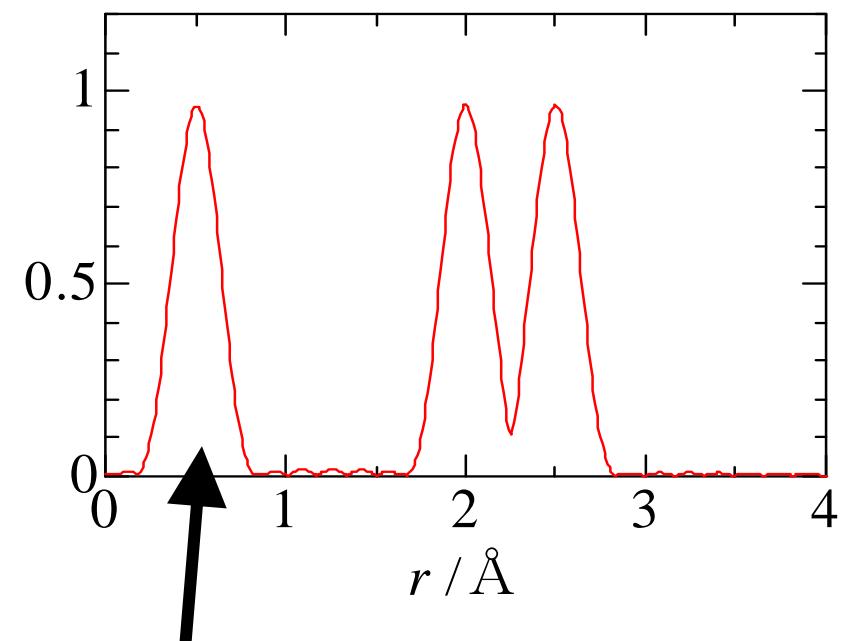


# *Fourier Transform for two-shell model*

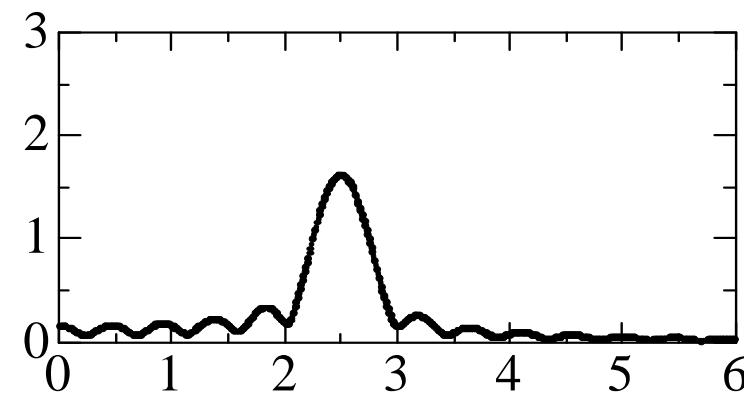
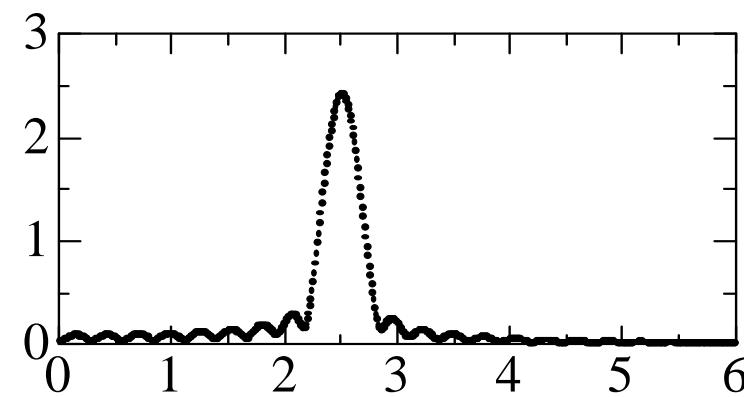
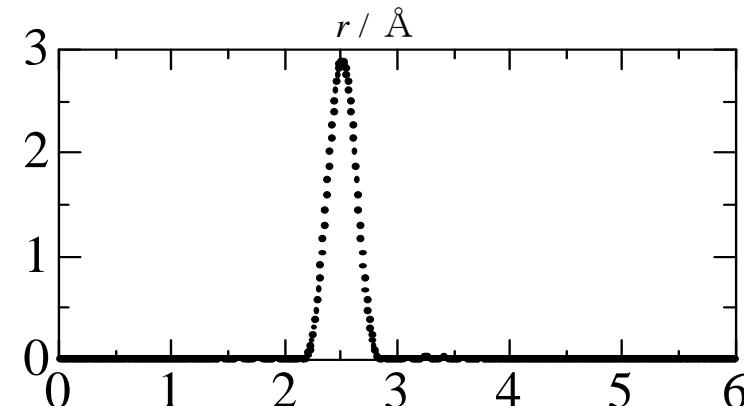
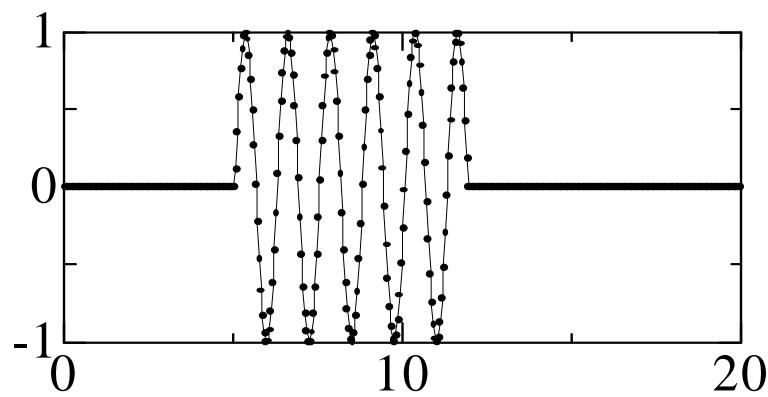
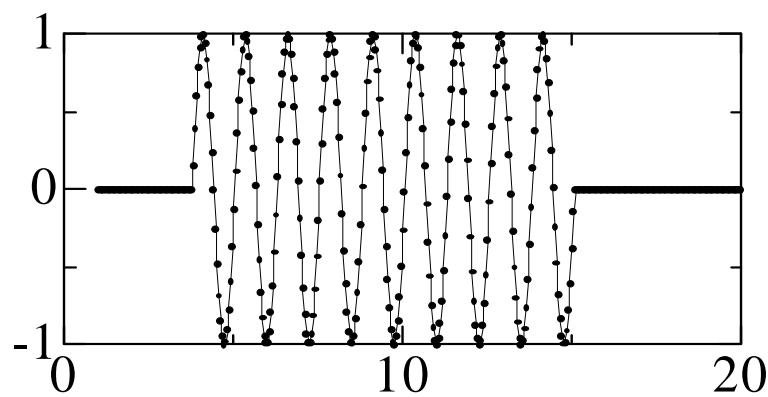
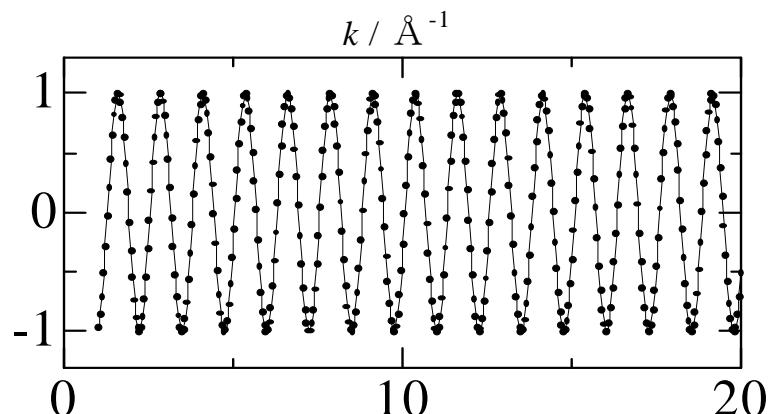


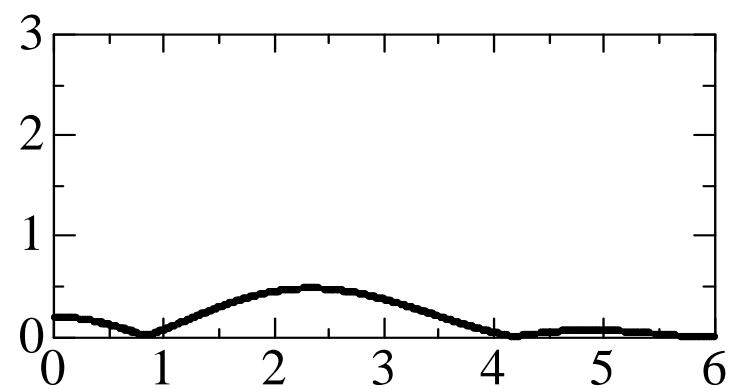
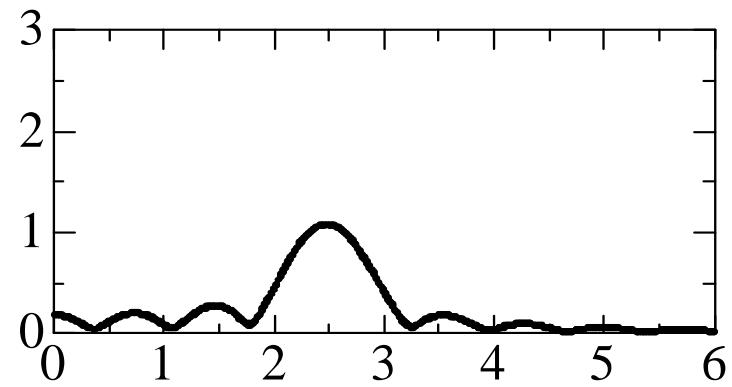
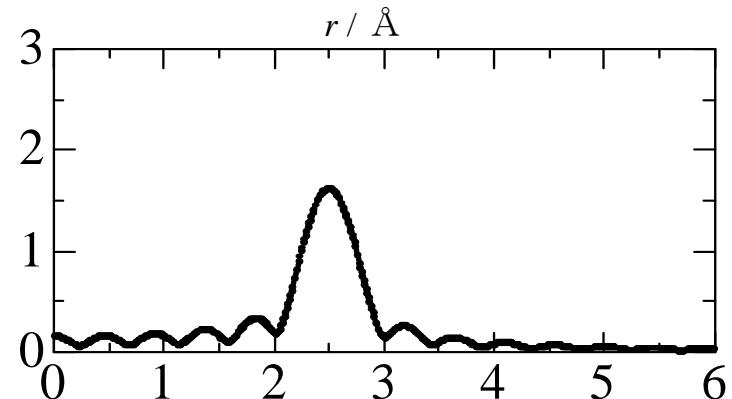
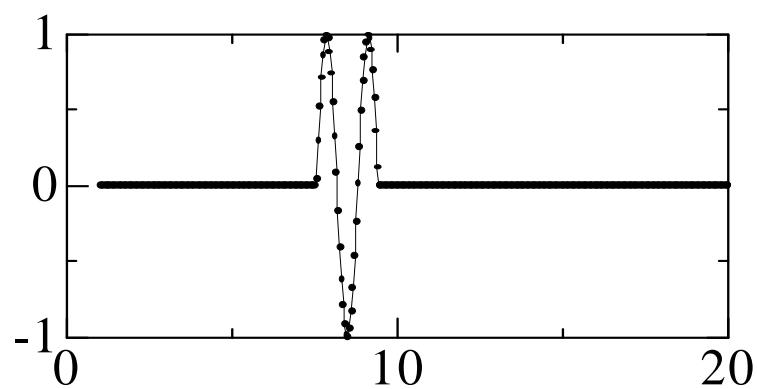
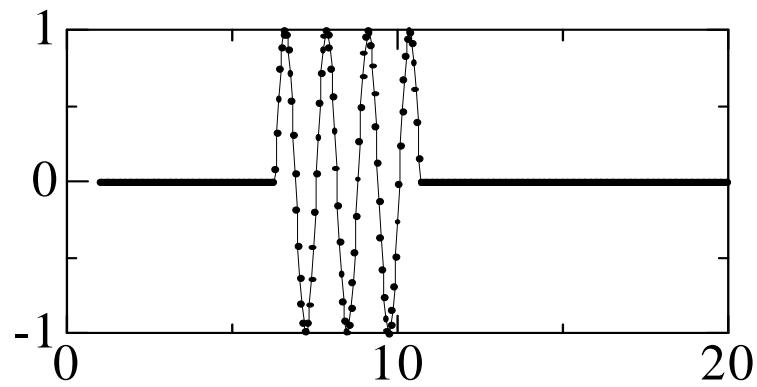
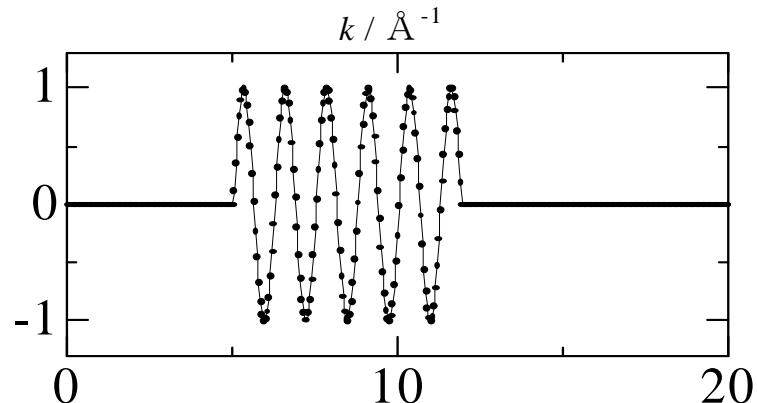


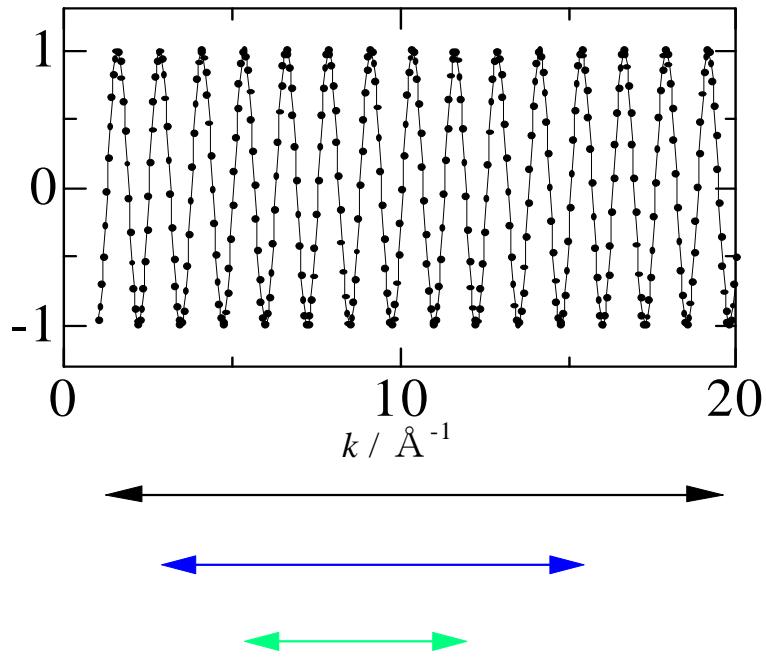
## *Fourier Transform for a three-shell model*



***This must be a BACKGROUND structure, not corresponding to a real atom-atom distance.***



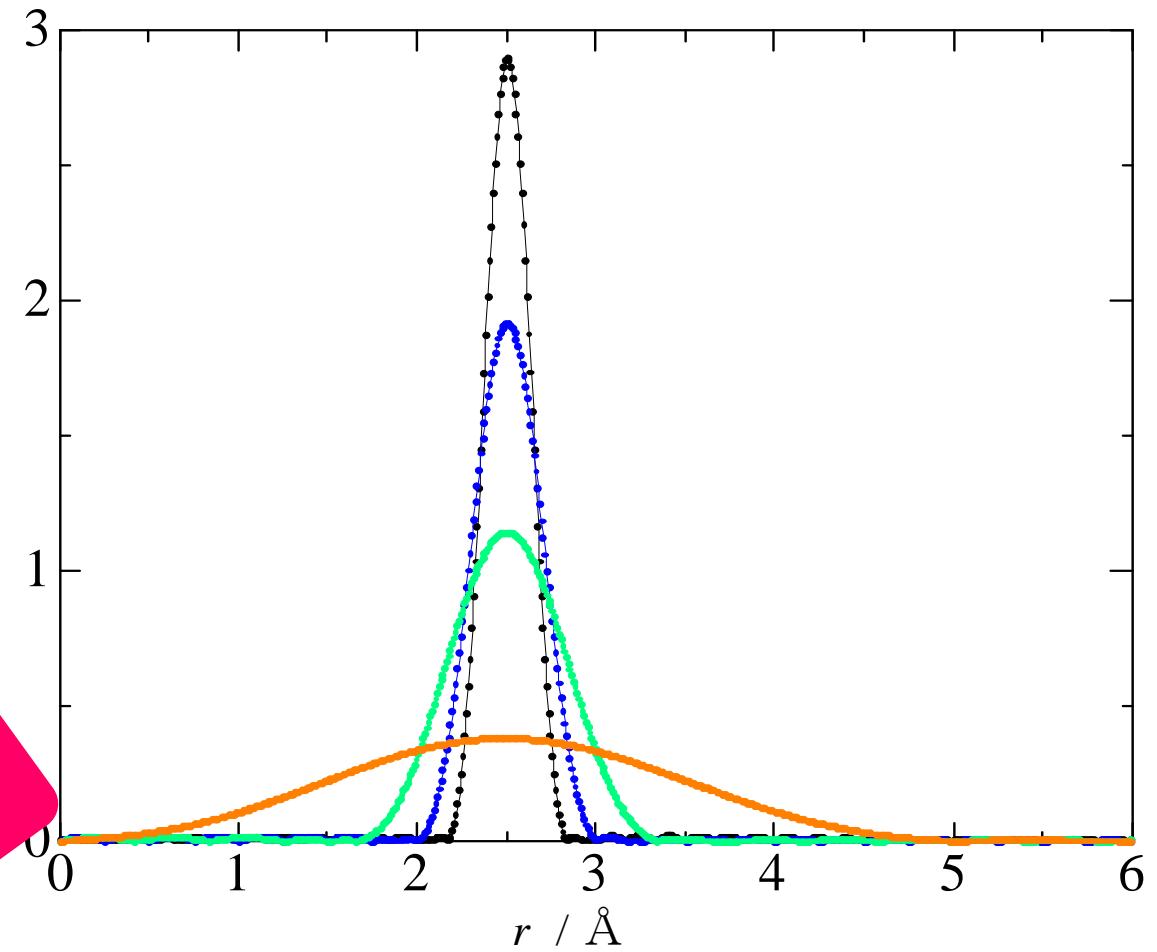




Fourier Transform for  
different  $k$  ranges

If you have a small  
number of cycles in  $k$ ,

Problem !



## BASIC EXAFS equation

$$\chi(k) = \sum_i \frac{N_i}{k r_i^2} f_i(k) \exp(-2\sigma_i^2 k^2 - 2r_i/\lambda) S_0^2(k) \sin(2kr_i + \phi_i(k))$$

amplitude part

oscillation part

By comparing the theoretical EXAFS  $\chi(k)$  and experimental  $\chi(k)$ , you can determine;

$N$  coordination number

$r$  bond length

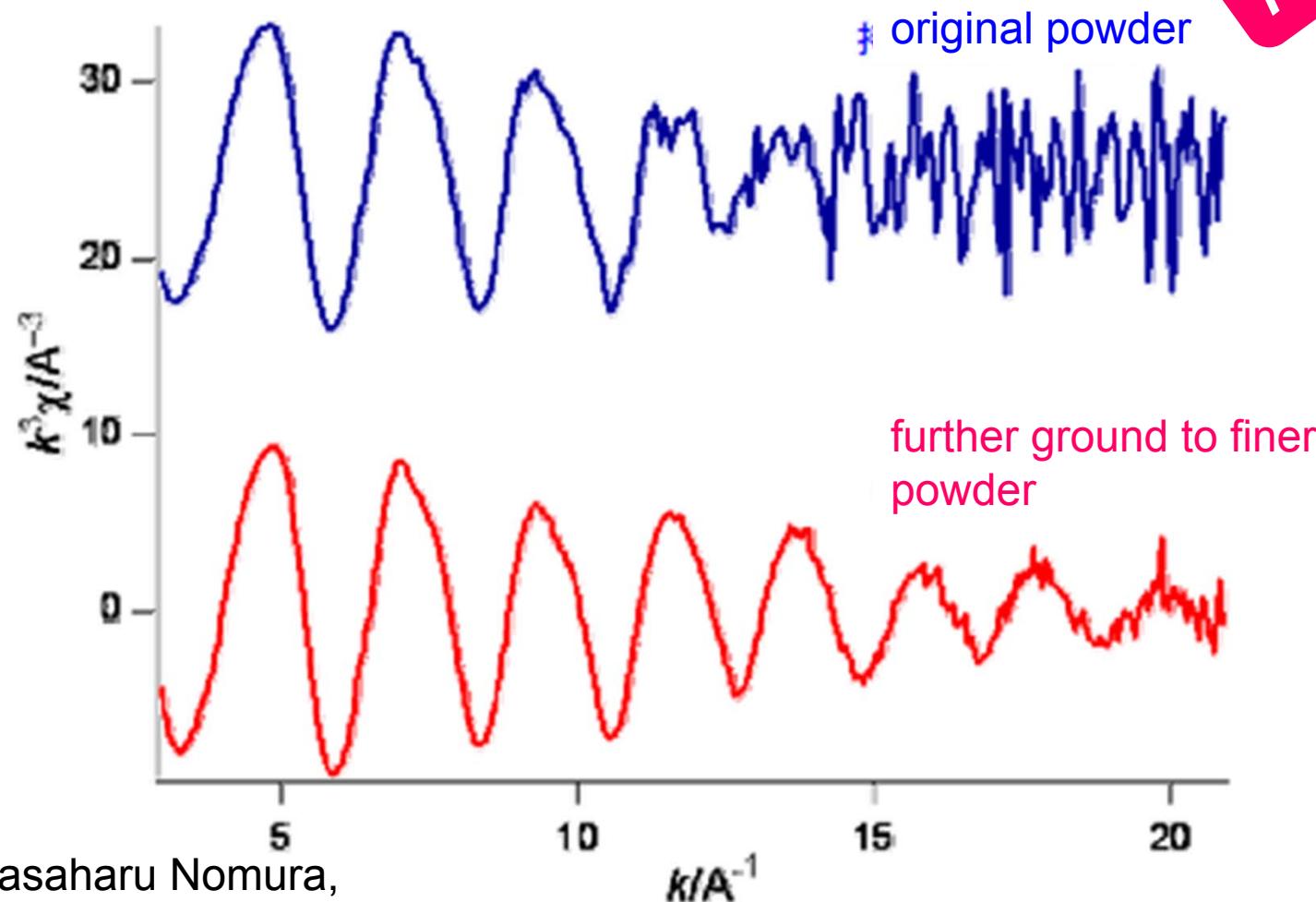
$f(k)$  and  $\phi(k)$  are element specific  
atomic type of coordination

*You may get in trouble with the data quality taken by transmission method*

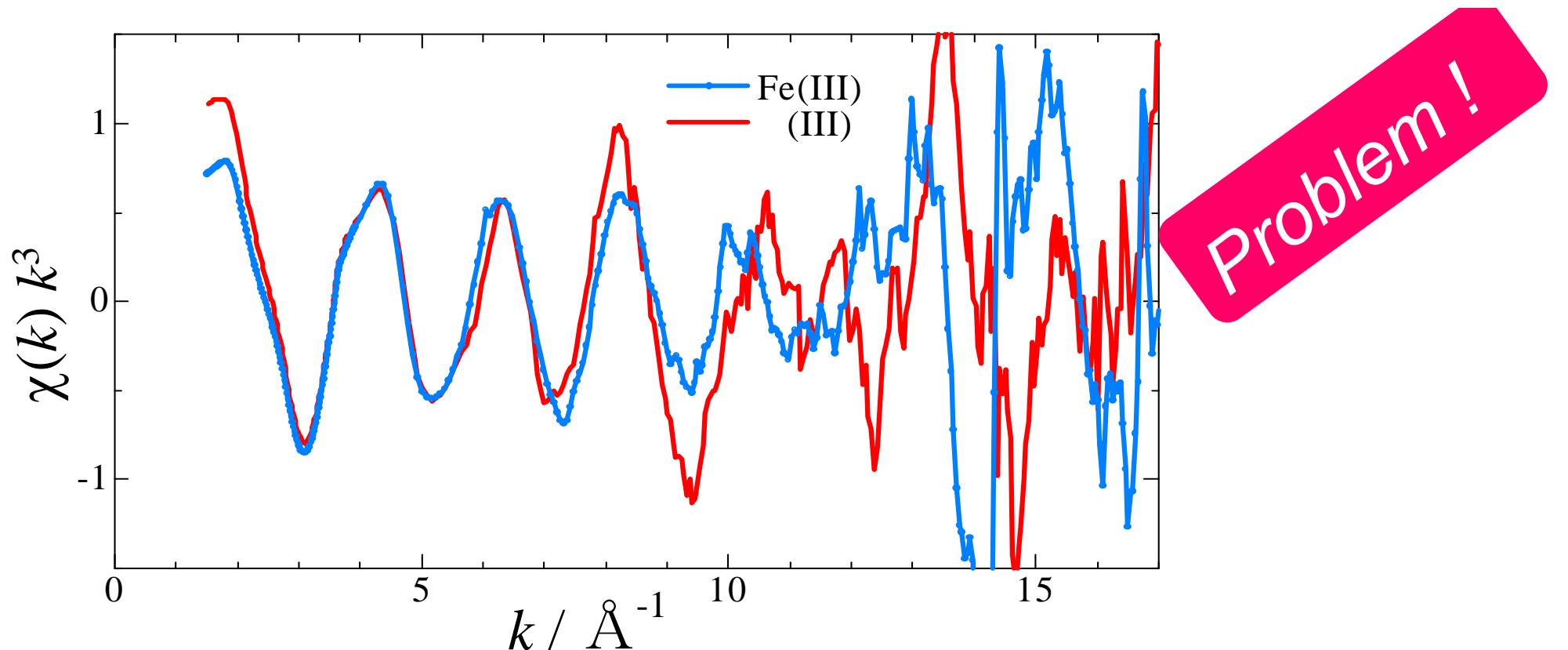
## Transmission method

Sample: Ge-Si powder

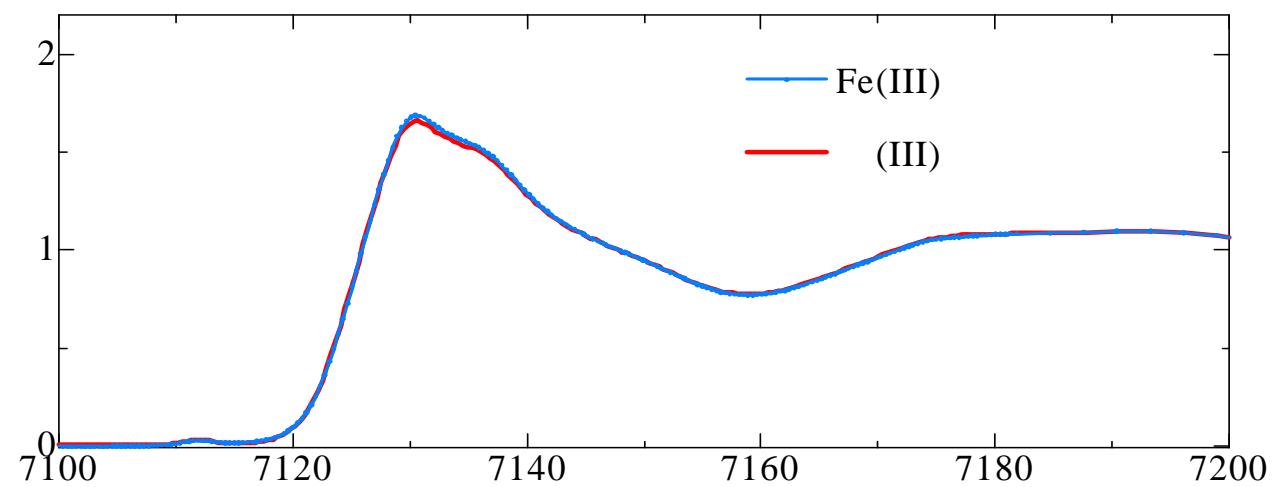
Problem !



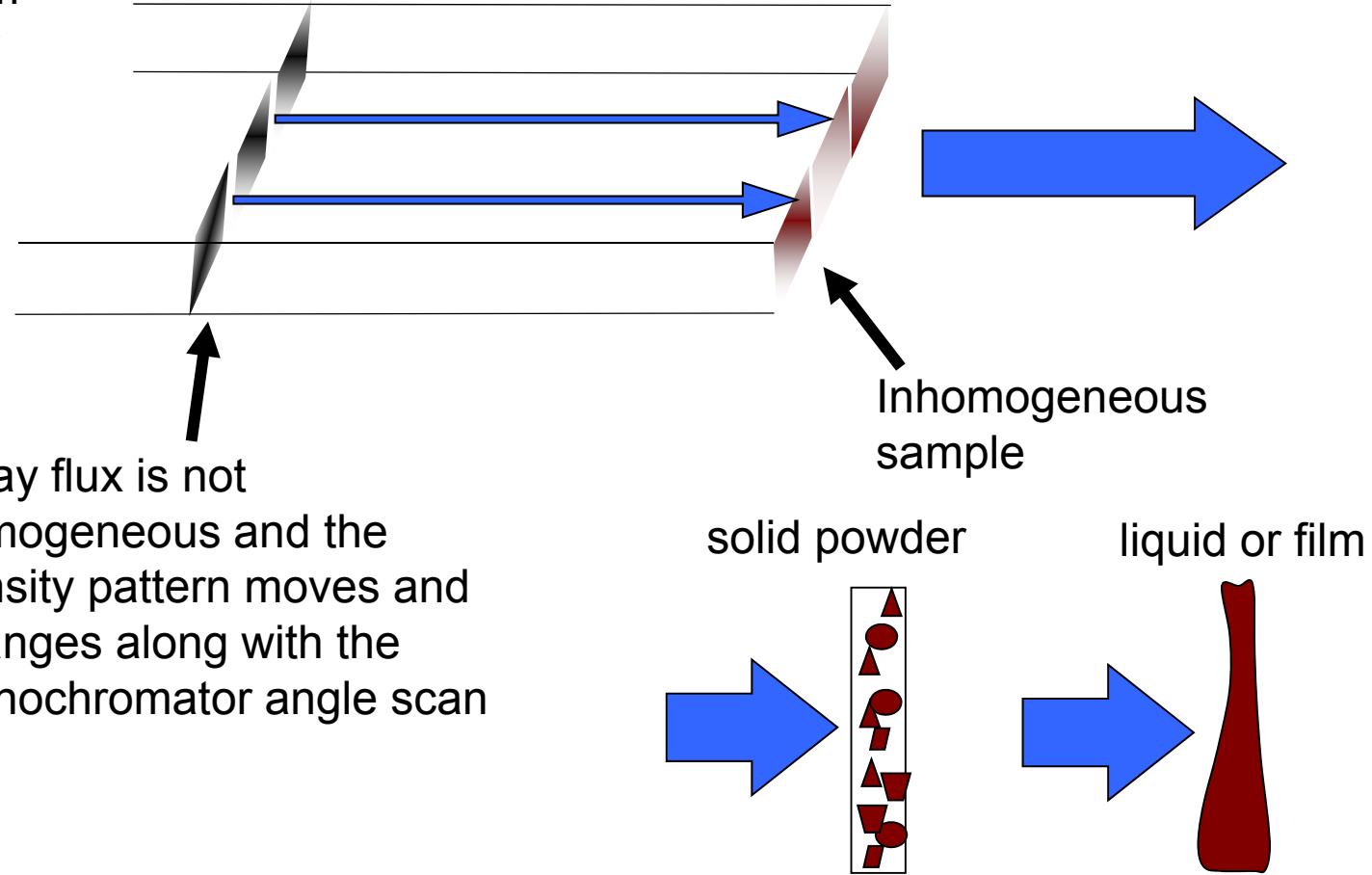
By Masaharu Nomura,  
Photon Factory, KEK



Fe(III) ions in aqueous  
solution  
possibly, inhomogeneous  
sample thickness



X-ray beam from monochromator



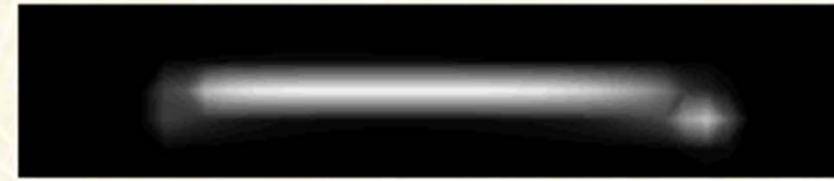
*Leads to weaker EXAFS oscillation amplitude and noisy spectrum*

## Si(311) double-crystal monochromator Output pattern

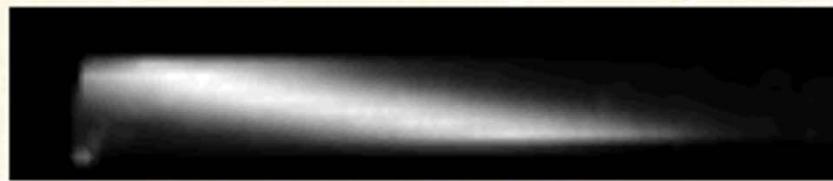
5 deg



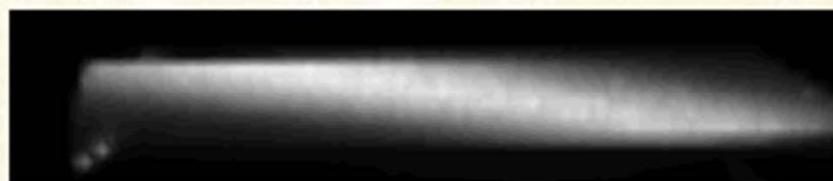
10 deg



15 deg



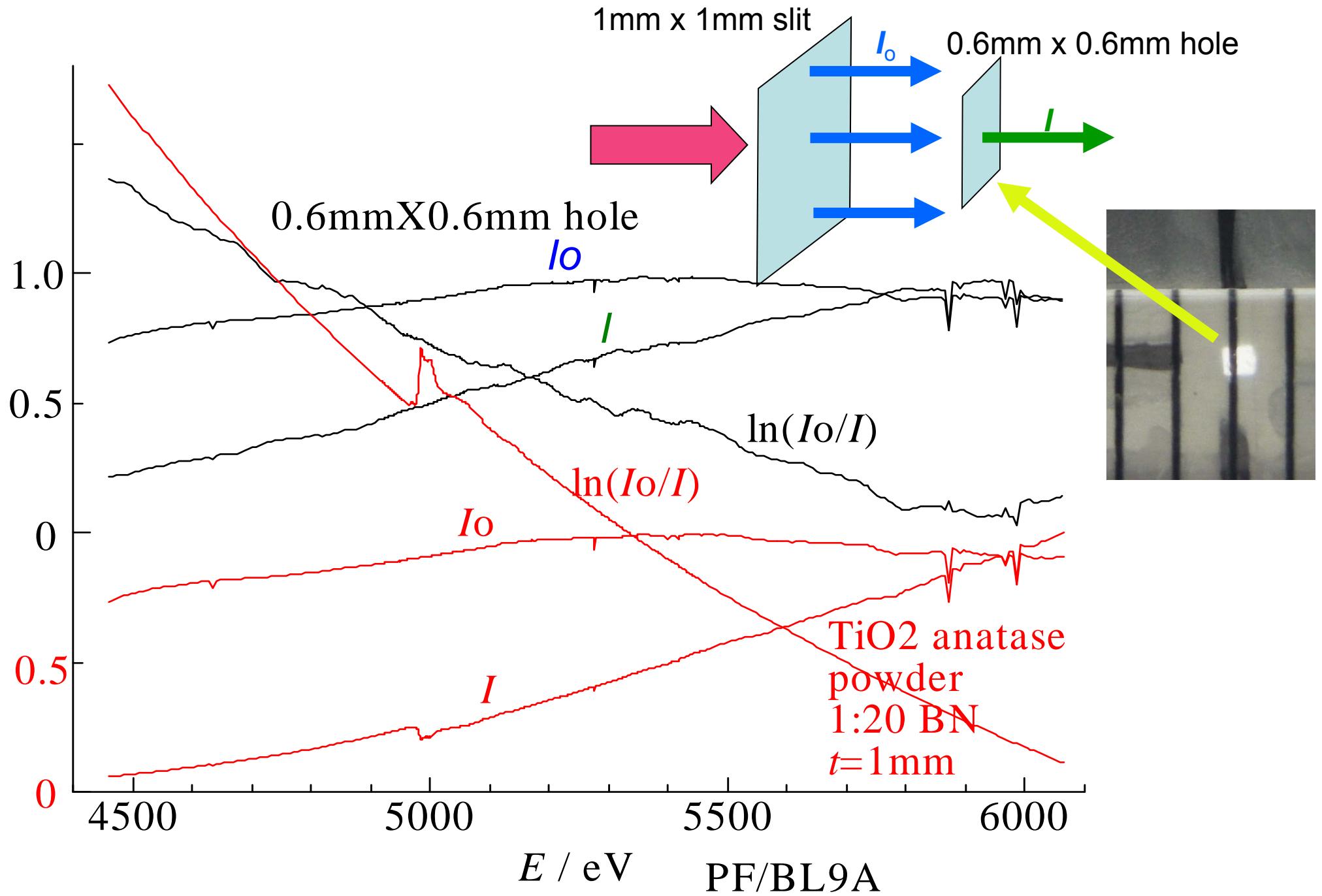
20 deg



before improvements on the crystal  
holding method

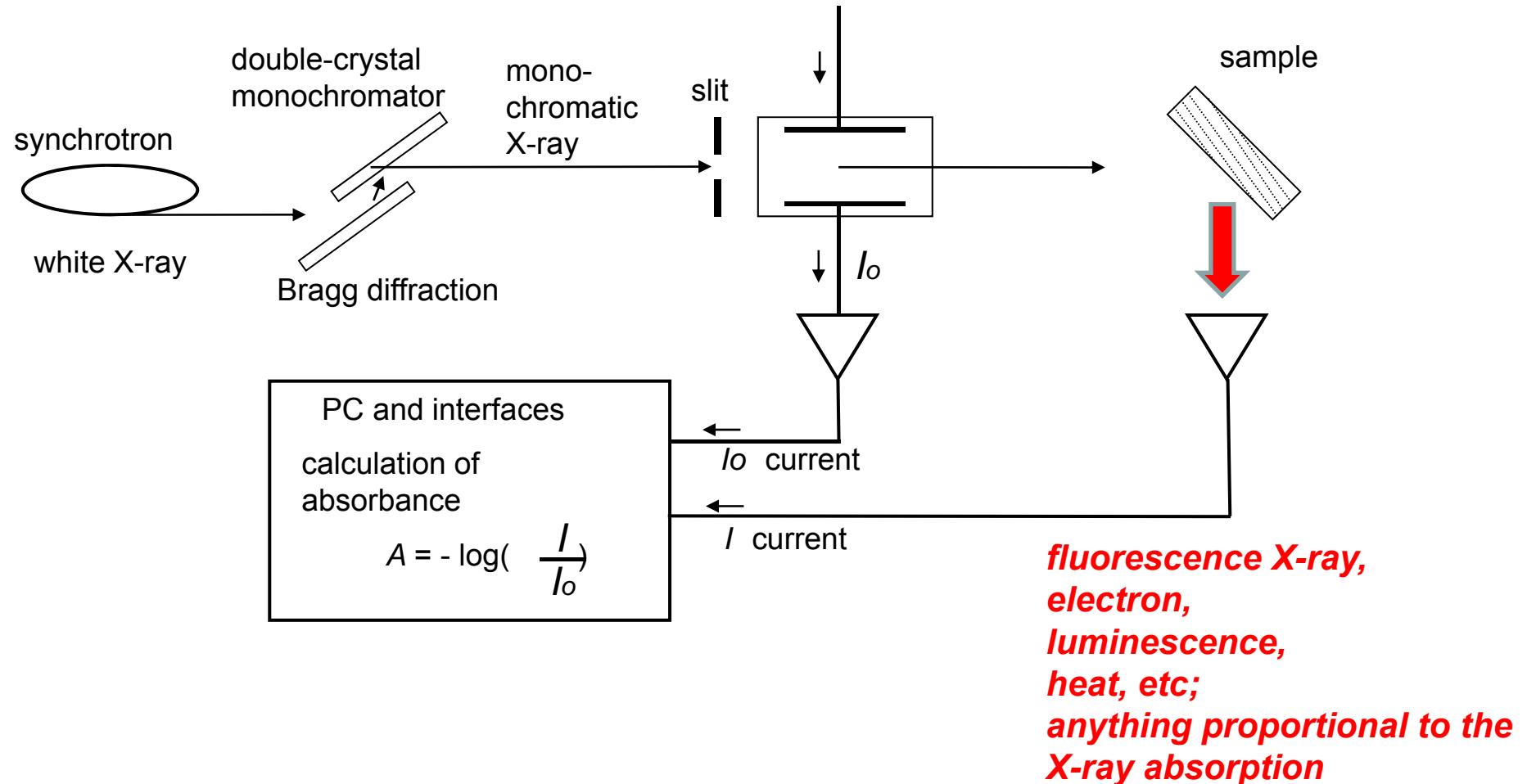
after improvements

mm

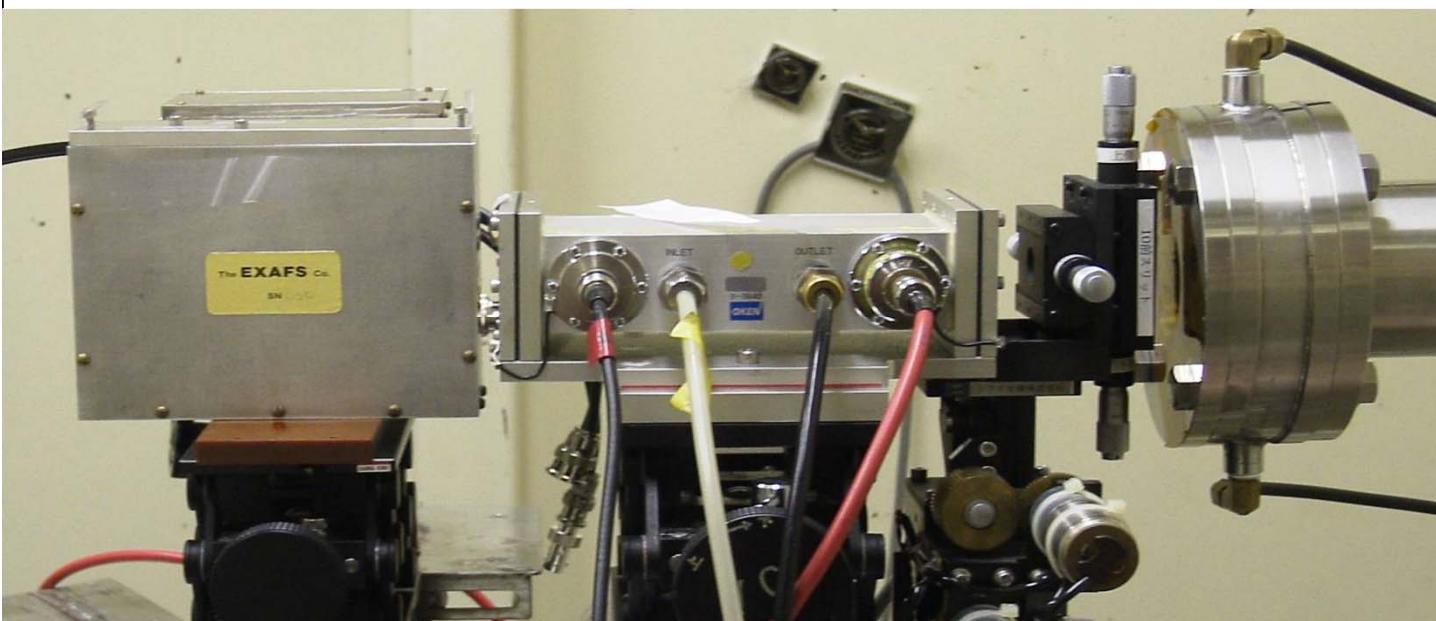
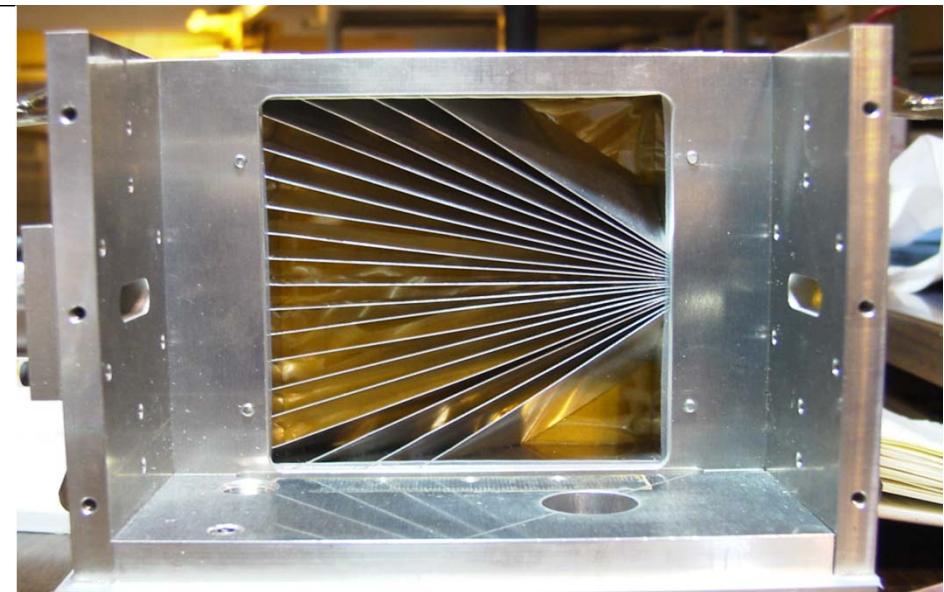
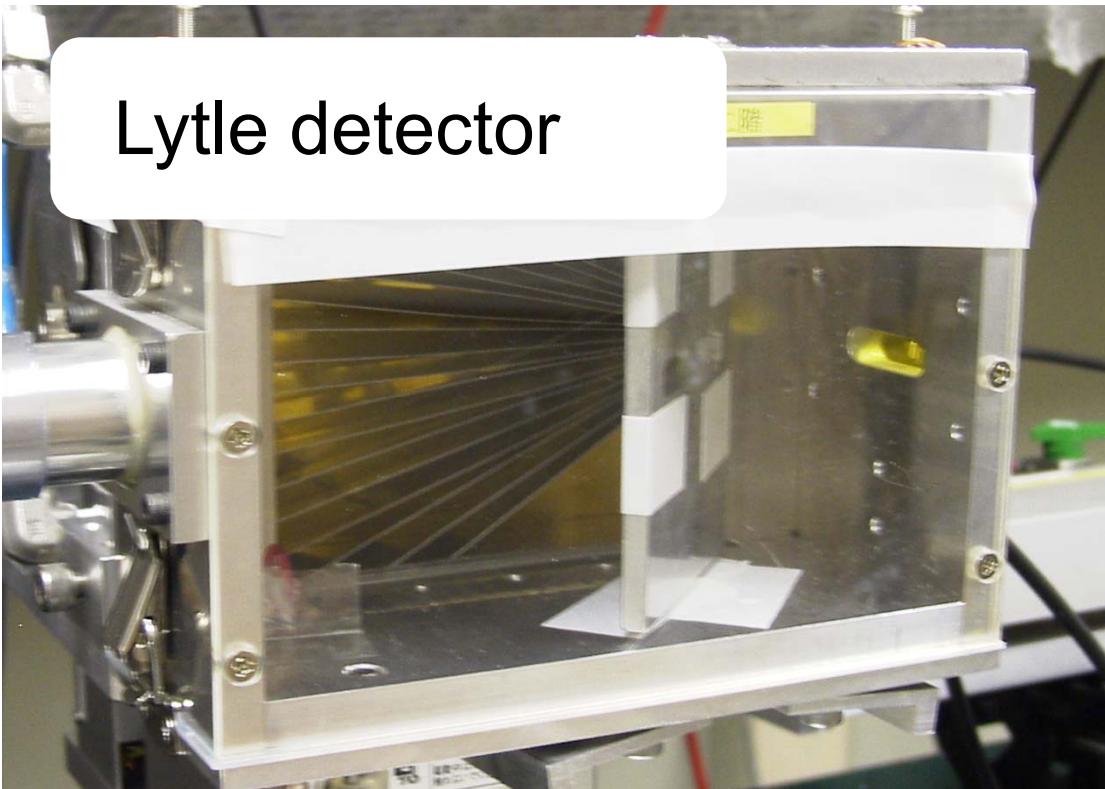


*Yield methods:*  
*Fluorescence yield*  
*and*  
*Total-conversion-electron-yield*

## X-ray absorption measurement by *yield* methods

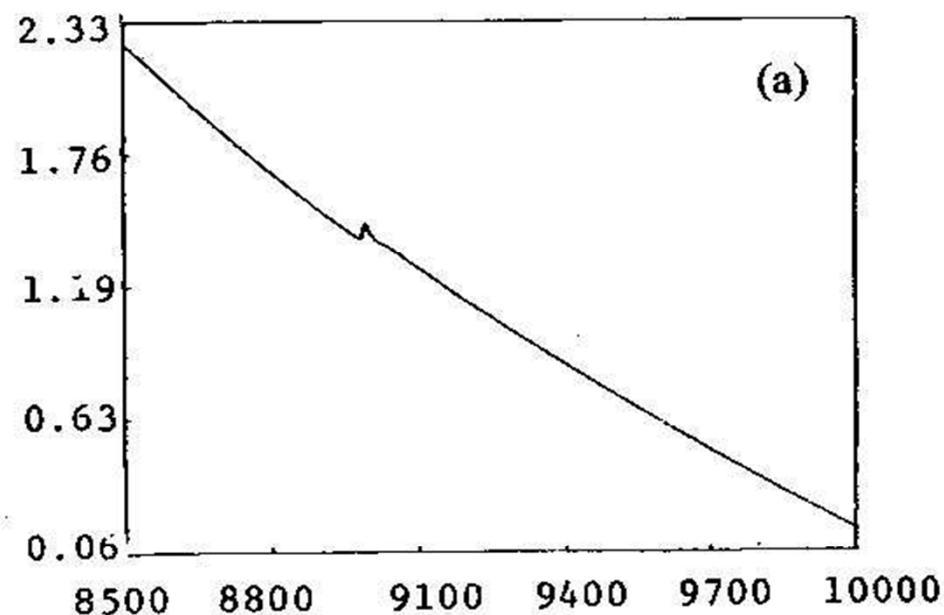


# Lytle detector

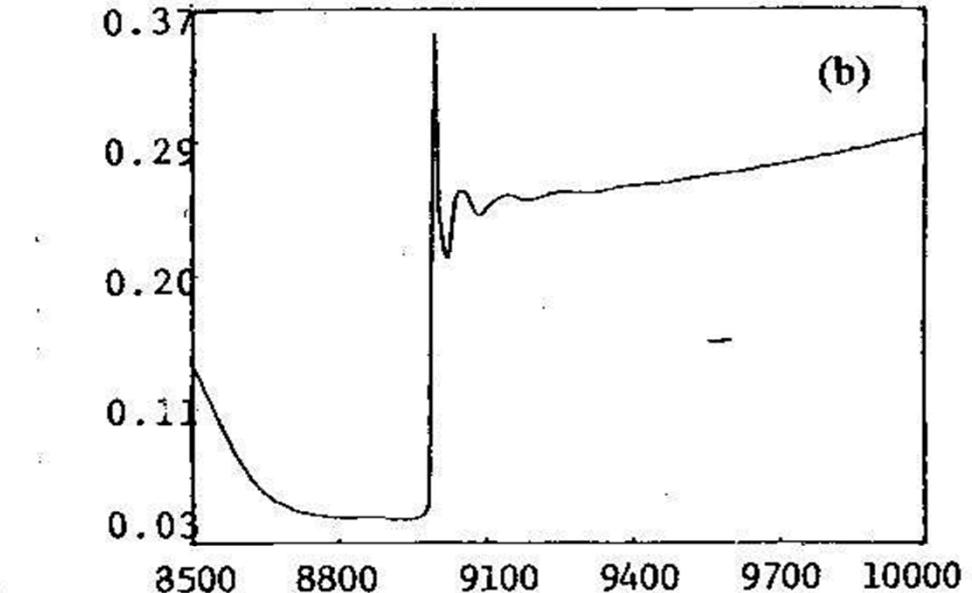


Sample:  $0.01 \text{ mol dm}^{-3}$  Cu(II) solution

transmittance



fluorescence

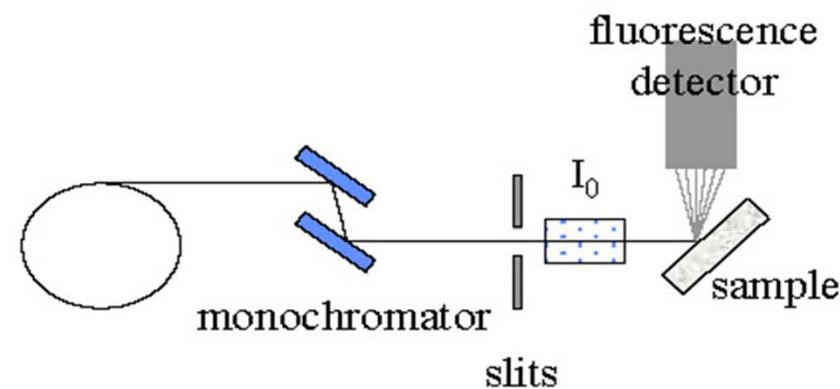
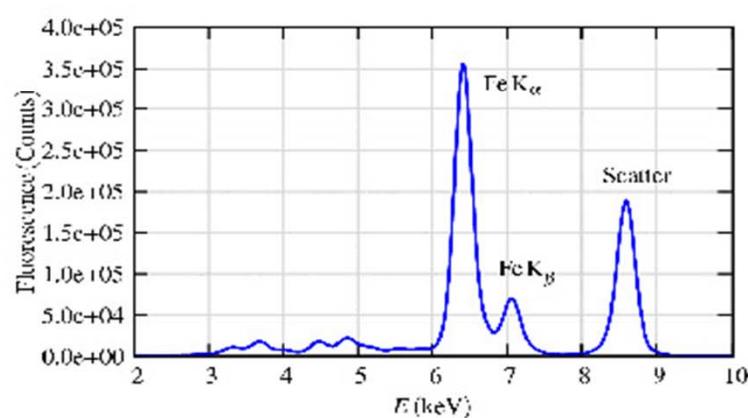


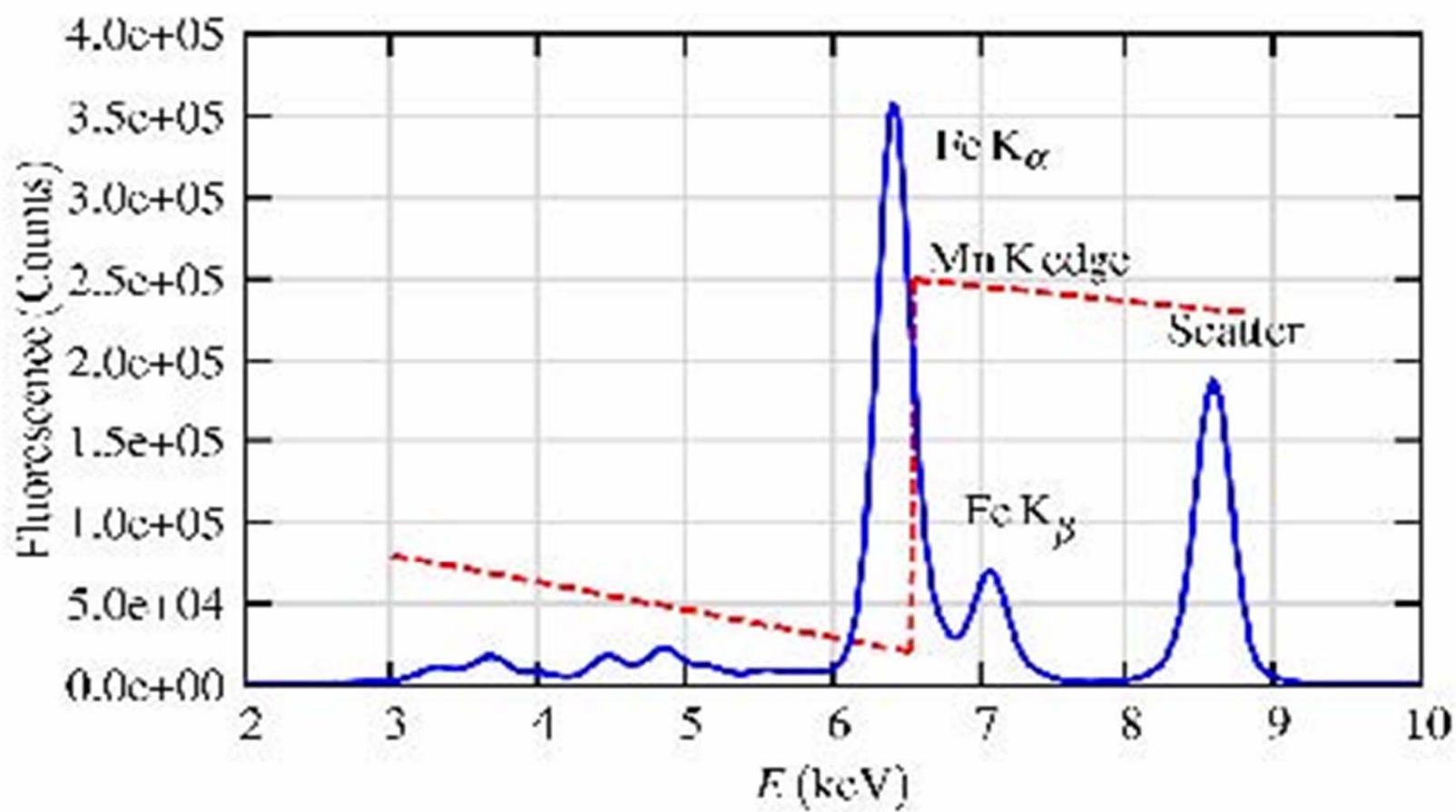
By Masaharu Nomura,  
Photon Factory, KEK

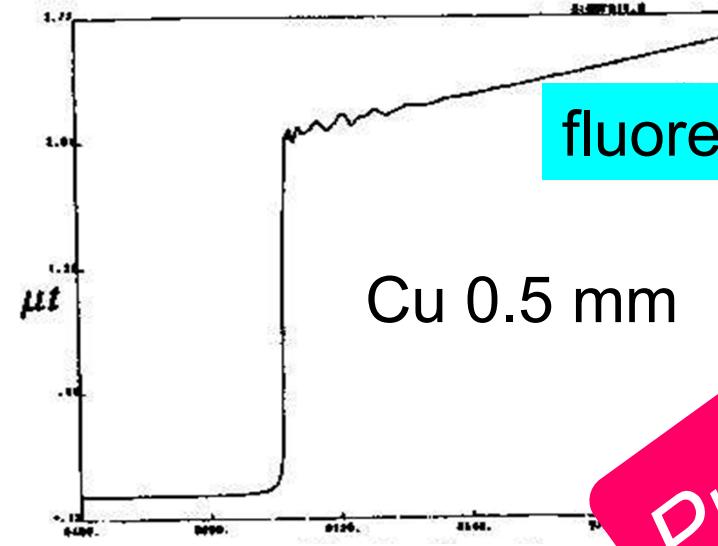
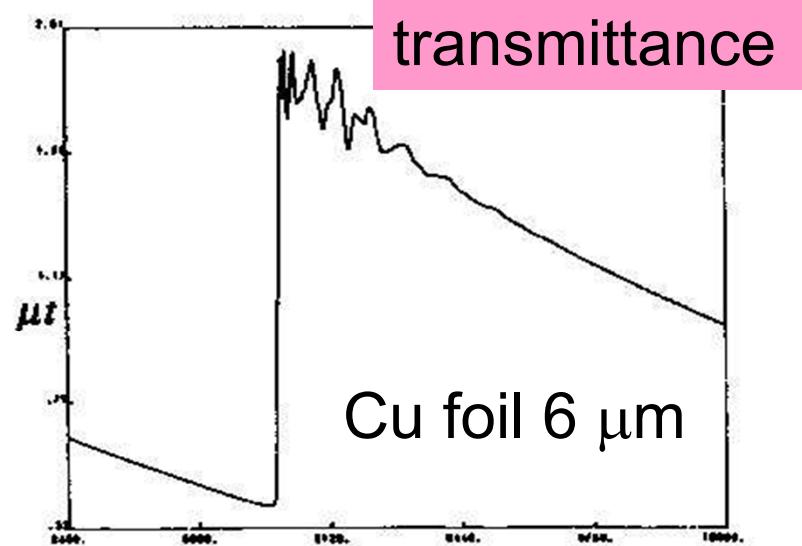
# Fluorescence XAFS Experiment: Solid State Detectors

**uop**  
A Honeywell Company

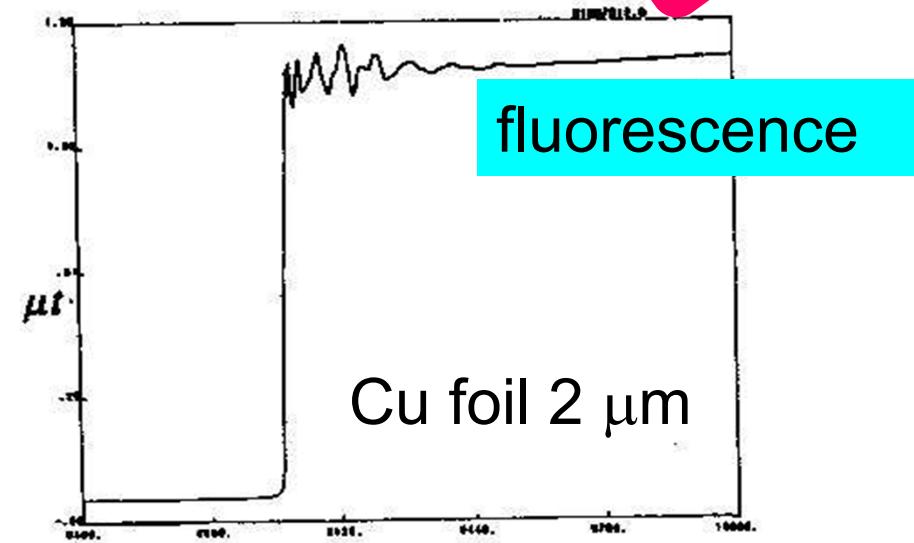
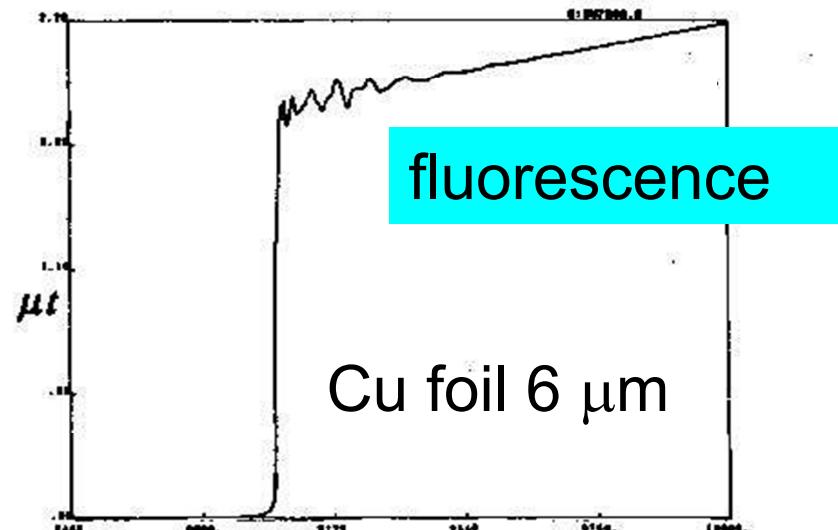
- Alternative is to use a solid state detector with active element of Ge or Si as the x-ray absorber. This uses electronic energy discrimination.
- Typical energy resolution 200-300 eV.
- Has advantage of measuring the full x-ray fluorescence spectrum, so useful for identifying other elements in sample.
- Can be used for XAFS measurements with concentration to 10's of ppm.







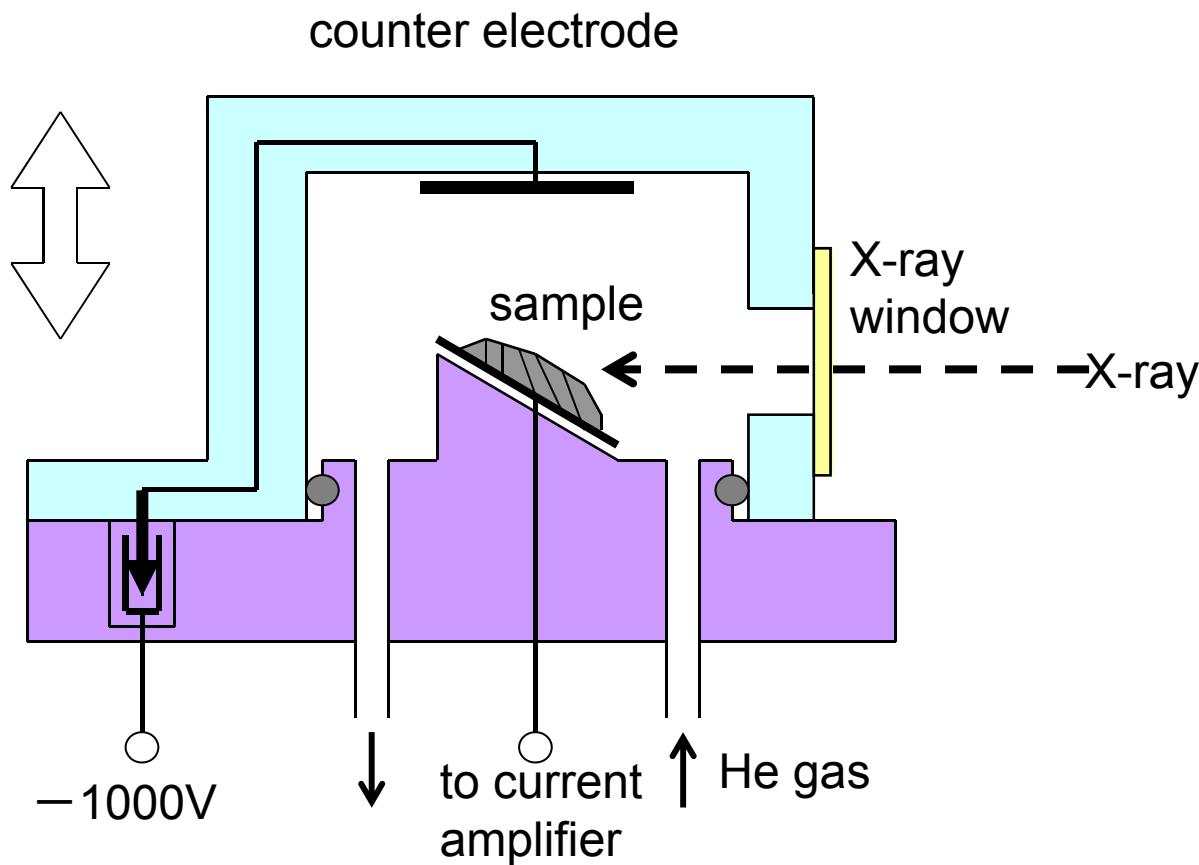
Problem !

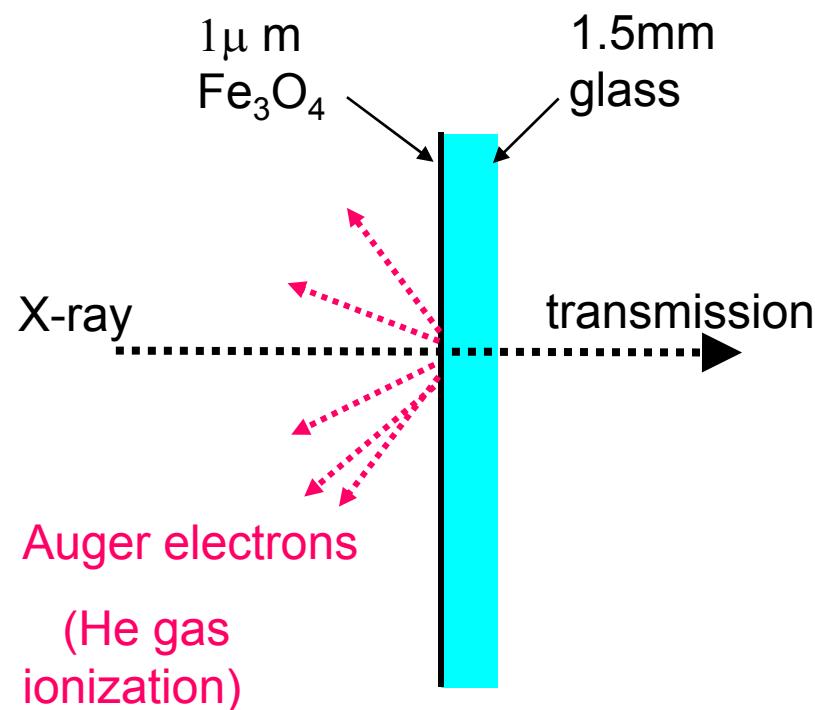


By Masaharu Nomura,  
Photon Factory, KEK

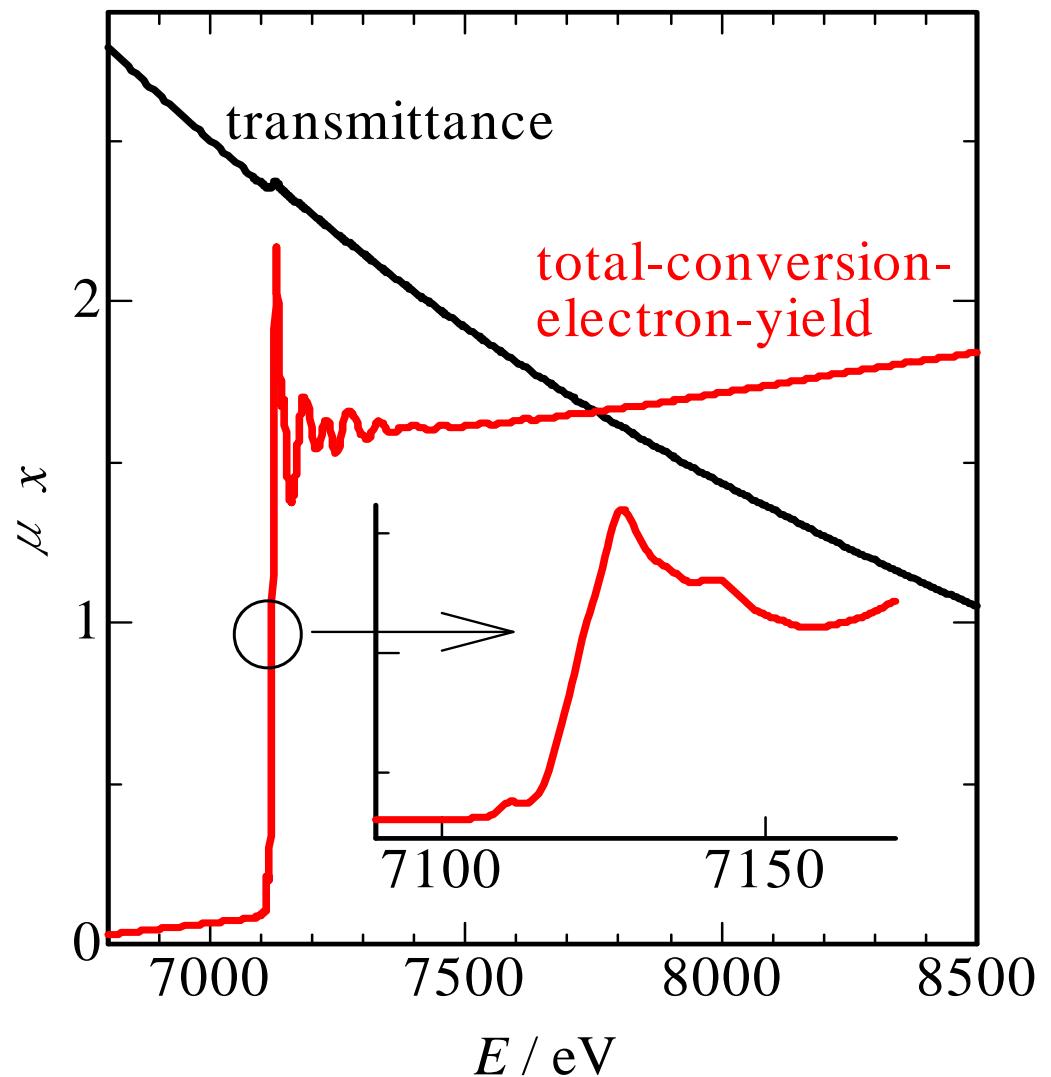
Self-absorption effect  $\rightarrow$  incorrect  $N$

# Total-Conversion-Electron-Yield method

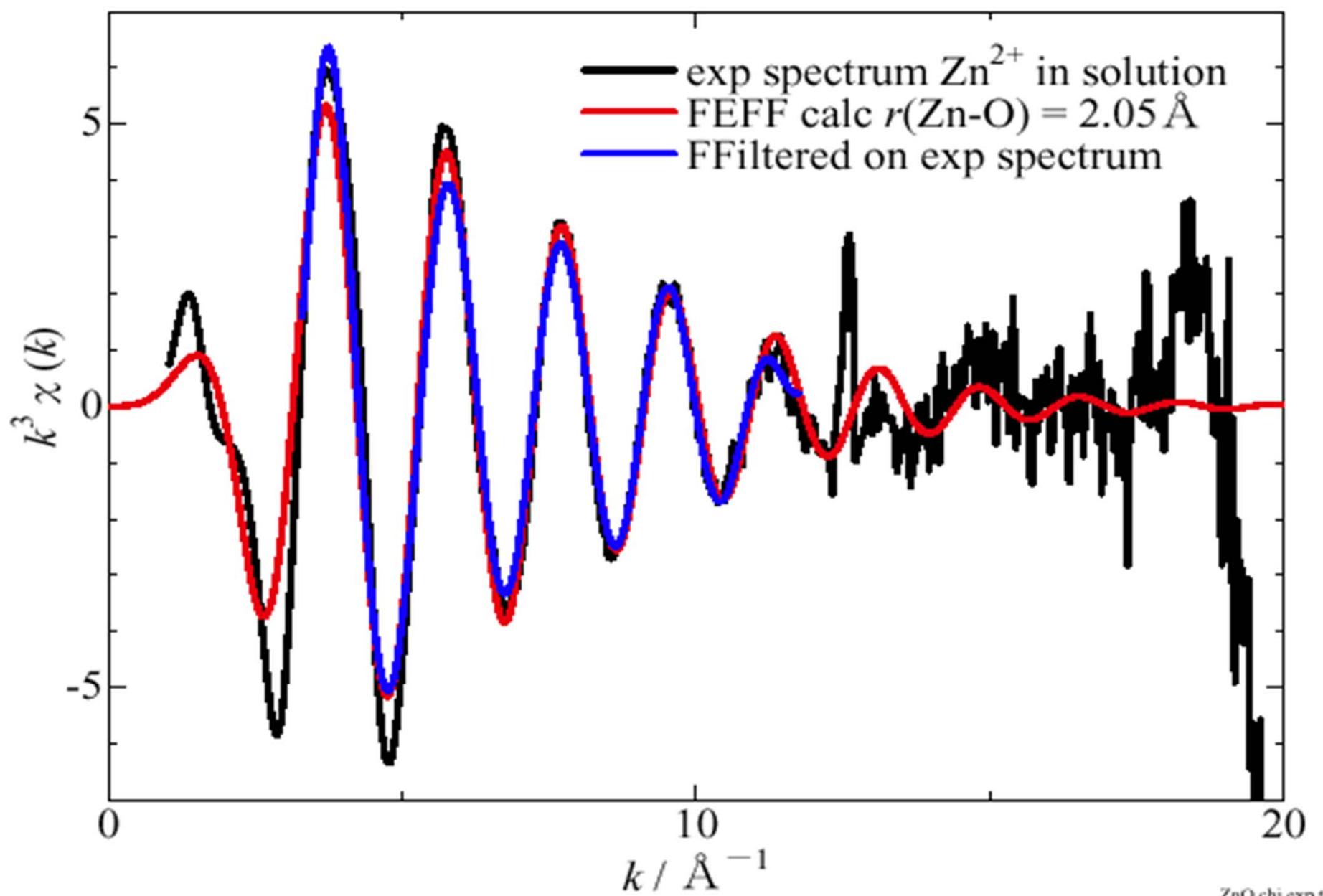




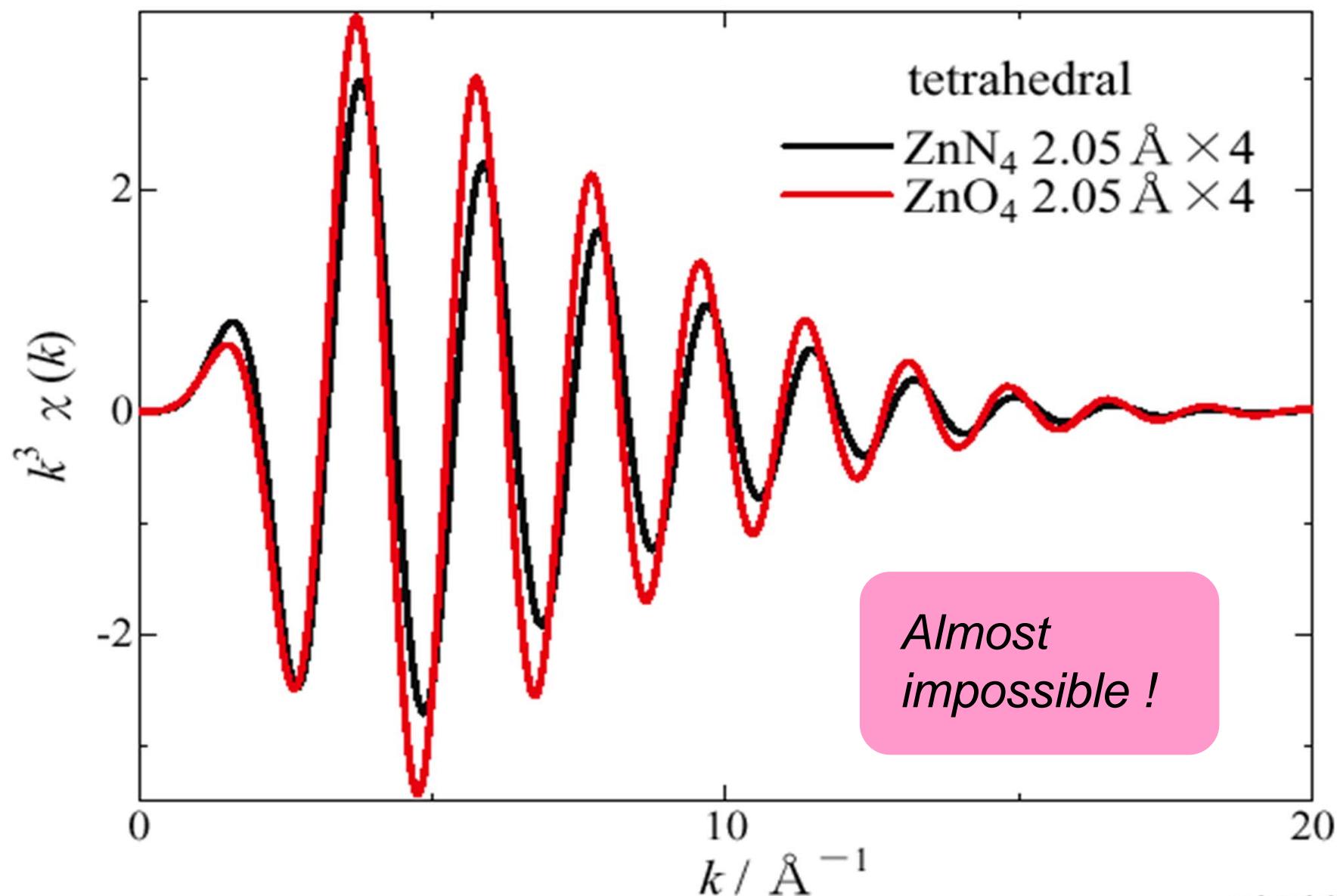
This method can be applied to thick samples owing to the short escape depth of Auger electron.



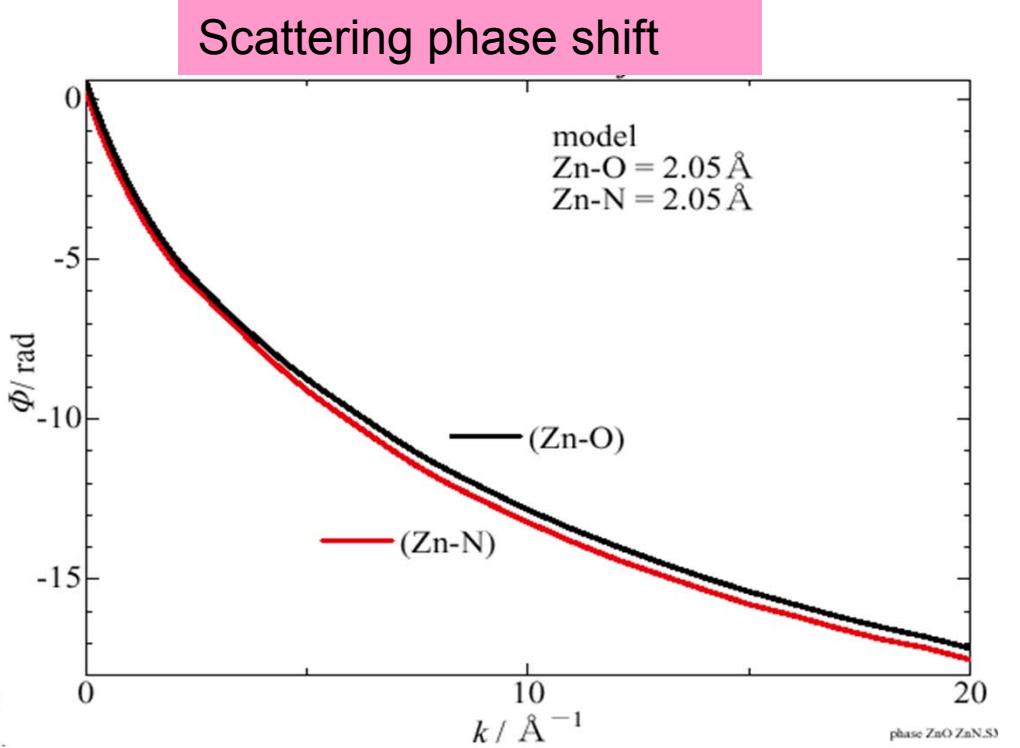
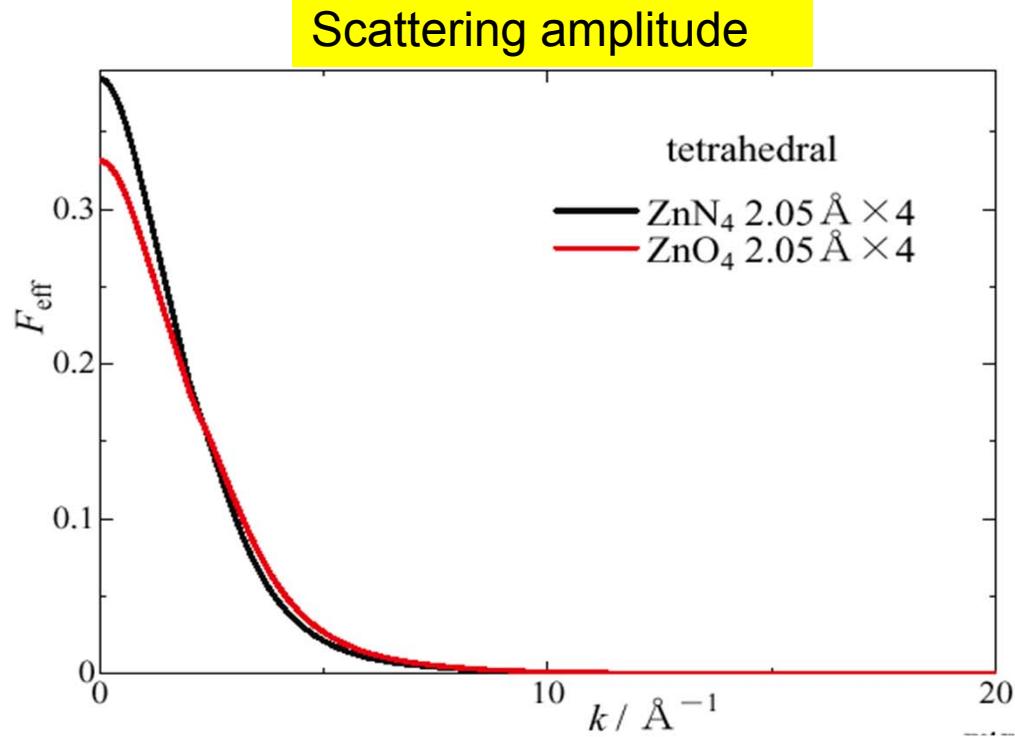
*Can we distinguish oxygen from  
nitrogen by EXAFS?*



ZnO chi exp theo.SMP



zno4 znn4 chi.smp

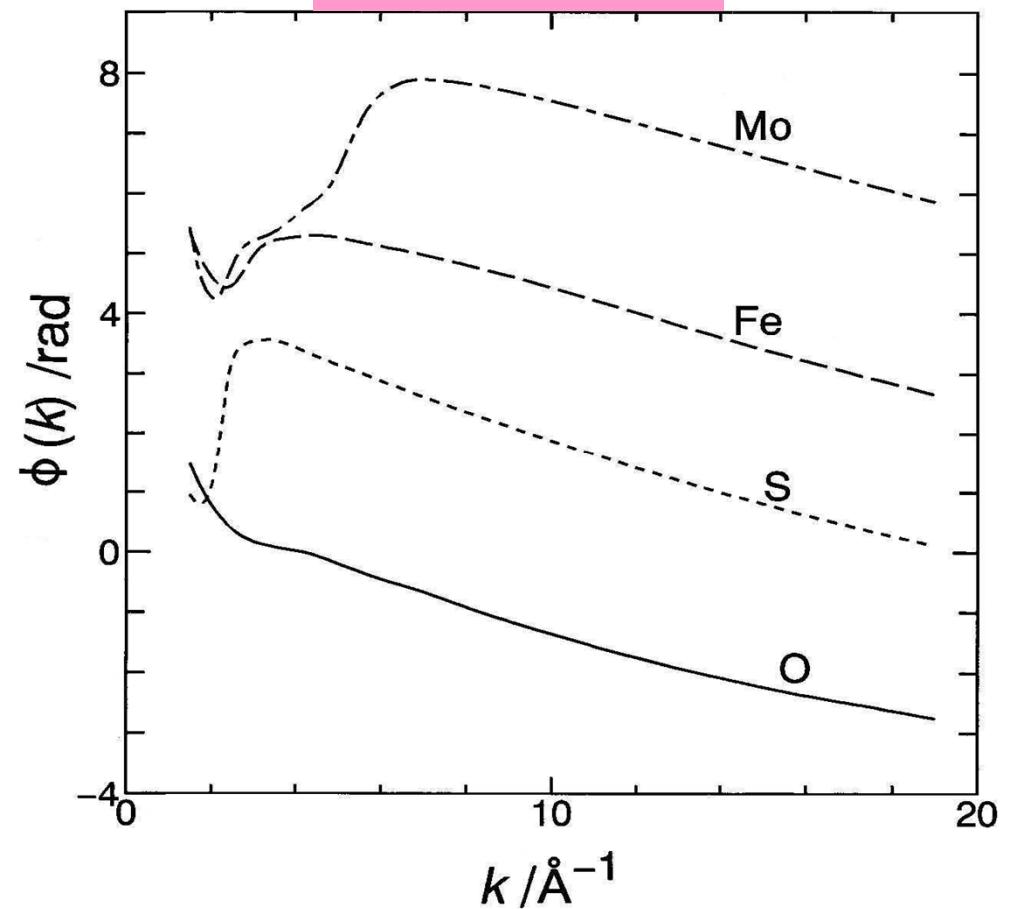
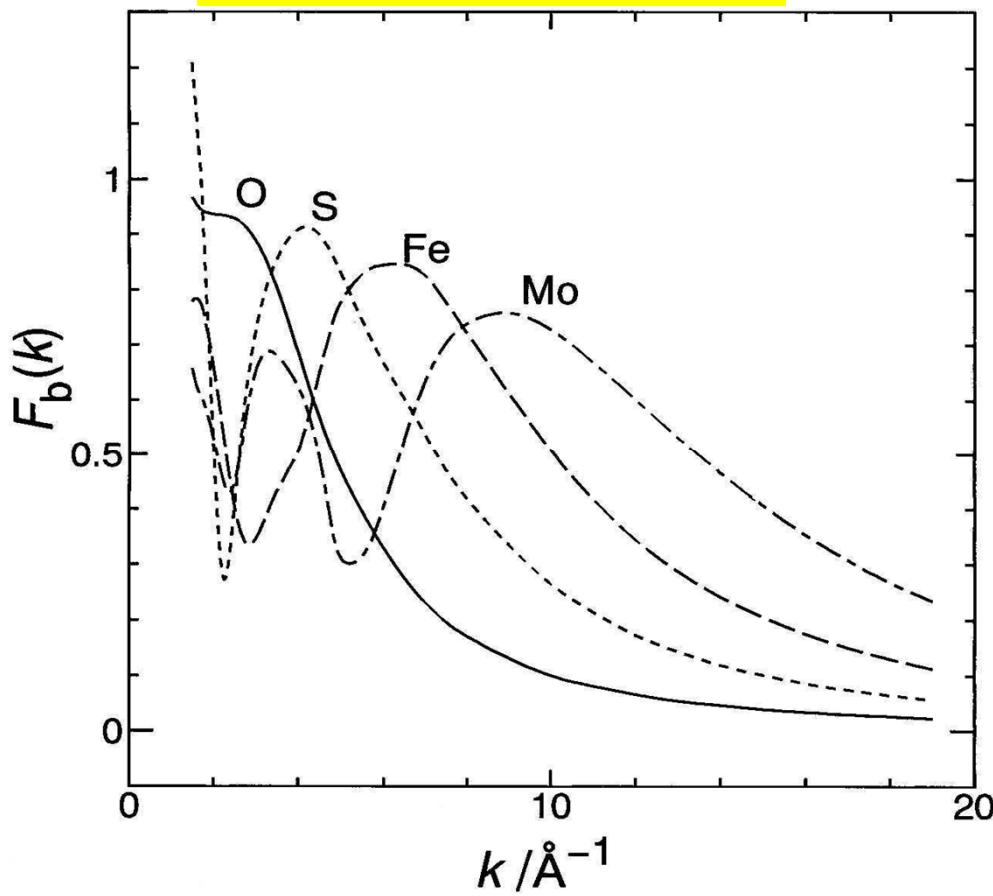


$$\chi(k) = \sum_i \frac{N_i}{k r_i^2} f_i(k) \exp(-2\sigma_i^2 k^2 - 2r_i/\lambda) S_0^2(k) \sin(2kr_i + \phi_i(k))$$

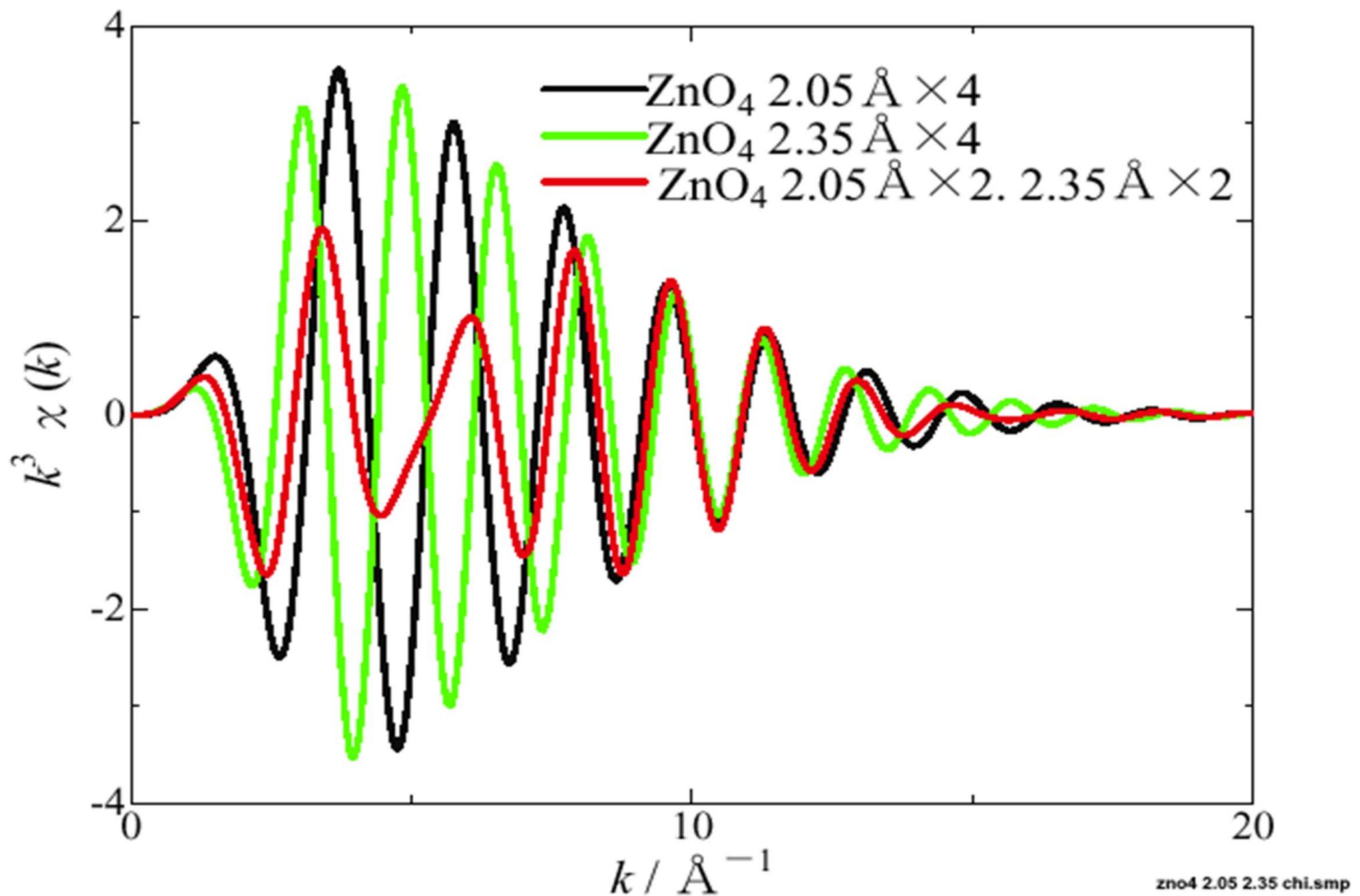
$$\chi(k) = \sum_i \frac{N_i}{k r_i^2} f_i(k) \exp(-2\sigma_i^2 k^2 - 2r_i/\lambda) S_0^2(k) \sin(2kr_i + \phi_i(k))$$

amplitude part      oscillation part

*f* scattering amplitude      *ϕ* phase shift

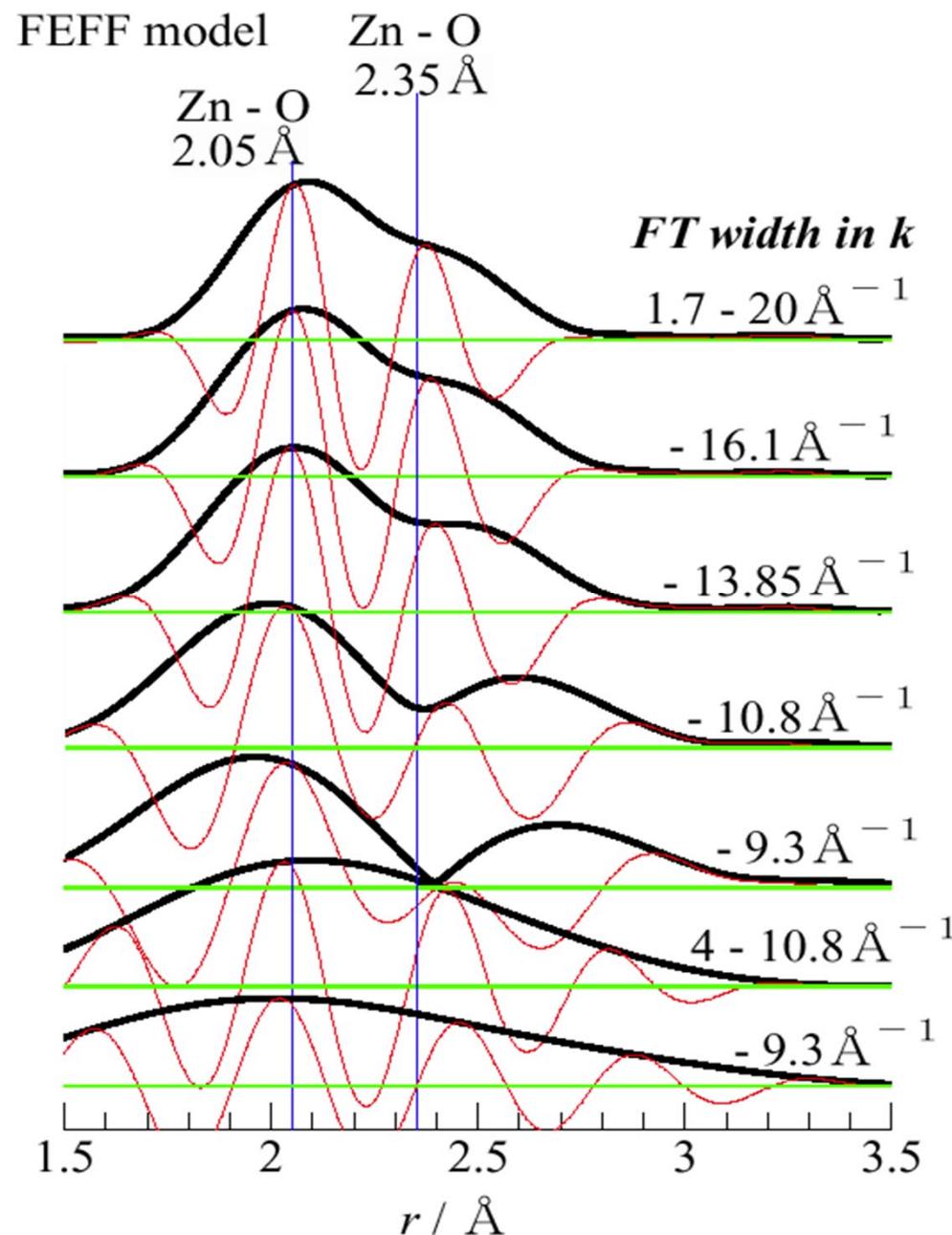


*Can we distinguish oxygen atoms 15% distant from others by EXAFS?*



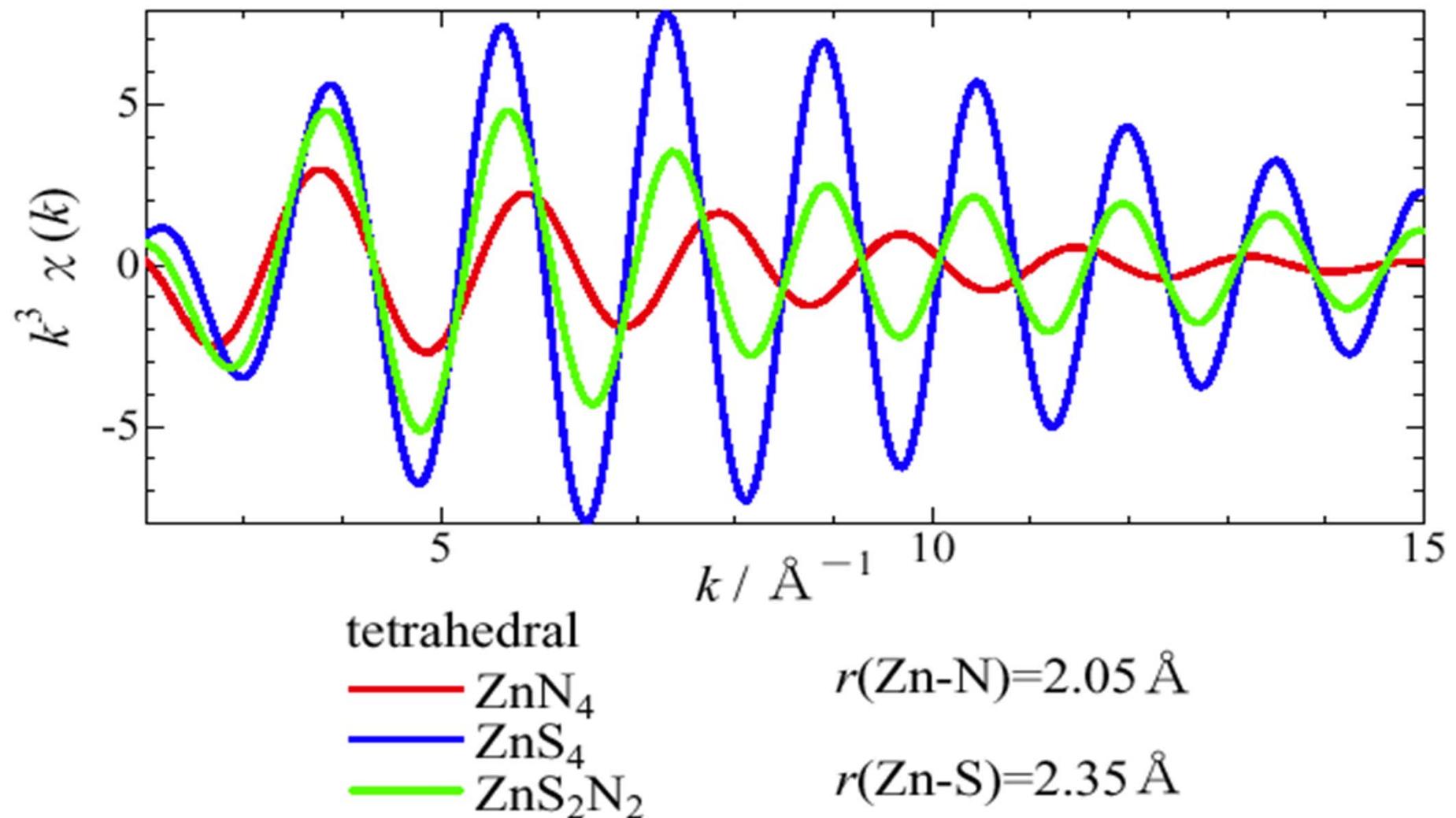
zno4 2.05 2.35 chi.smp

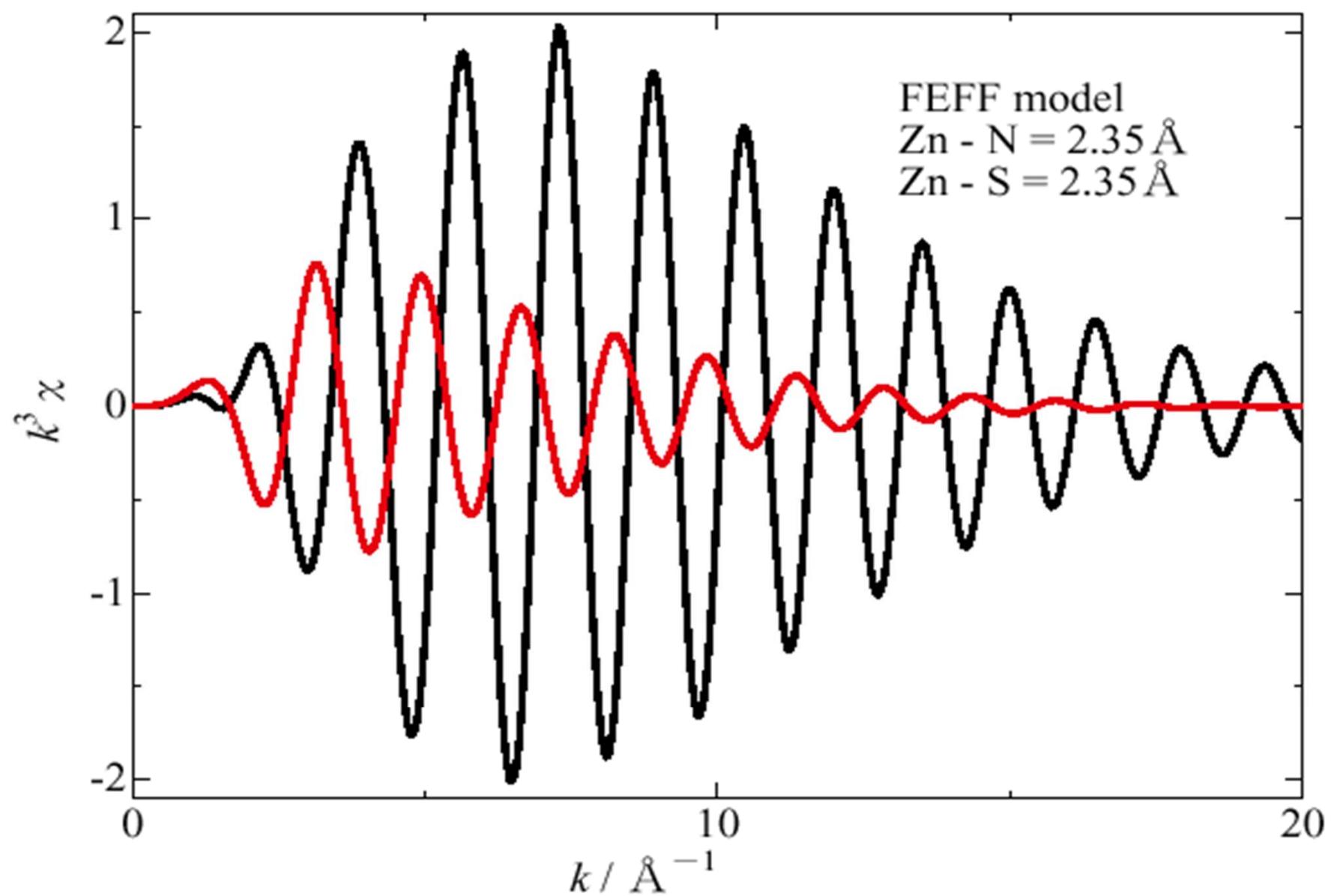
*Parameters used for Fourier Trans: O*



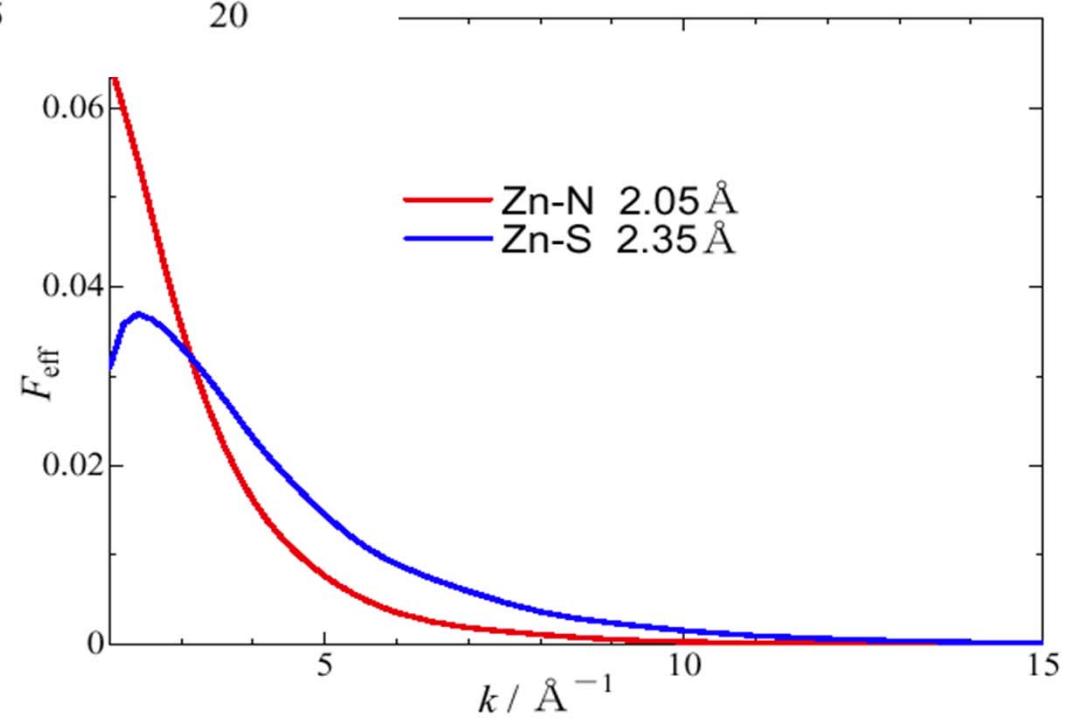
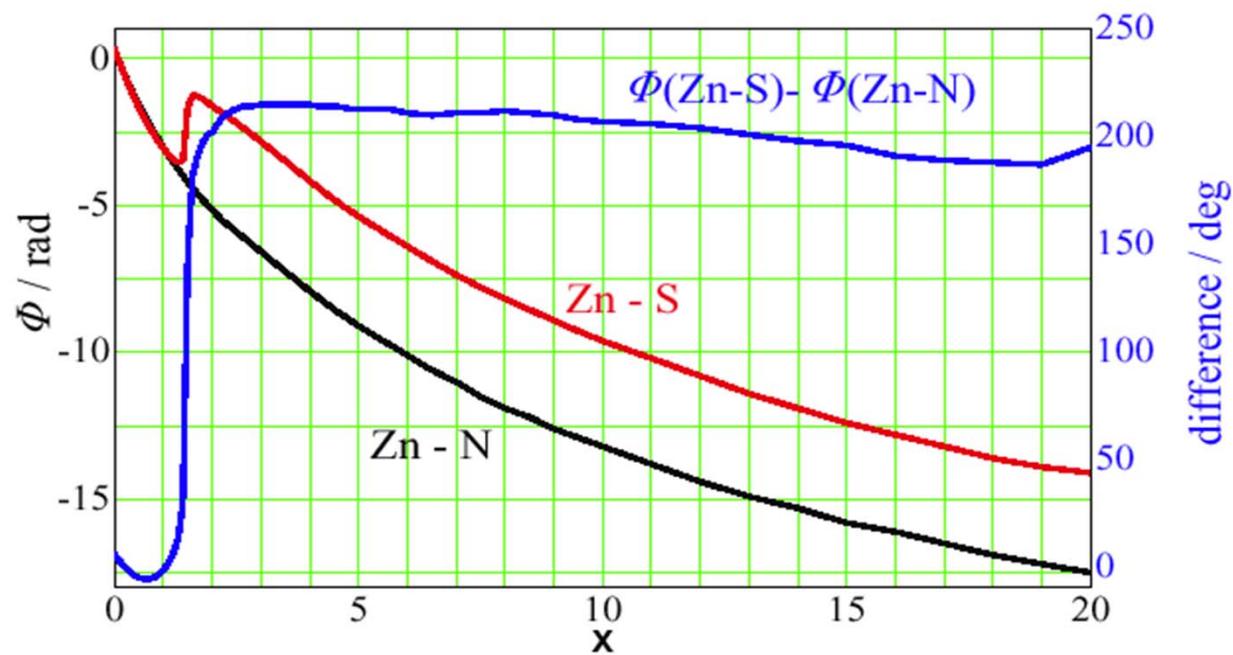
*James E. Penner-Hahn J. Am. Chem. Soc. 1998,120,8401*

*Can we distinguish sulfur from  
nitrogen (or oxygen) by EXAFS?*



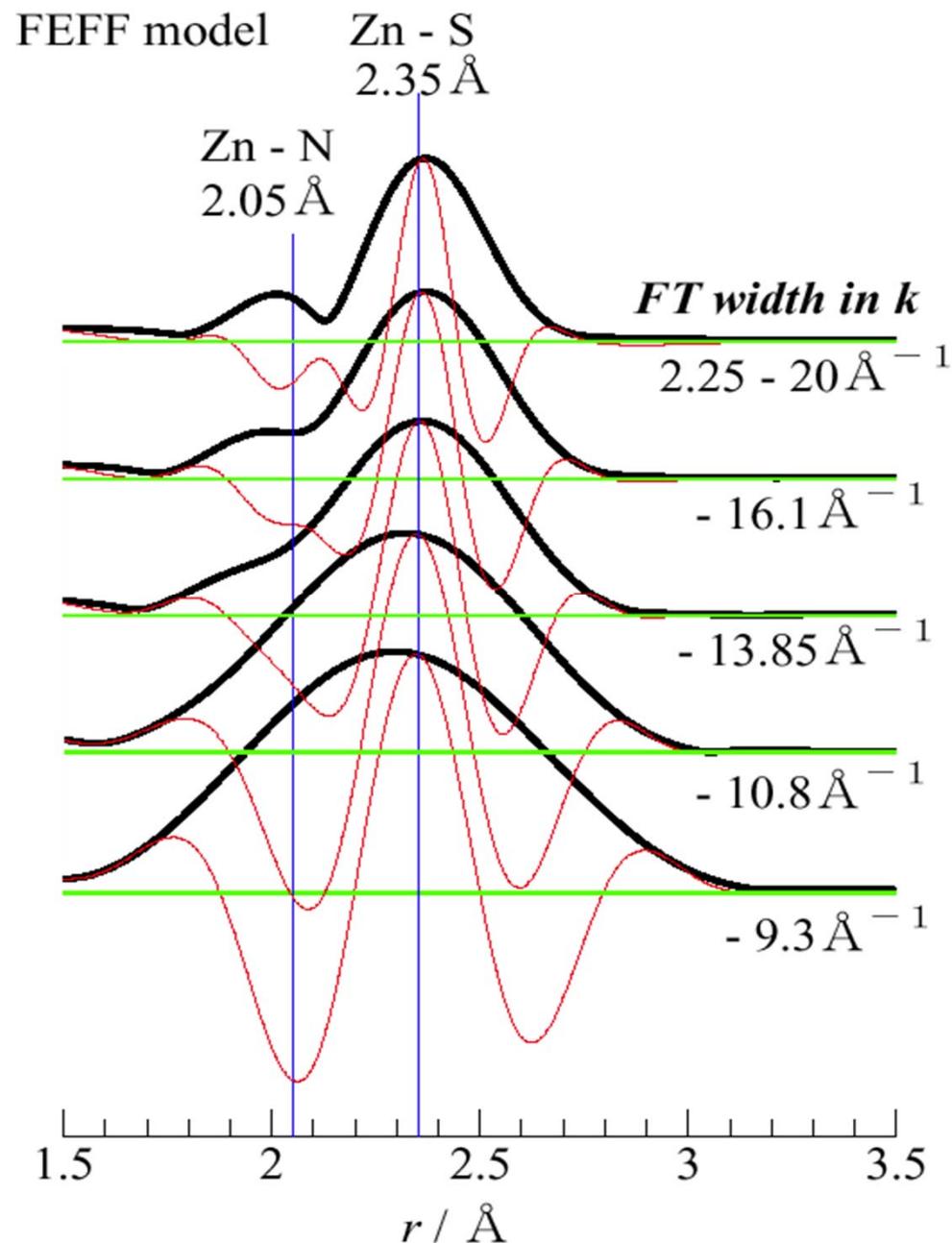


zns 2.35 znn 2.35.smp



f\_zns znn.smp

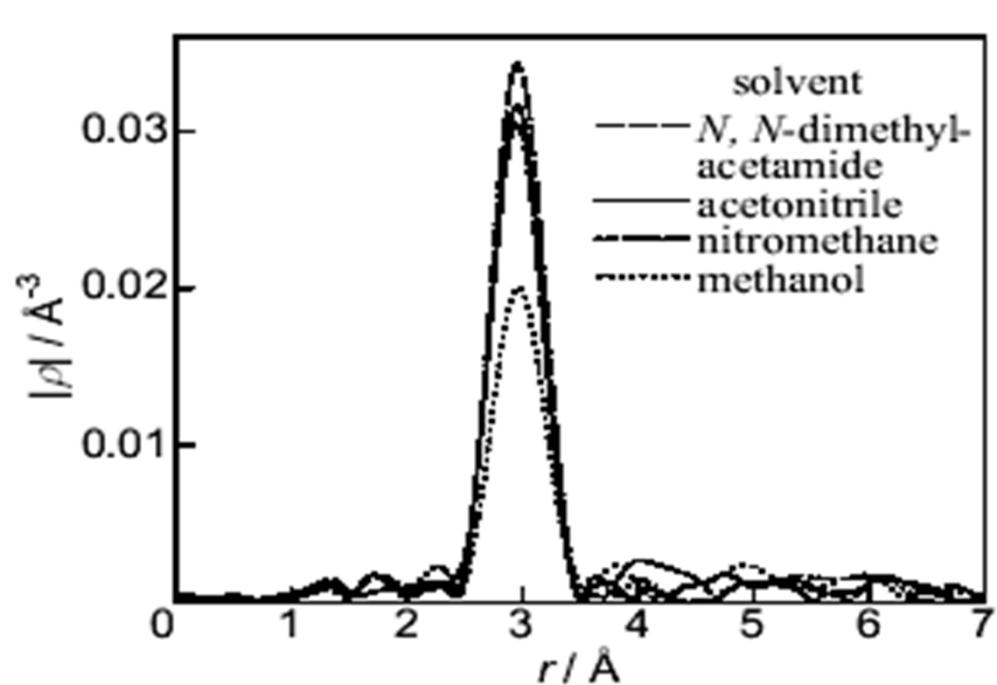
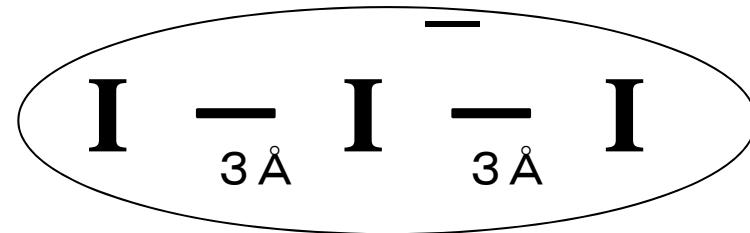
## *Parameters used for Fourier Trans: S*



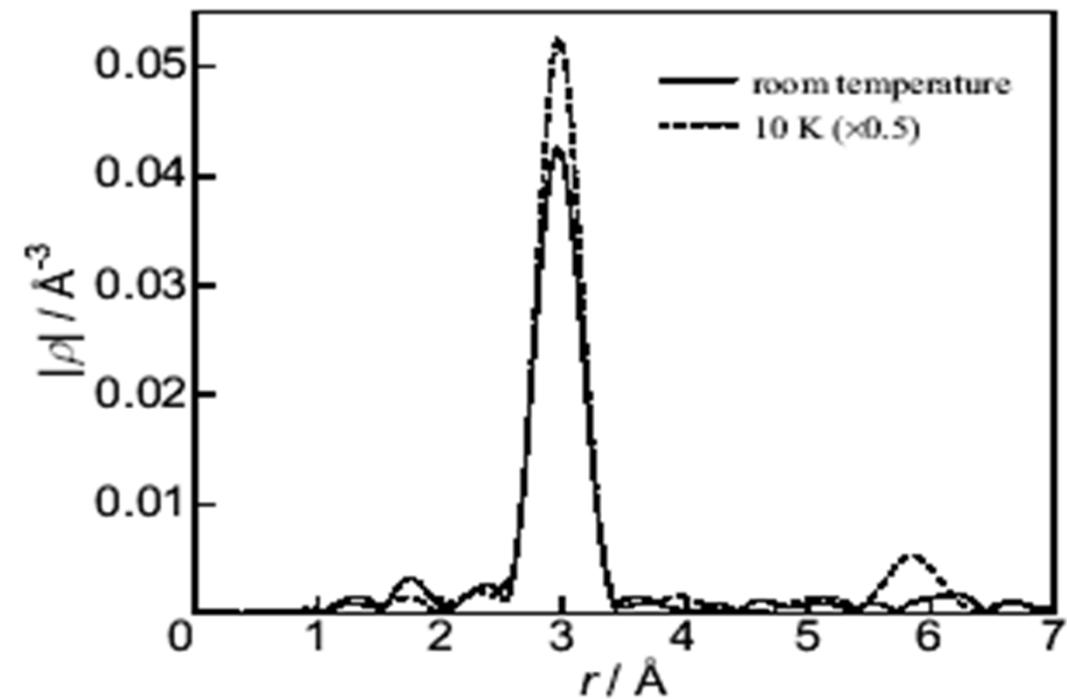
*Almost  
impossible !*

*Can we detect the end-end atomic interaction in I-I-I molecule ( $I_3^-$ ) by EXAFS?*

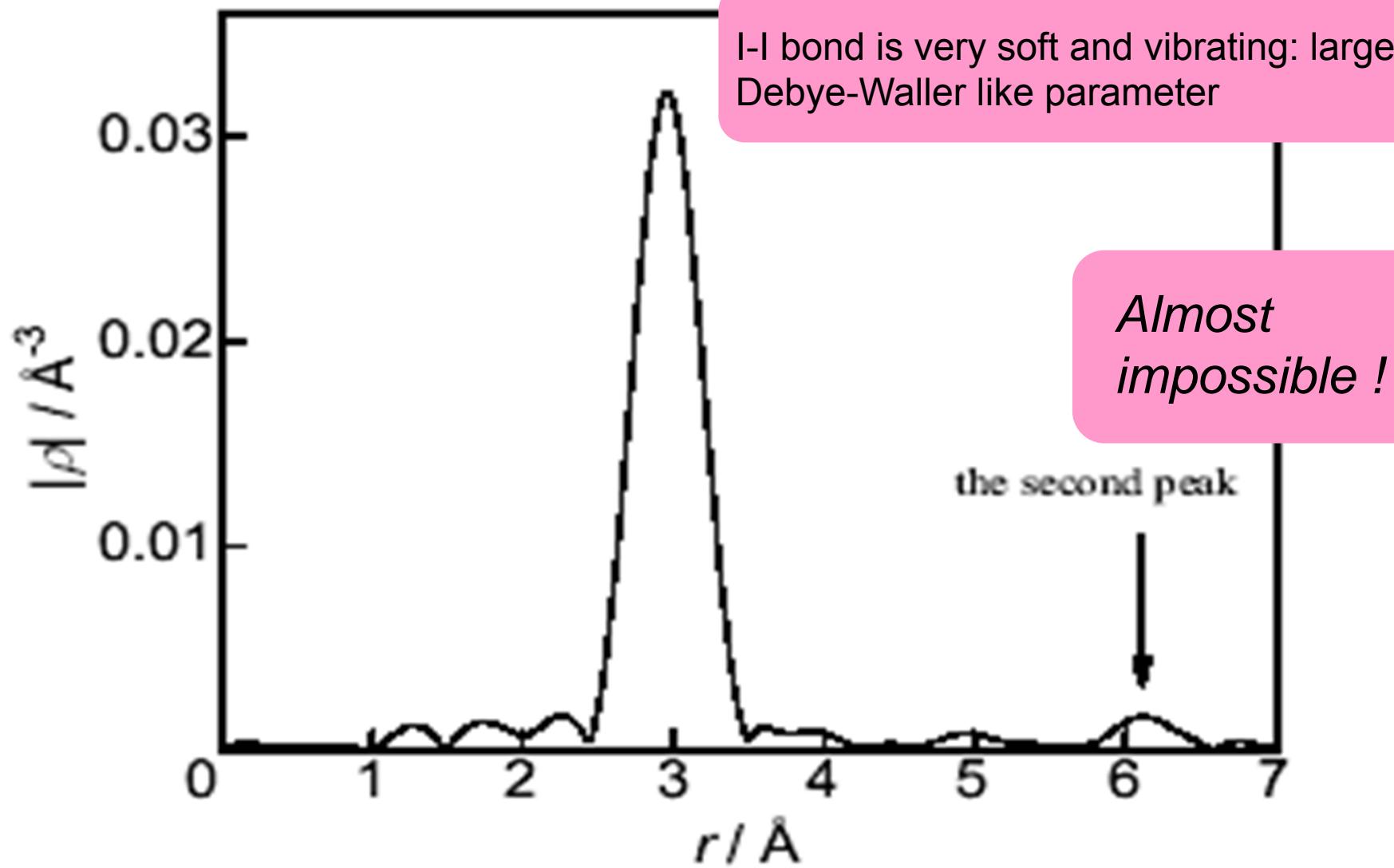
I K-edge EXAFS FT for I<sub>3</sub>



Dissolved in organic solvents



(n-C<sub>3</sub>H<sub>7</sub>)<sub>4</sub>N I<sub>3</sub> powder

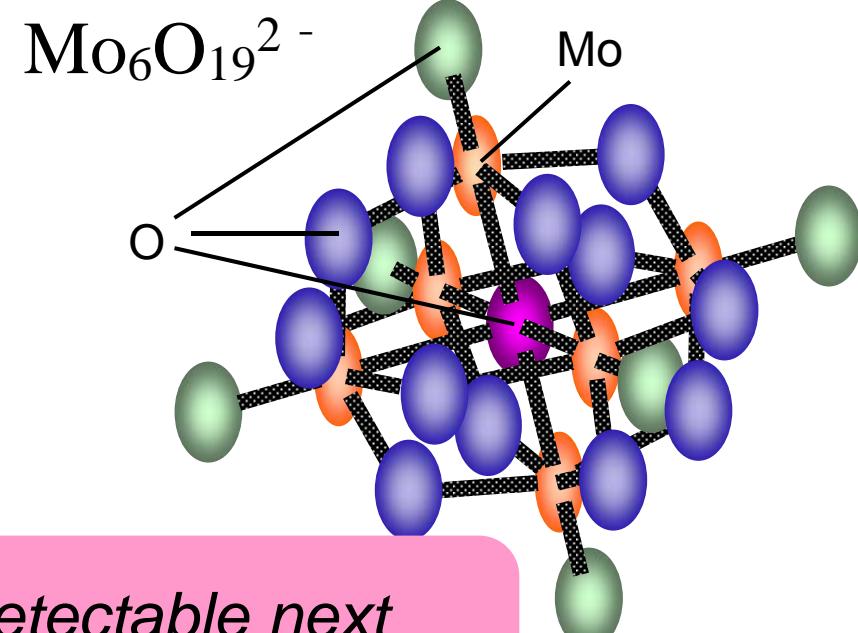
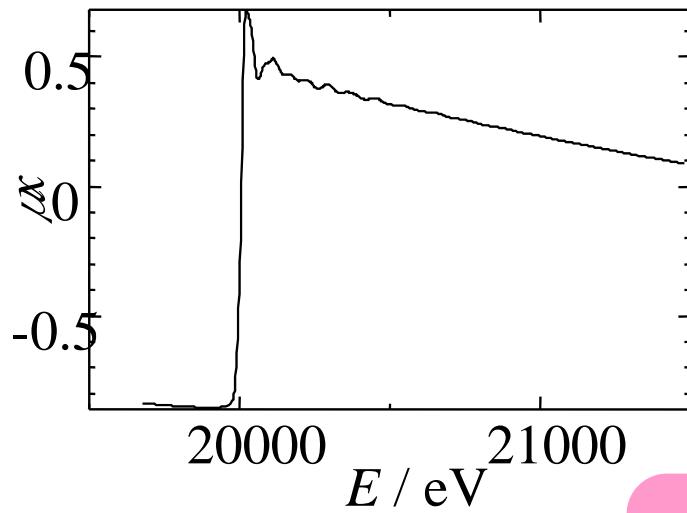


Iodine K-edge EXAFS Fourier transform for the compound spectrum made up from 12 independent spectra for organic solvent solutions.

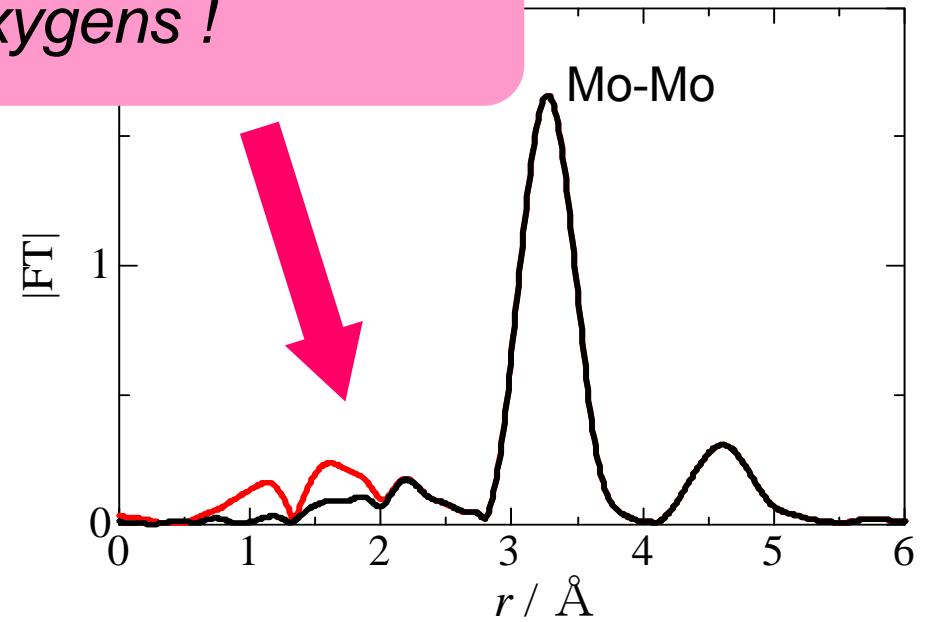
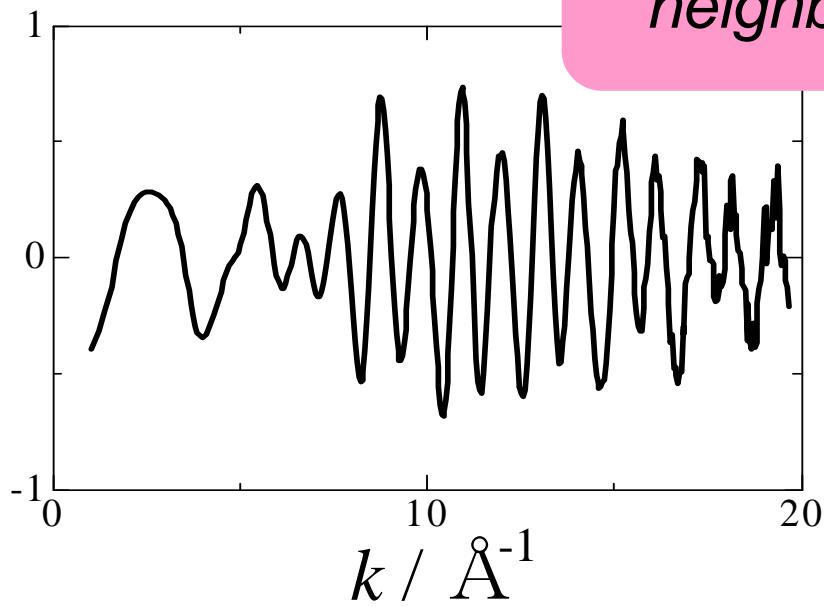
H. Sakane, T. Mitsui, H. Tanida, I. Watanabe. J. Synchrotron Rad. 8, 674 (2001).

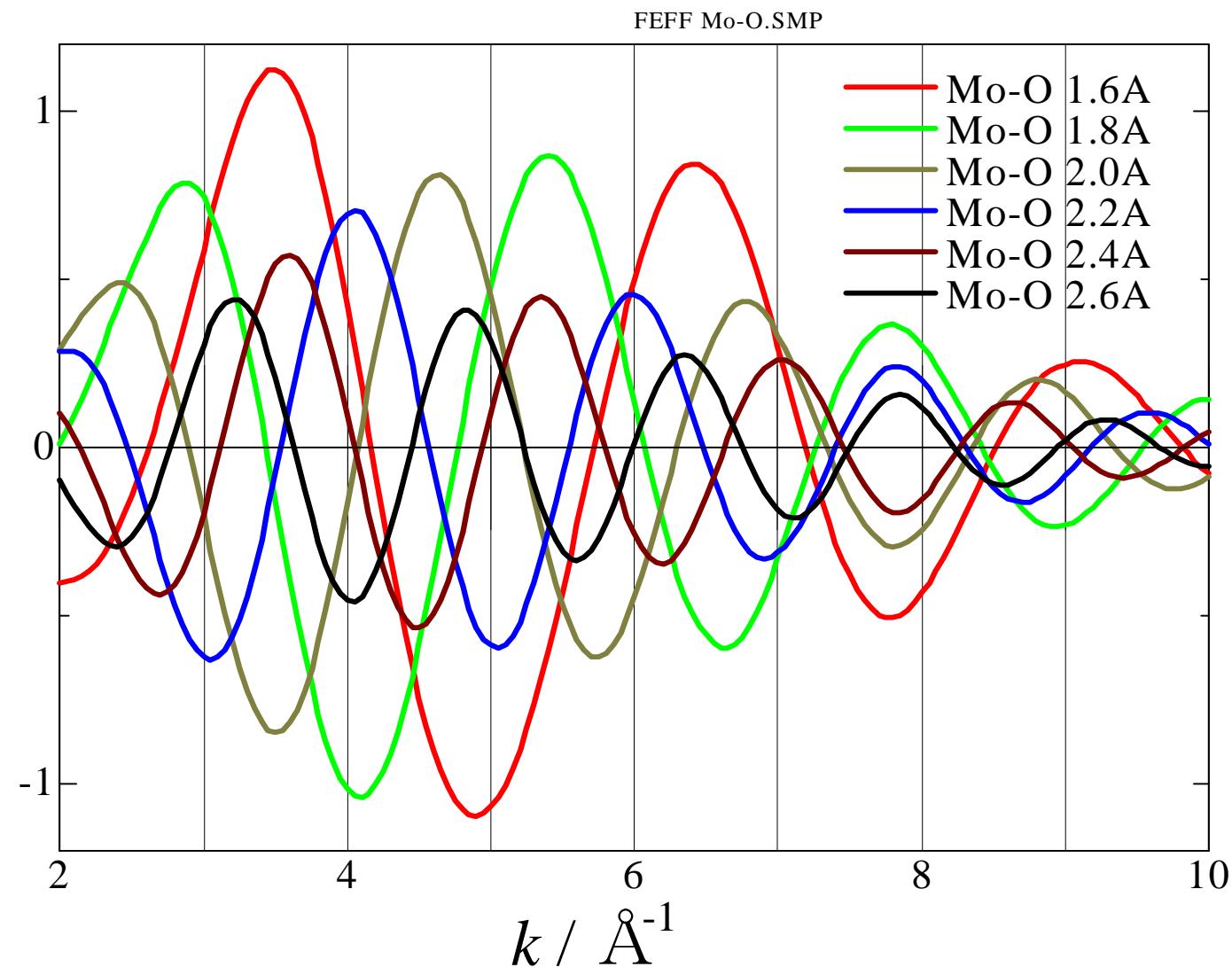
*Large symmetrical cluster of  
molybdenum oxide complex*

Mo K-edge XAFS



*Almost undetectable next neighbor oxygens !*





# EXAFS

*Extended X-ray Absorption Fine Structure*

*Theory; very difficult.*

*Experiment; looks easy.*

*Data analysis; looks straight forward.*

*Thanks to the advanced data  
analysis software.*

# EXAFS

*In reality,*

*Theory; becomes even more and more complex and difficult to understand.*

*Experiment; to obtain CORRECT spectral data is NOT an easy task.*

*Data analysis; no one except for the GOD knows whether the conclusion from the EXAFS analysis is CORRECT.*

*EXAFS is a tricky technique.*

*Then, what do we have to do ?*

*Use*

- ★ *other analytical methods,*
- ★ *knowledge of chemistry and physics,*

*and*

- ★ *good sense as a scientist*

*and combine them together with  
the EXAFS analysis.*

<http://cars9.uchicago.edu/ifeffit/BruceRavel/Horae>

## XAS Analysis Software Using IFEFFIT

free software



Current release: 0.8.059  
Release date: 1 July, 2009

ATHENA is an interactive graphical utility for processing EXAFS data. It handles most of the common data handling chores of interest, including deglitching, aligning, merging, background removal, Fourier transforms, and much more.



Current release: 0.8.013  
Release date: 15 December, 2008

ARTEMIS is an interactive graphical utility for fitting EXAFS data using theoretical standards from FEFF and sophisticated data modelling along with flexible data visualization and statistical analysis. ARTEMIS includes interfaces to ATOMS and FEFF.